

***Short Course On  
Phase-Locked Loops and Their Applications  
Day 1, AM Lecture***

***Integer-N Frequency Synthesizers***

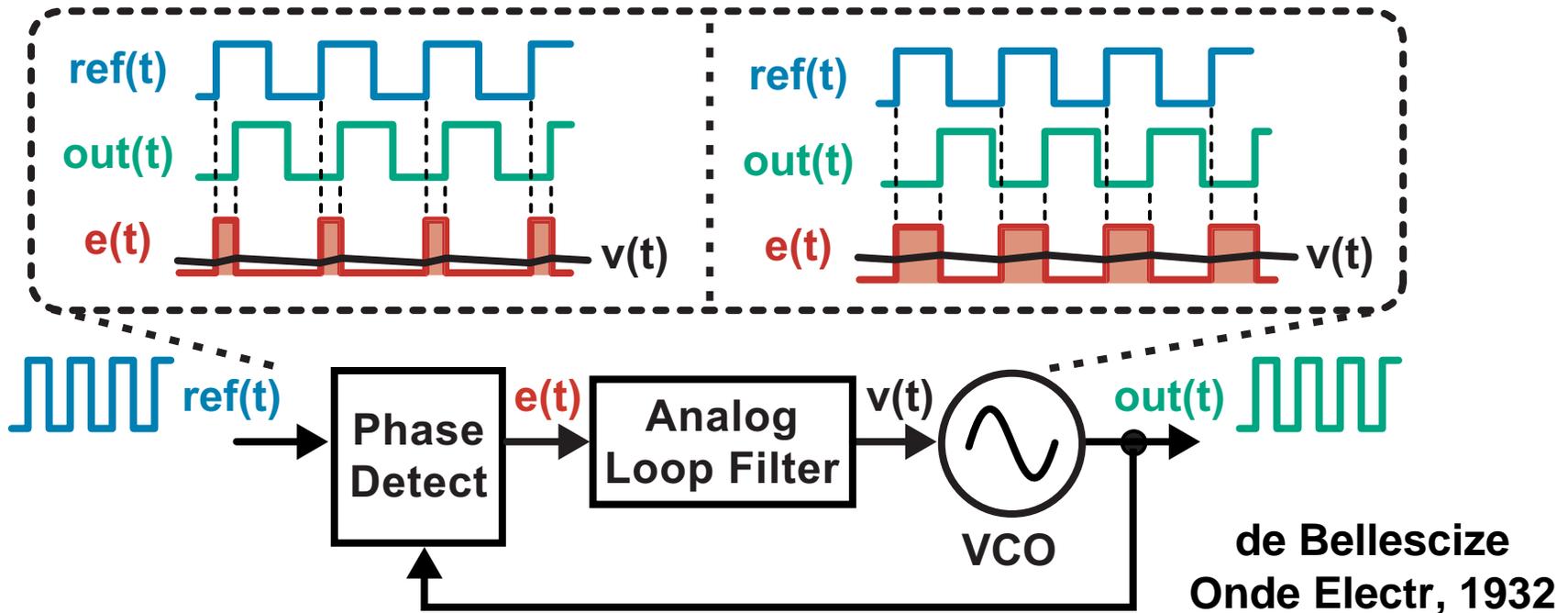
**Michael Perrott**

**August 11, 2008**

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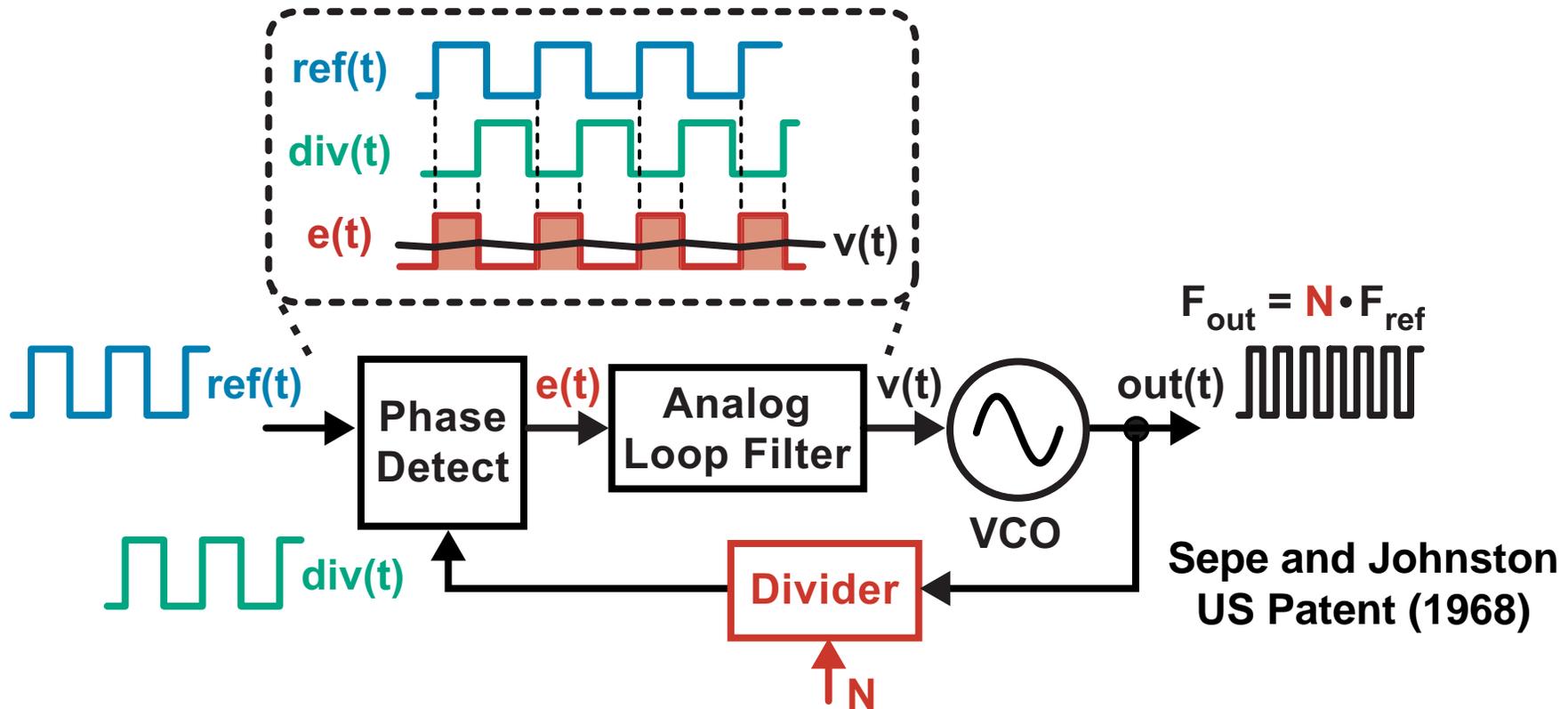
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# What is a Phase-Locked Loop (PLL)?



- VCO efficiently provides oscillating waveform with variable frequency
- PLL synchronizes VCO frequency to input reference frequency through feedback
  - Key block is phase detector
    - Realized as digital gates that create pulsed signals

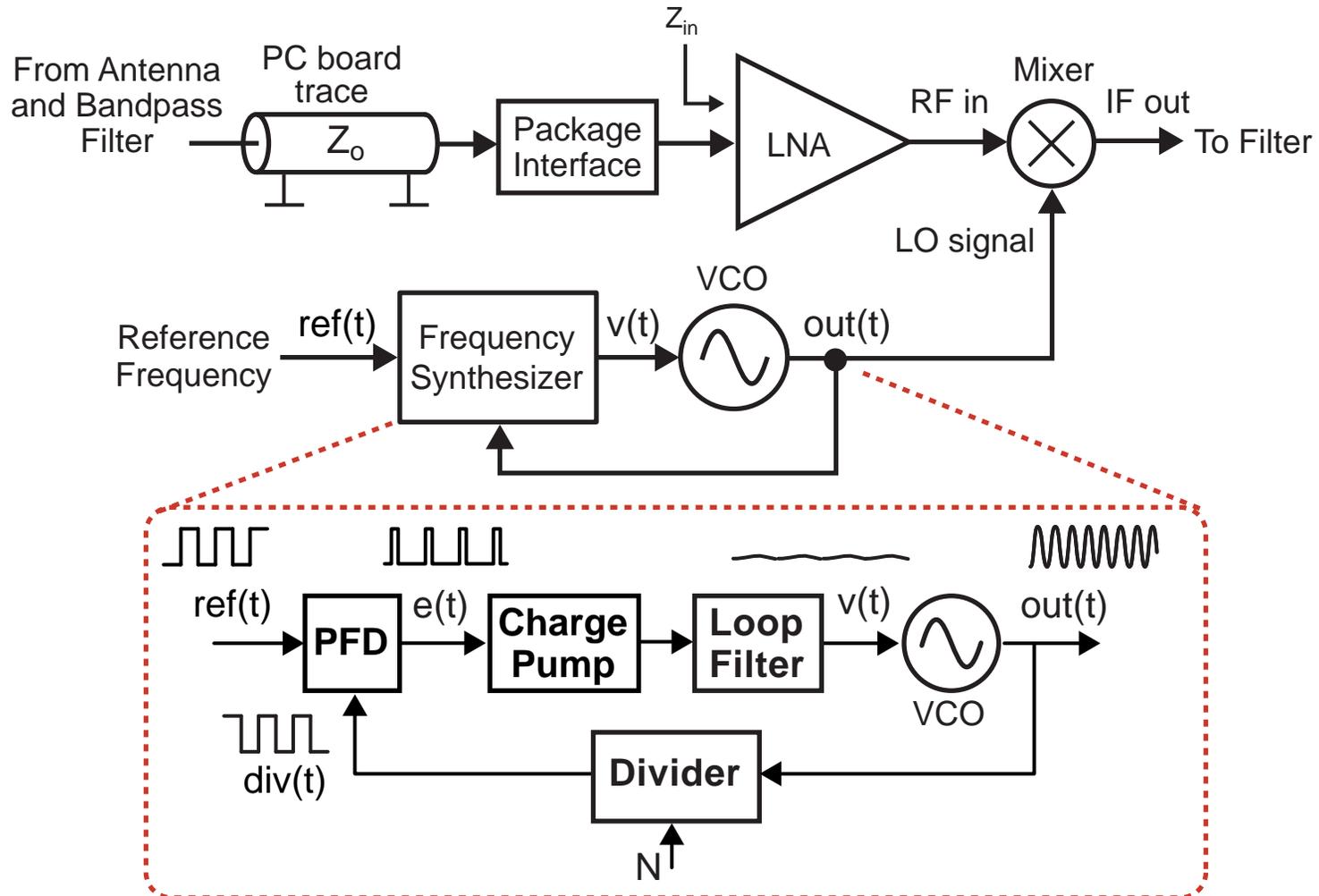
# Integer-N Frequency Synthesizers



- Use digital counter structure to divide VCO frequency
  - Constraint: must divide by integer values
- Use PLL to synchronize reference and divider output

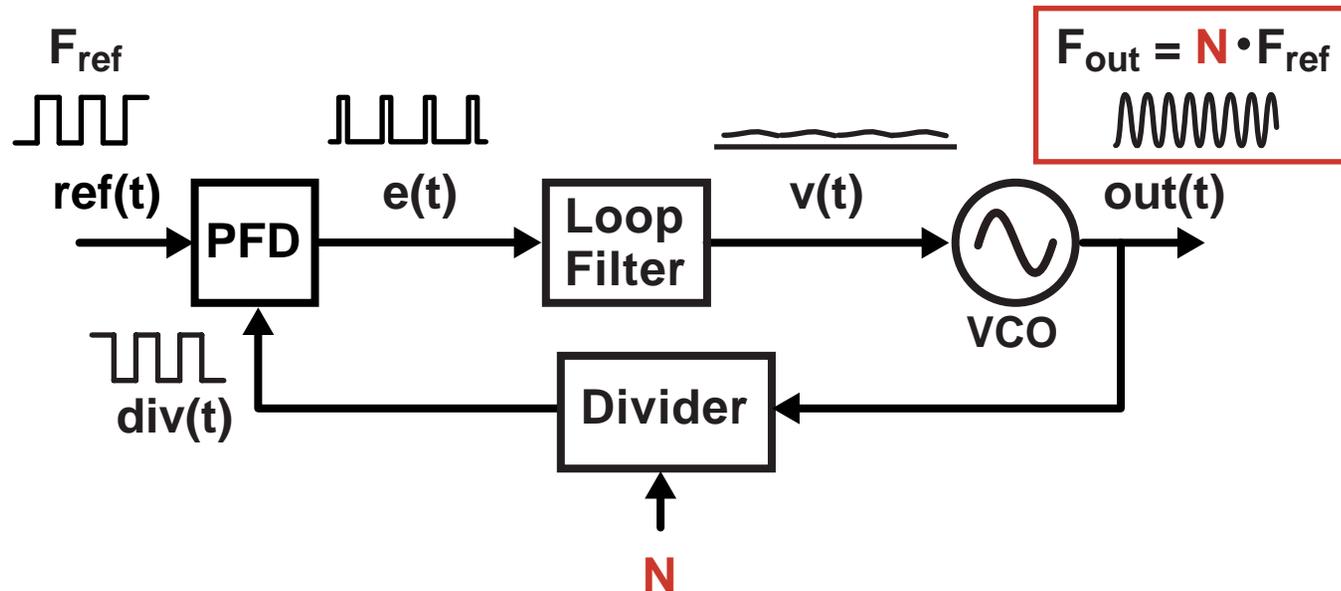
**Output frequency is digitally controlled**

# Integer-N Frequency Synthesizers in Wireless Systems



- **Design Issues: low noise, fast settling time, low power**

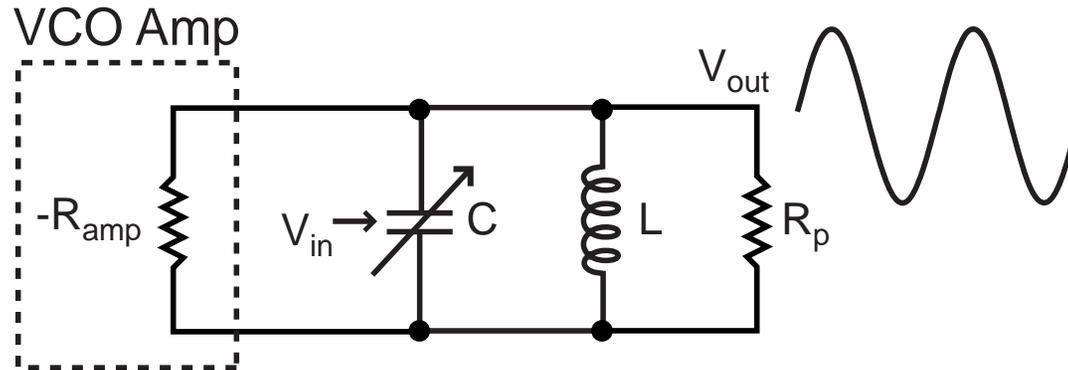
# Outline of Integer-N Frequency Synthesizer Talk



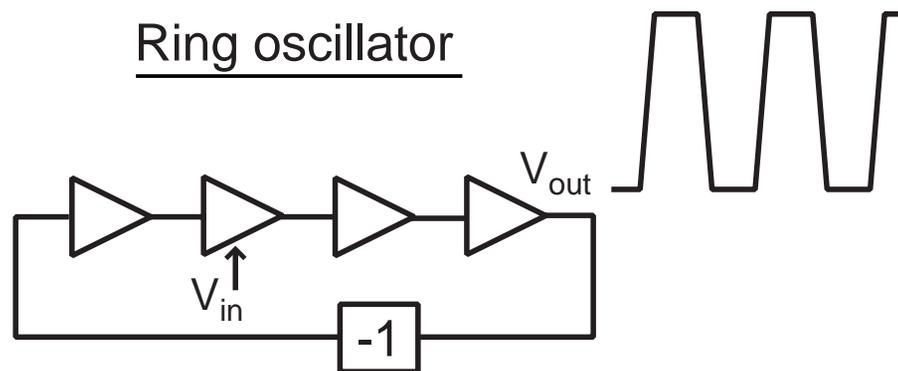
- Overview of PLL Blocks
- System Level Modeling
  - Transfer function analysis
  - Nonlinear behavior
  - Type I versus Type II systems
- Noise Analysis

# Popular VCO Structures

## LC oscillator

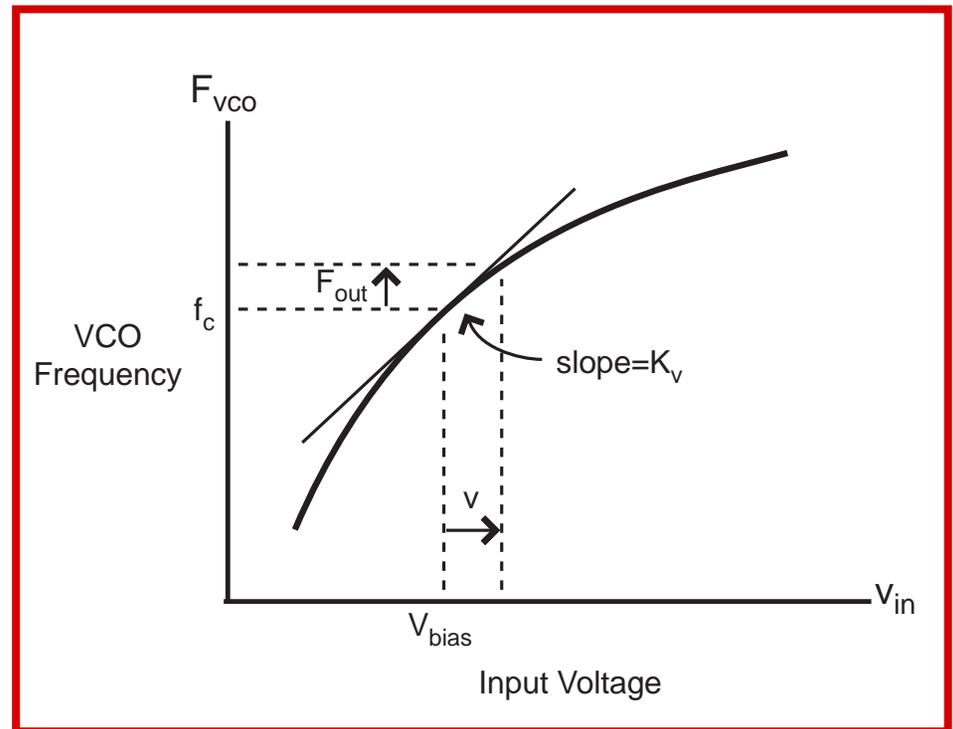
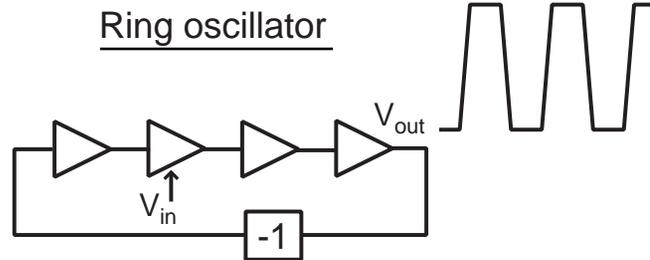
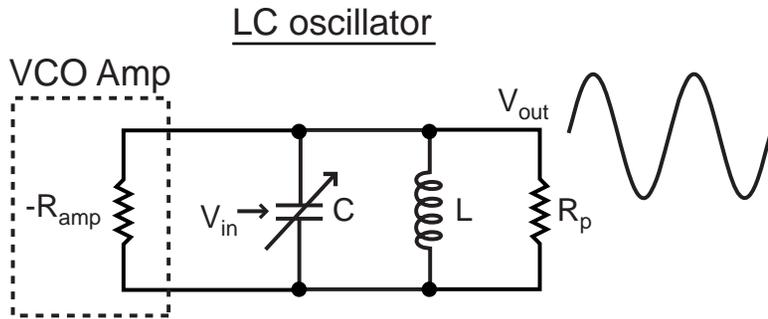


## Ring oscillator



- **LC Oscillator: low phase noise, large area**
- **Ring Oscillator: easy to integrate, higher phase noise**

# Model for Voltage to Frequency Mapping of VCO



$$F_{out}(t) = K_v v(t)$$

# Model for Voltage to Phase Mapping of VCO

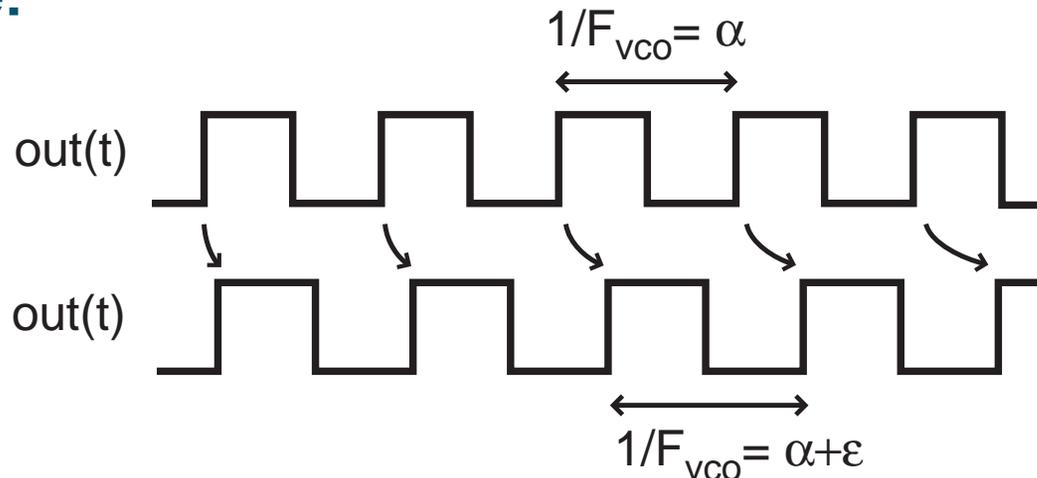
- Time-domain frequency relationship (from previous slide)

$$F_{out}(t) = K_v v(t)$$

- Time-domain phase relationship

$$\Phi_{out}(t) = \int_{-\infty}^t 2\pi F_{out}(\tau) d\tau = \int_{-\infty}^t 2\pi K_v v(\tau) d\tau$$

- Intuition of integral relationship between frequency and phase:

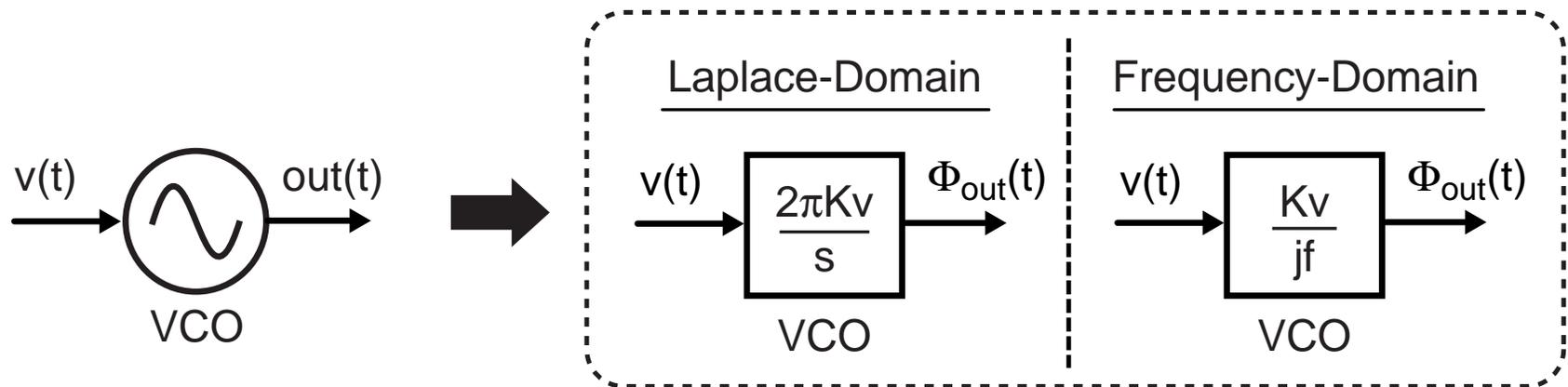


# Frequency-Domain Model for VCO

- Time-domain relationship (from previous slide)

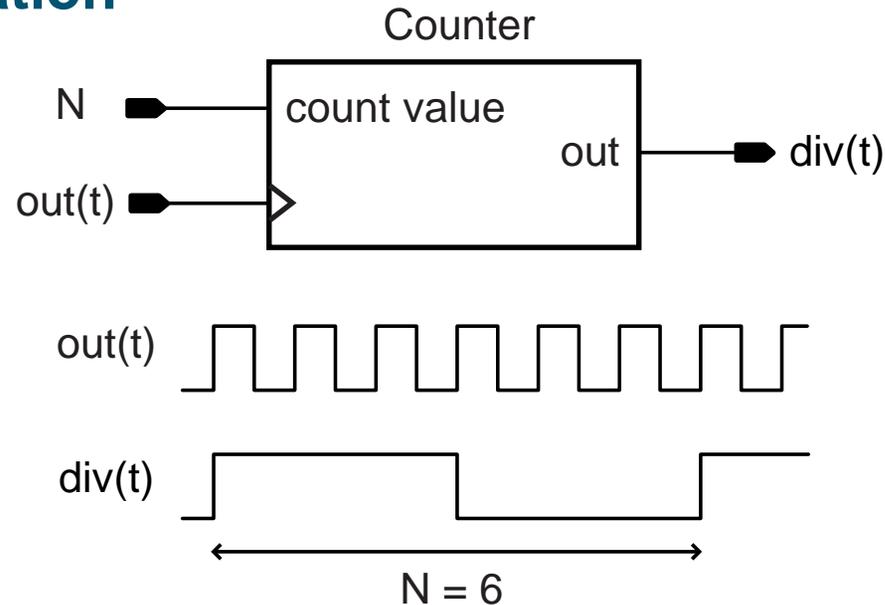
$$\Phi_{out}(t) = \int_{-\infty}^t 2\pi K_v v(\tau) d\tau$$

- Corresponding frequency-domain model



# Divider

## Implementation



## Time-domain model

### Frequency:

$$F_{div}(t) = \frac{1}{N} F_{out}(t).$$

### Phase:

$$\Phi_{div}(t) = \int_{-\infty}^t 2\pi \frac{1}{N} F_{out}(\tau) d\tau = \frac{1}{N} \Phi_{out}(t)$$

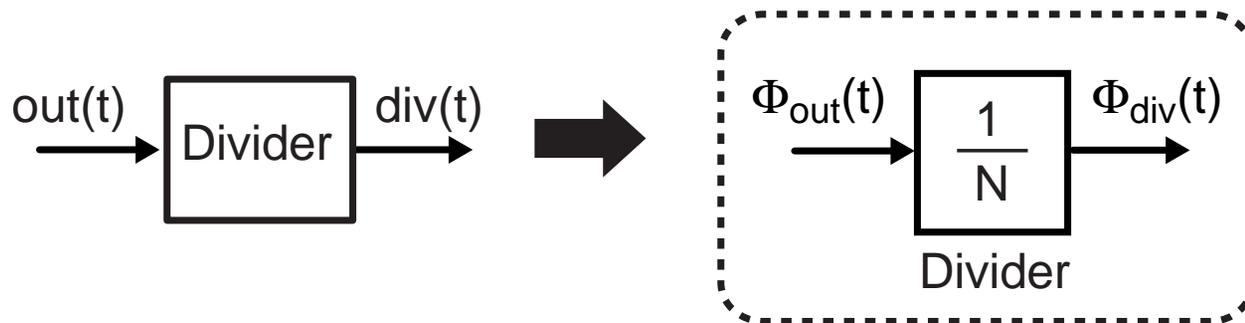
## Frequency-Domain Model of Divider

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- Time-domain relationship between VCO phase and divider output phase (from previous slide)

$$\Phi_{div}(t) = \frac{1}{N} \Phi_{out}(t)$$

- Corresponding frequency-domain model (same as Laplace-domain)

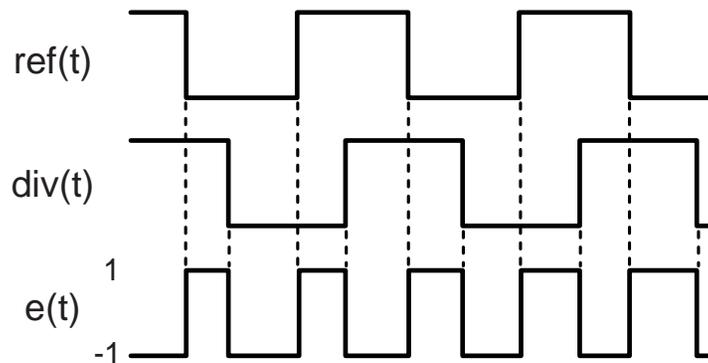
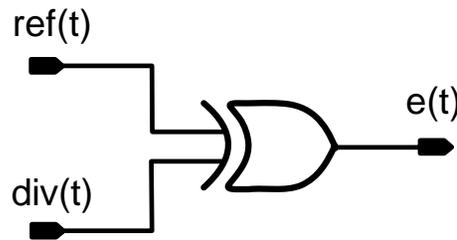


# Phase Detector (PD)

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- XOR structure

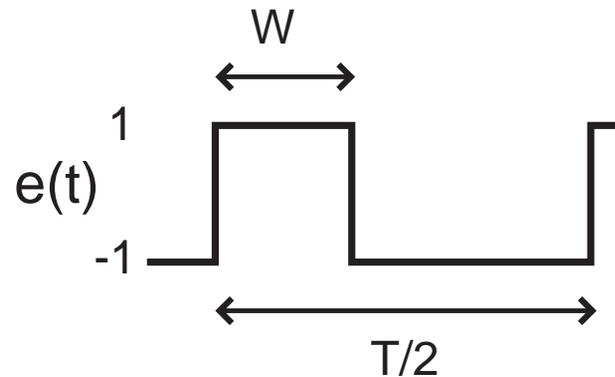
- Average value of error pulses corresponds to phase error
- Loop filter extracts the average value and feeds to VCO



## Modeling of XOR Phase Detector

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- Average value of pulses is extracted by loop filter
  - Look at detector output over one cycle:

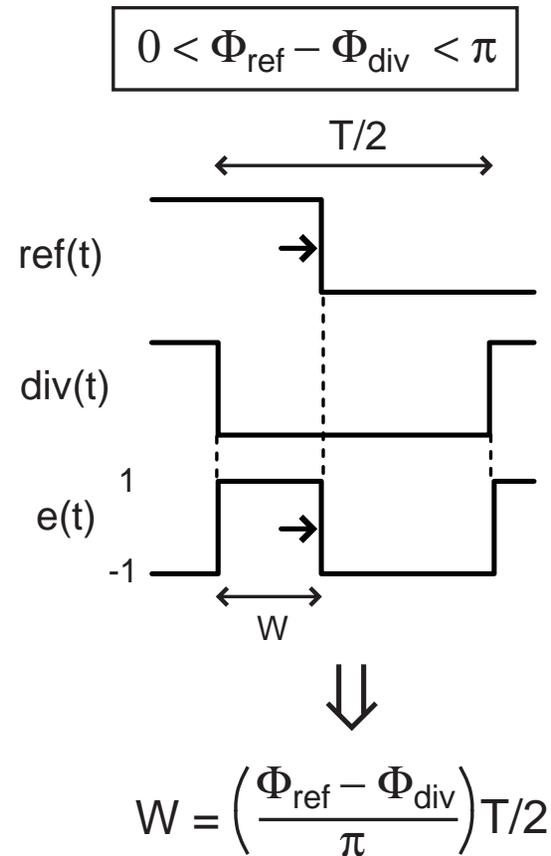
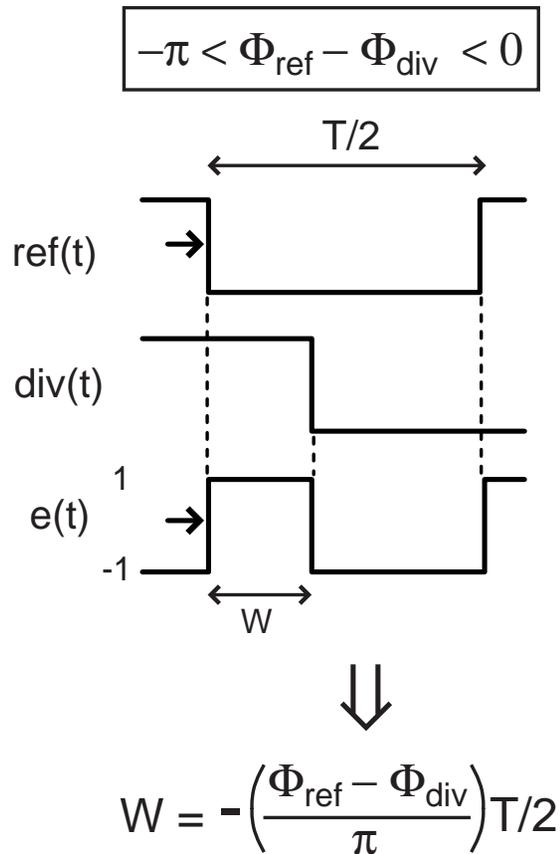


- Equation:

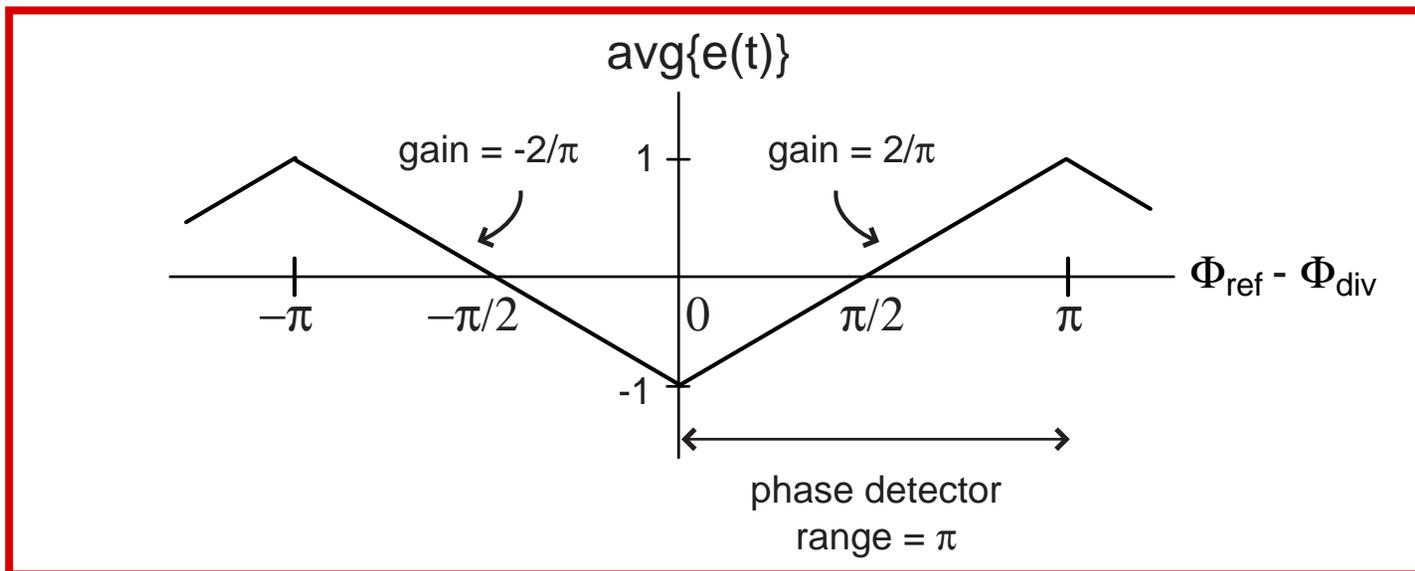
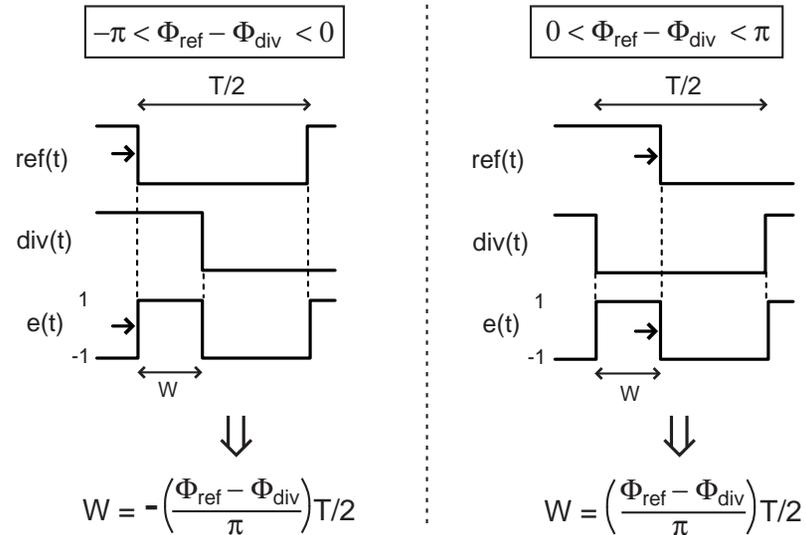
$$\text{avg}\{e(t)\} = -1 + 2\frac{W}{T/2}$$

# Relate Pulse Width to Phase Error

- Two cases:

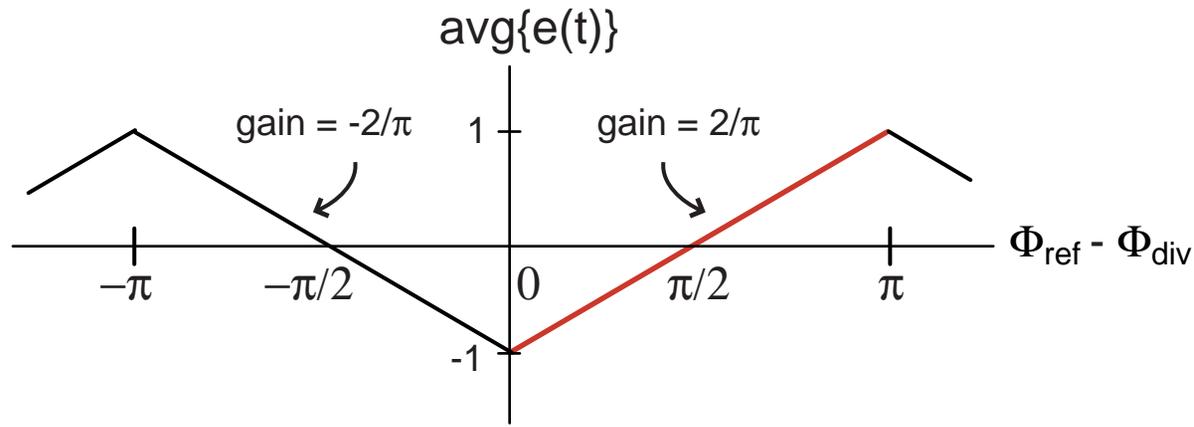


# Overall XOR Phase Detector Characteristic

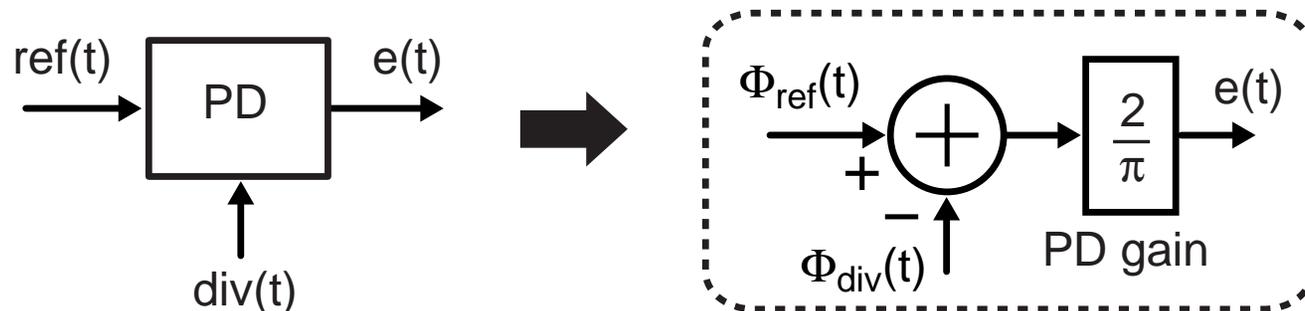


# Frequency-Domain Model of XOR Phase Detector

- Assume phase difference confined within 0 to  $\pi$  radians
  - Phase detector characteristic looks like a constant gain element

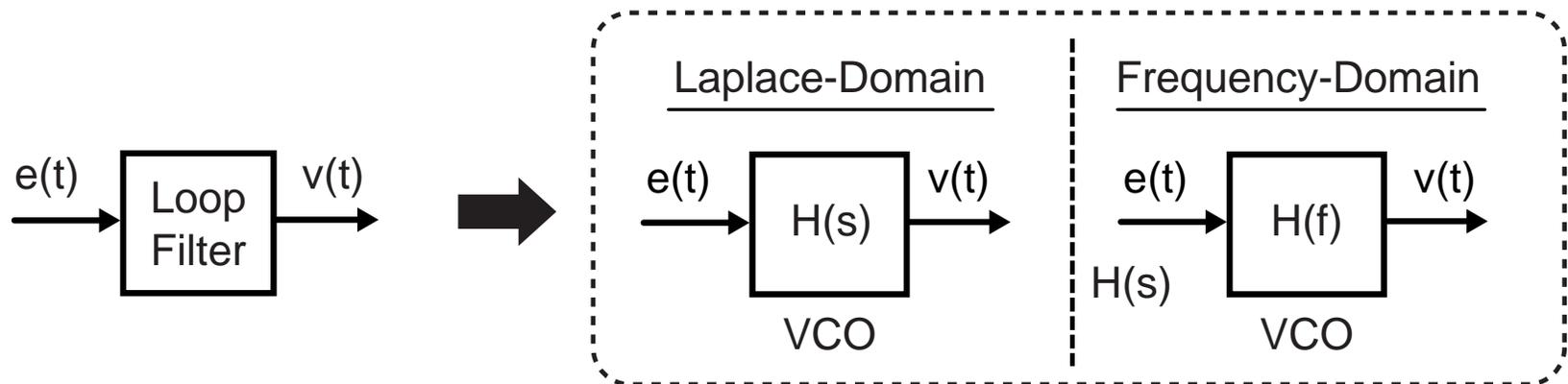


- Corresponding frequency-domain model

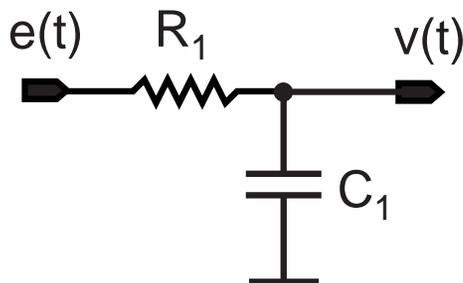


# Loop Filter

- Consists of a lowpass filter to extract average of phase detector error pulses
- Frequency-domain model



- First order example

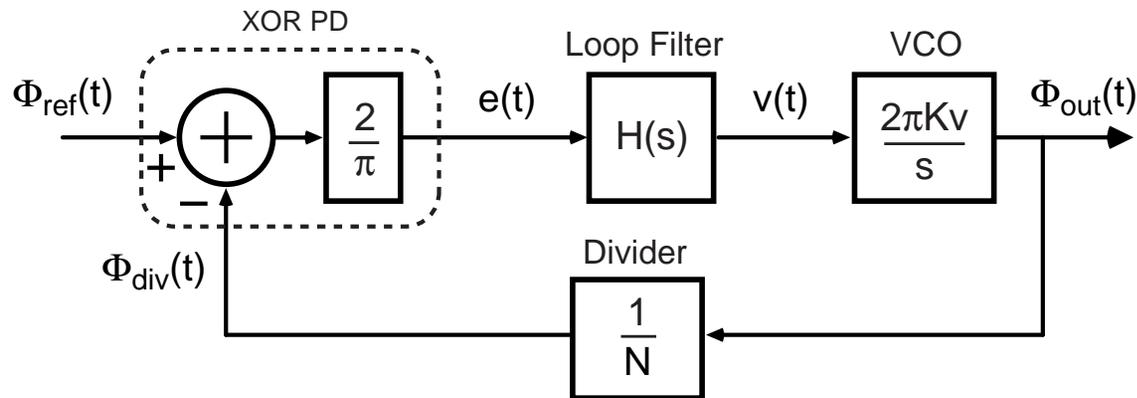


$$\Rightarrow H(s) = \frac{1}{1 + sR_1C_1}$$

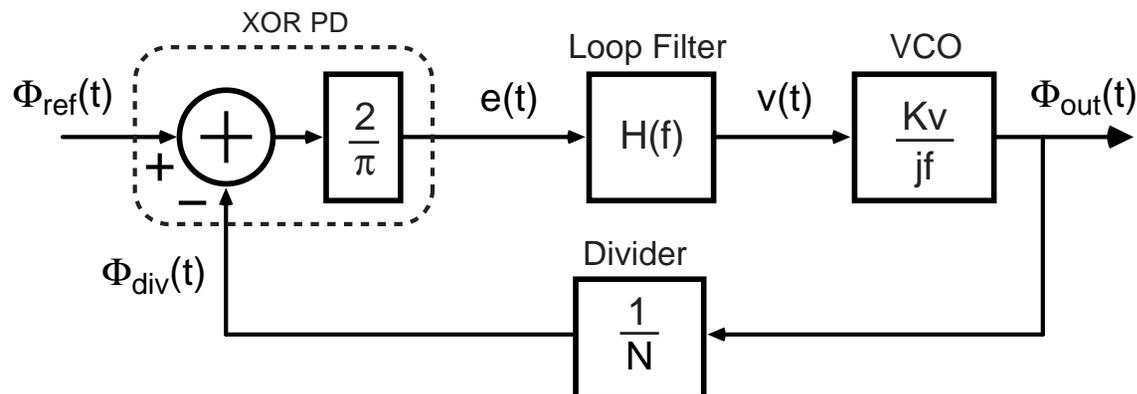
# Overall Linearized PLL Frequency-Domain Model

- Combine models of individual components

Laplace-Domain Model

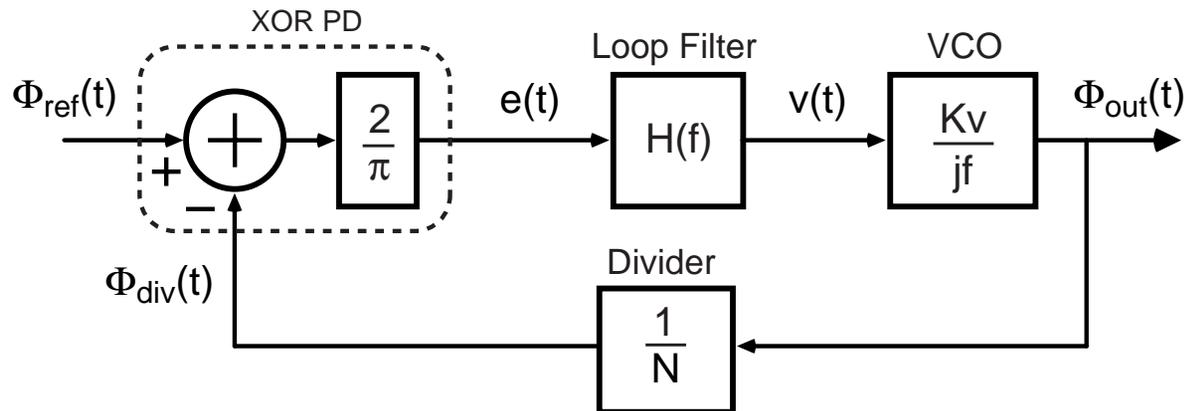


Frequency-Domain Model



# Open Loop versus Closed Loop Response

- Frequency-domain model



- Define  $A(f)$  as *open loop* response

$$A(f) = \frac{2}{\pi} H(f) \left( \frac{K_v}{jf} \right) \frac{1}{N}$$

- Define  $G(f)$  as a parameterizing *closed loop* function

- More details later in this lecture

$$G(f) = \frac{A(f)}{1 + A(f)}$$

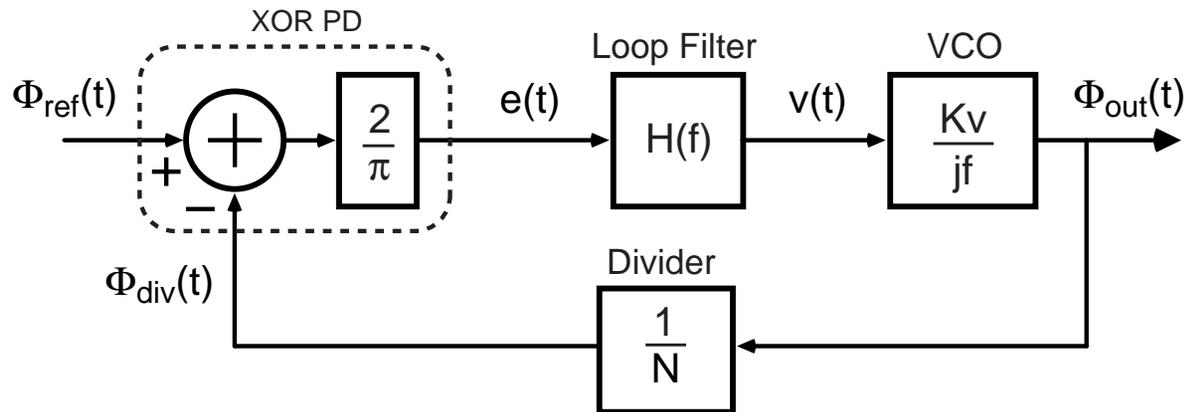
# ***Classical PLL Transfer Function Design Approach***

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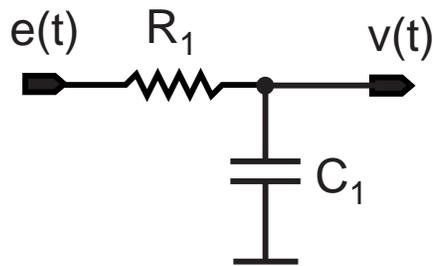
- 1. Choose an appropriate topology for  $H(f)$** 
  - Usually chosen from a small set of possibilities
- 2. Choose pole/zero values for  $H(f)$  as appropriate for the required filtering of the phase detector output**
  - Constraint: set pole/zero locations higher than desired PLL bandwidth to allow stable dynamics to be possible
- 3. Adjust the open-loop gain to achieve the required bandwidth while maintaining stability**
  - Plot gain and phase bode plots of  $A(f)$
  - Use phase (or gain) margin criterion to infer stability

# Example: First Order Loop Filter

## Overall PLL block diagram

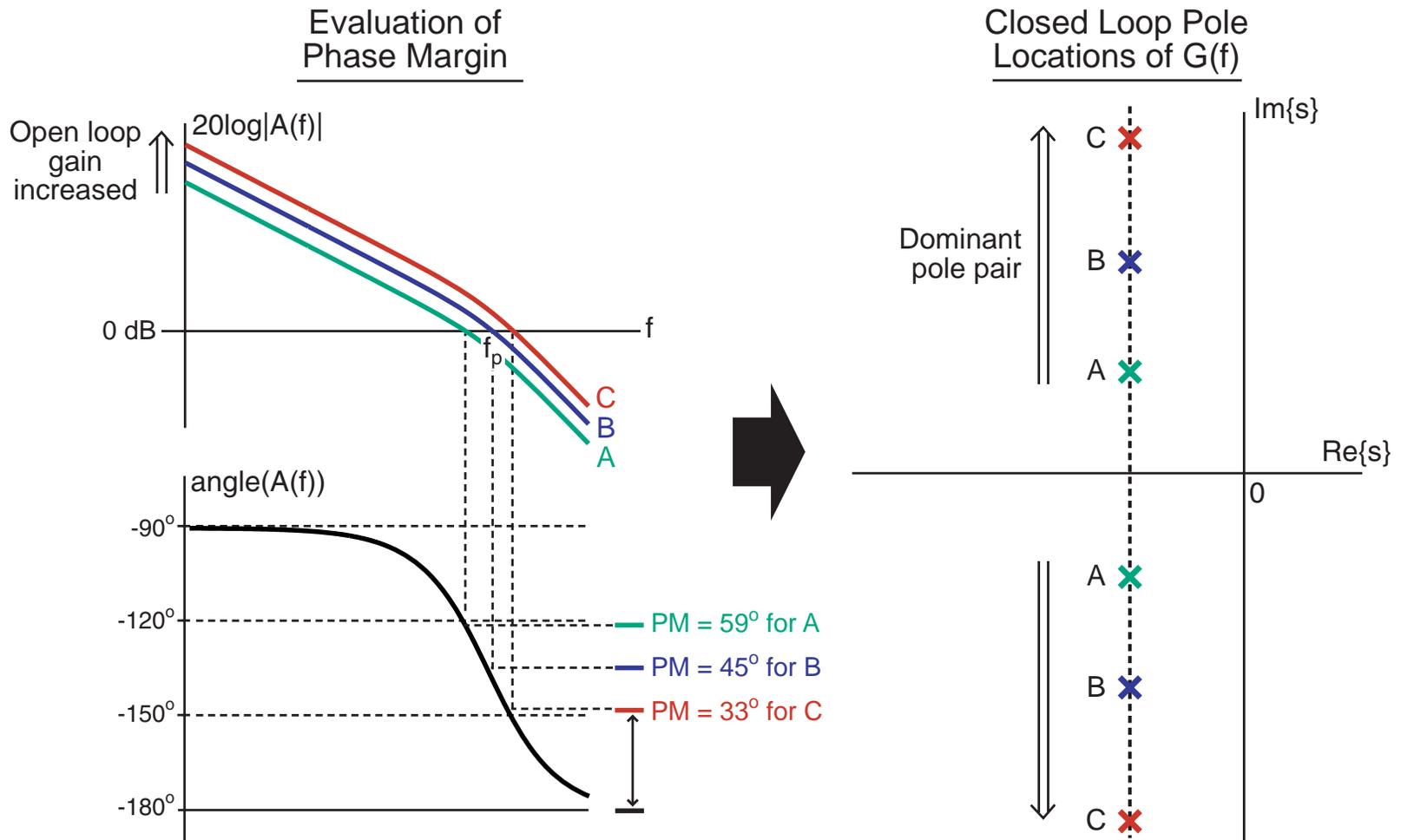


## Loop filter



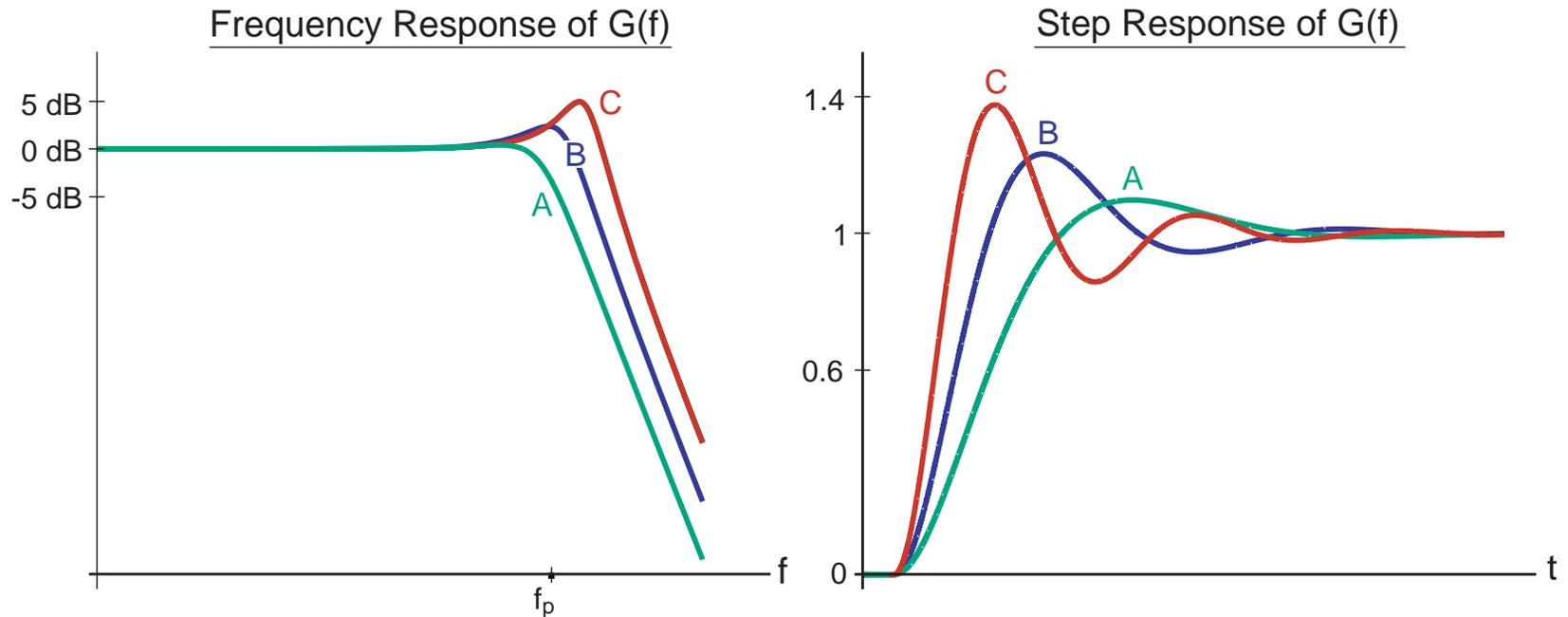
$$\Rightarrow H(f) = \frac{1}{1 + jf/f_p}$$

# Closed Loop Poles Versus Open Loop Gain



- Higher open loop gain leads to an increase in  $Q$  of closed loop poles

# Corresponding Closed Loop Response

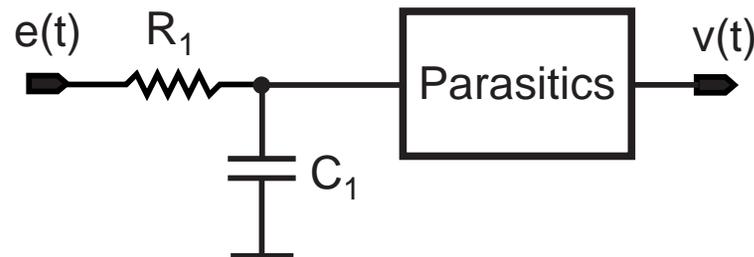


- Increase in open loop gain leads to
  - Peaking in closed loop frequency response
  - Ringing in closed loop step response

## The Impact of Parasitic Poles

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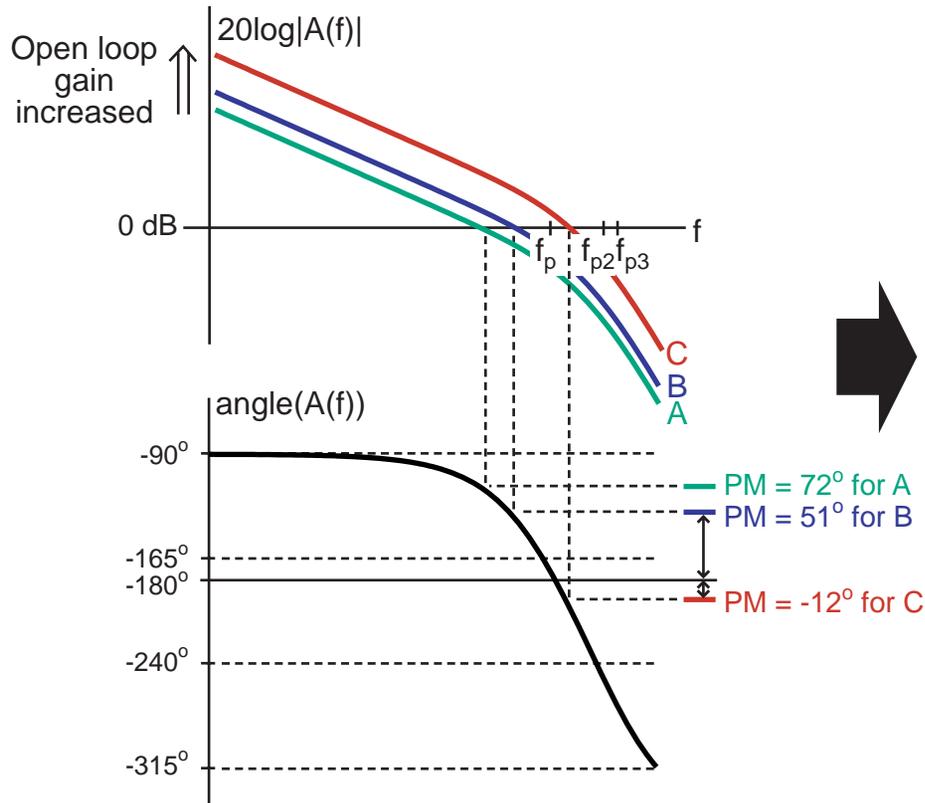
- Loop filter and VCO may have additional parasitic poles and zeros due to their circuit implementation
- We can model such parasitics by including them in the loop filter transfer function
- Example: add two parasitic poles to first order filter



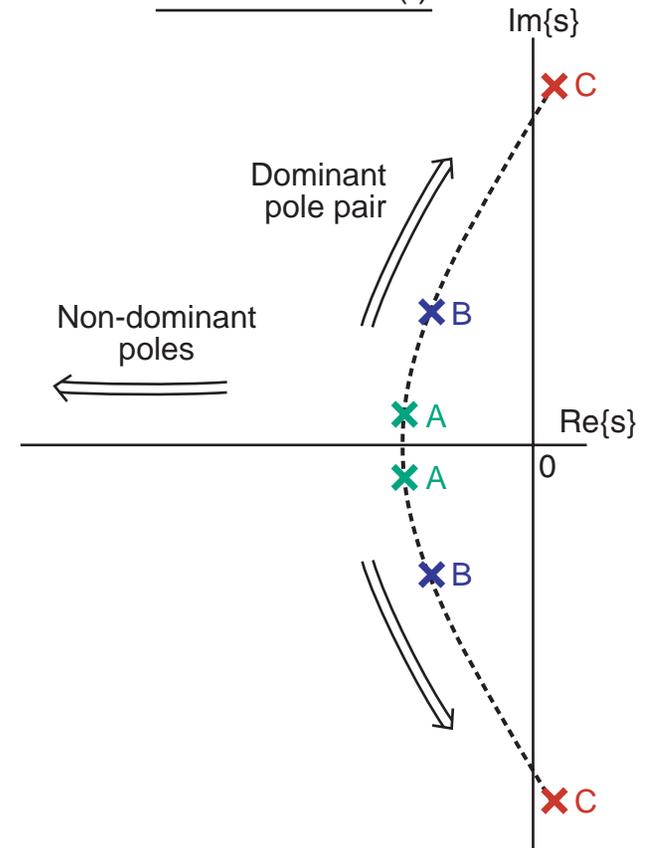
$$\Rightarrow H(f) = \left( \frac{1}{1 + jf/f_1} \right) \left( \frac{1}{1 + jf/f_2} \right) \left( \frac{1}{1 + jf/f_3} \right)$$

# Closed Loop Poles Versus Open Loop Gain

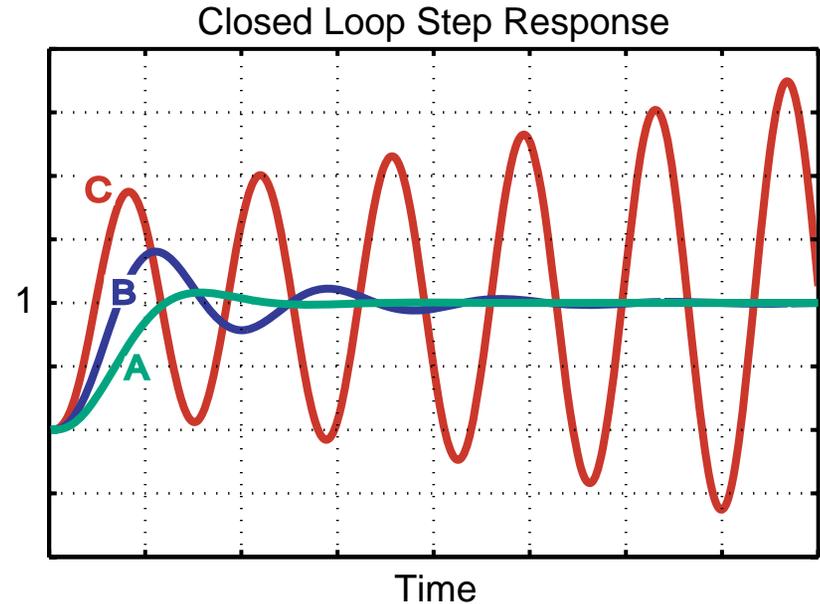
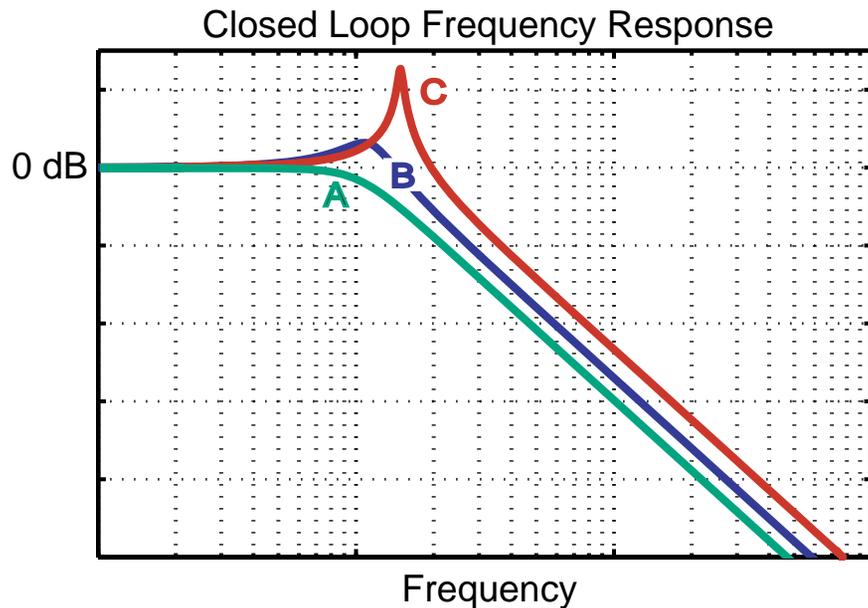
Evaluation of Phase Margin



Closed Loop Pole Locations of G(f)

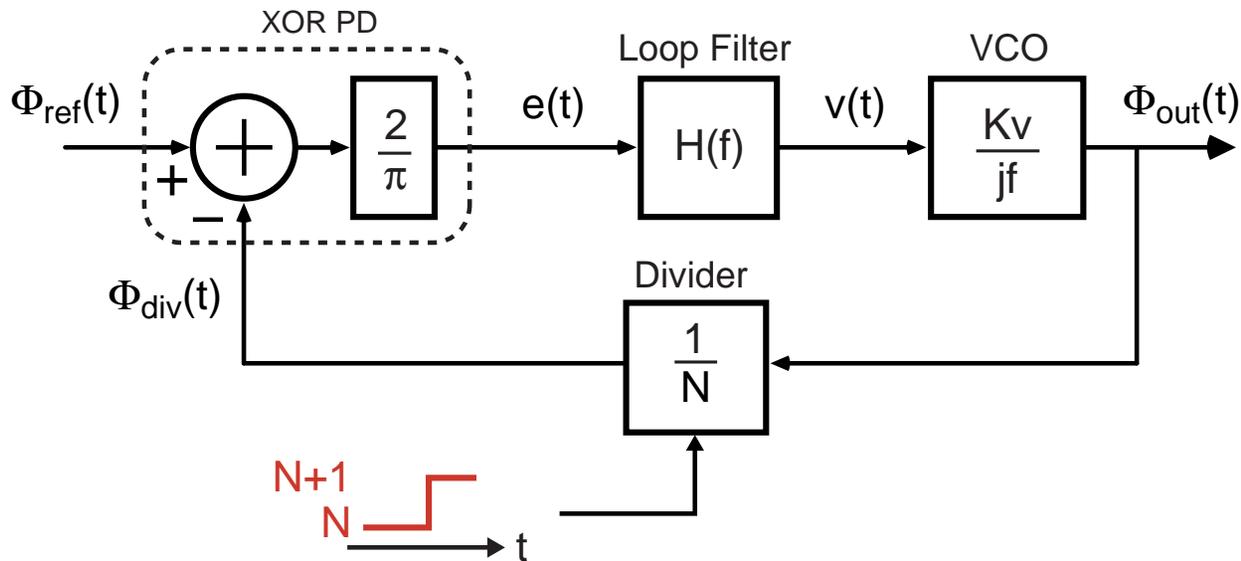


# Corresponding Closed Loop Response



- Increase in open loop gain now eventually leads to instability
  - Large peaking in closed loop frequency response
  - Increasing amplitude in closed loop step response

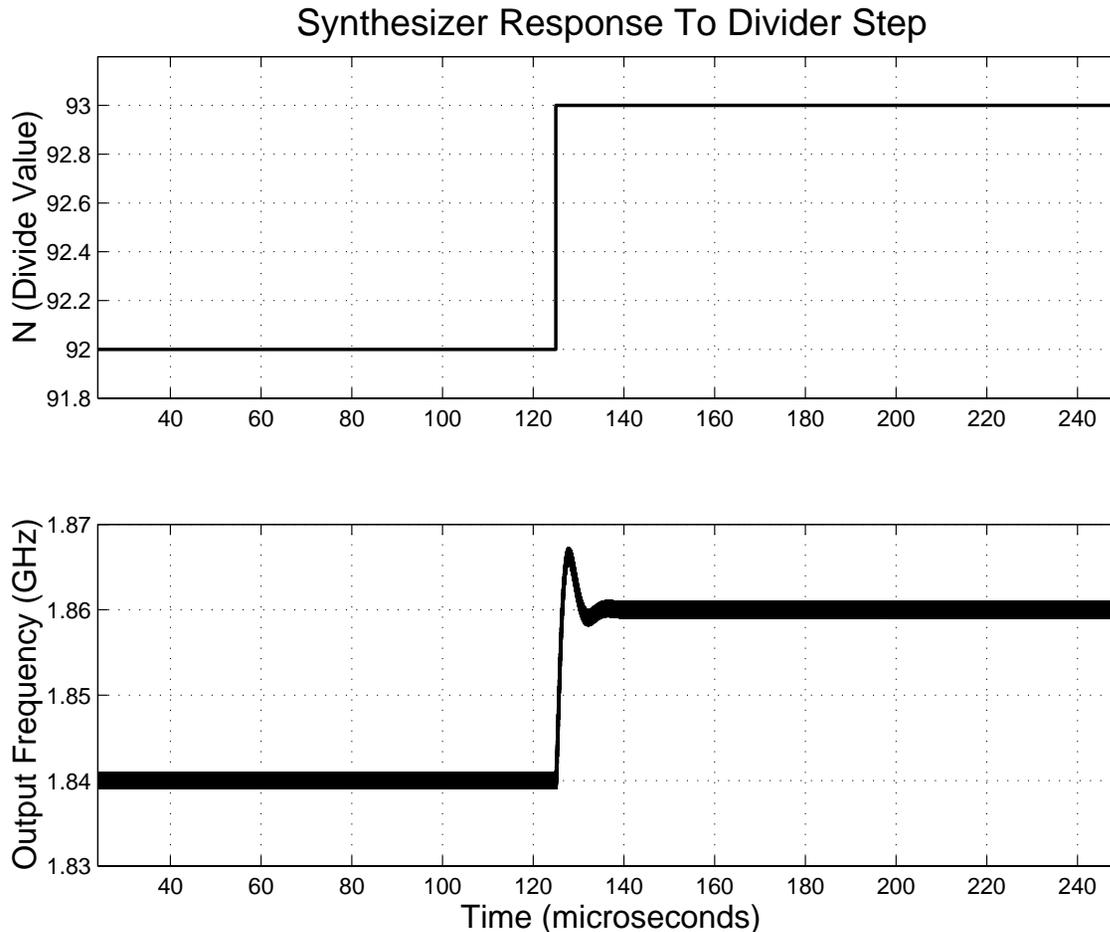
# Response of PLL to Divide Value Changes



- Change in output frequency achieved by changing the divide value
- Classical approach provides no direct model of impact of divide value variations
  - Treat divide value variation as a perturbation to a linear system
    - PLL responds according to its closed loop response

# Response of an Actual PLL to Divide Value Change

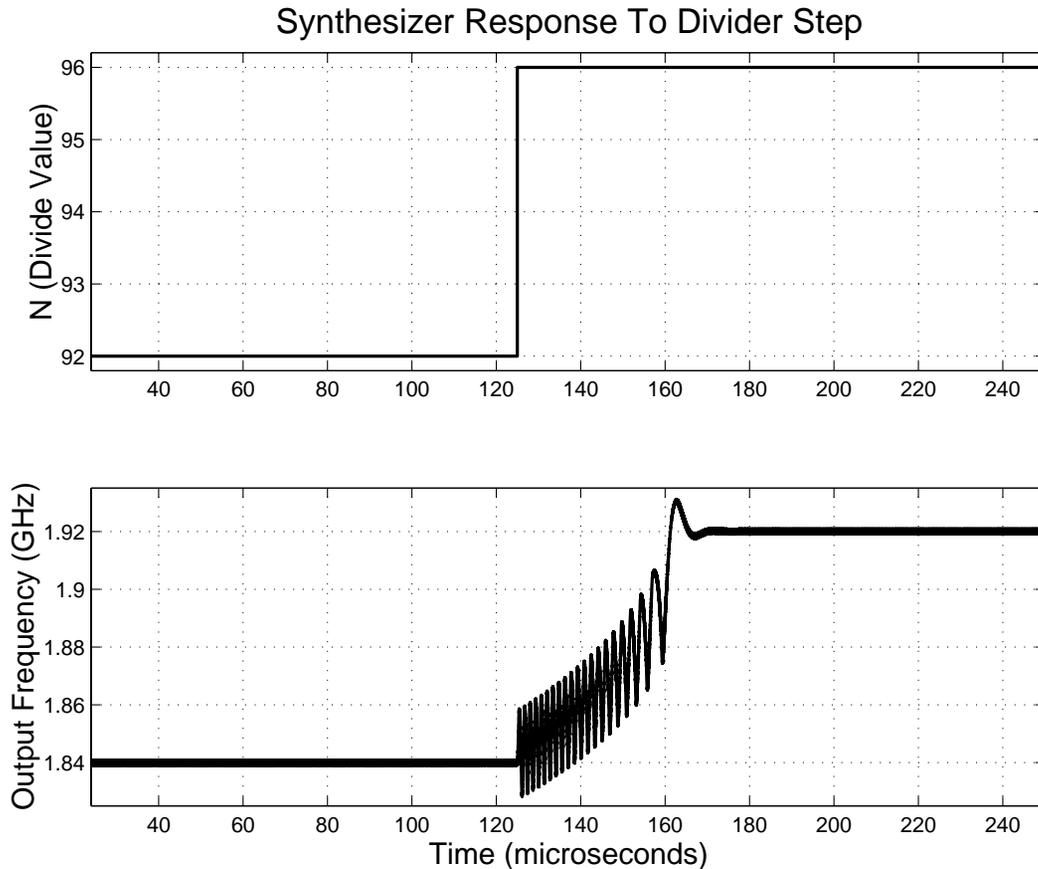
- **Example: Change divide value by one**



- **PLL responds according to closed loop response!**

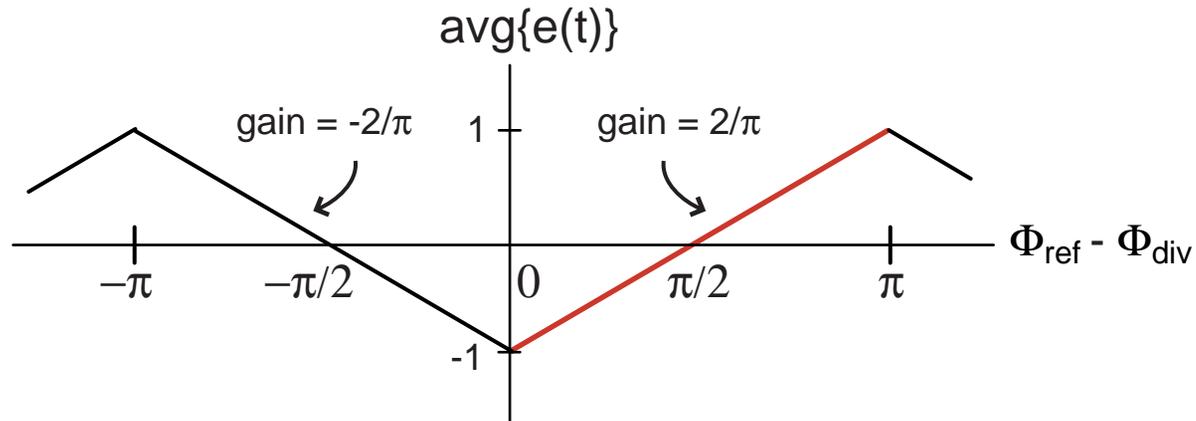
# What Happens with Large Divide Value Variations?

- PLL temporarily loses frequency lock (cycle slipping occurs)



- Why does this happen?

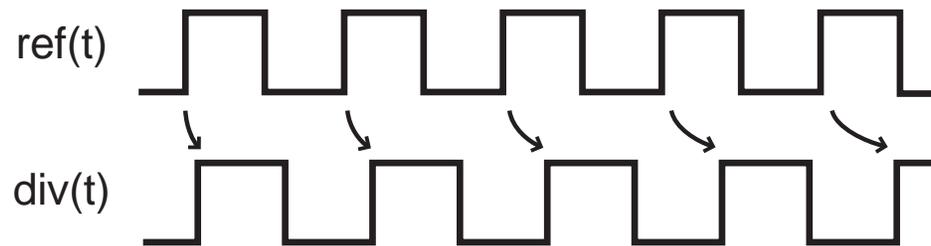
# Recall Phase Detector Characteristic



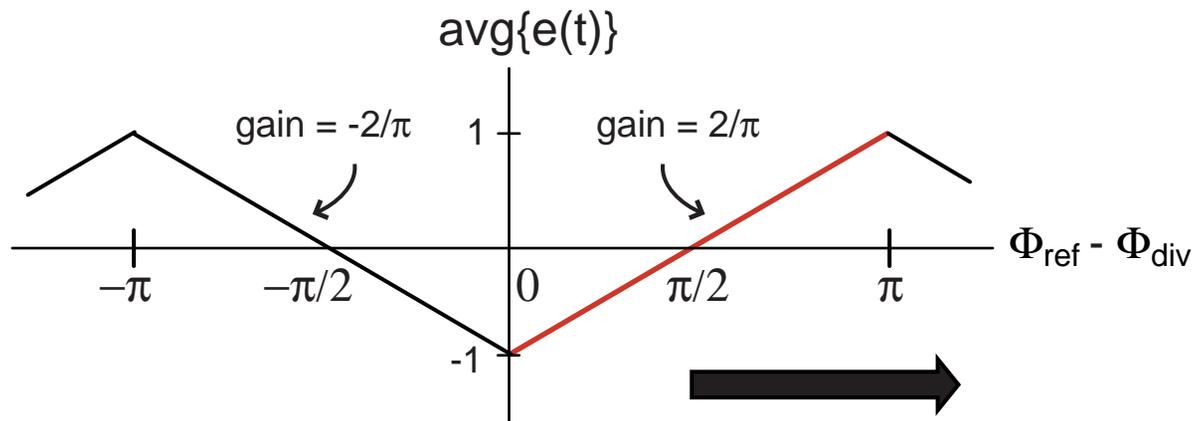
- To simplify modeling, we assumed that we always operated in a confined phase range (0 to  $\pi$ )
  - Led to a simple PD model
- Large perturbations knock us out of that confined phase range
  - PD behavior varies depending on the phase range it happens to be in

# Cycle Slipping

- Consider the case where there is a frequency offset between divider output and reference
  - We know that phase difference will accumulate

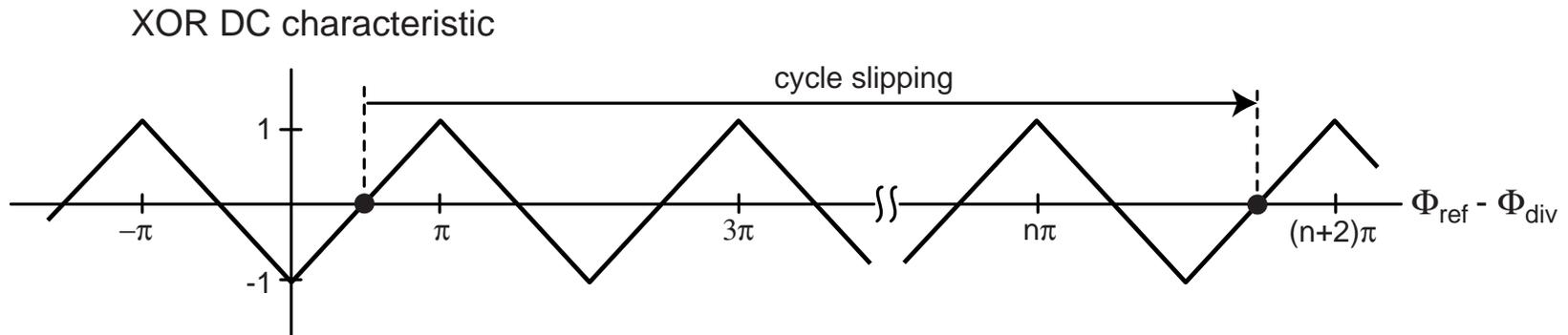


- Resulting ramp in phase causes PD characteristic to be swept across its different regions (cycle slipping)



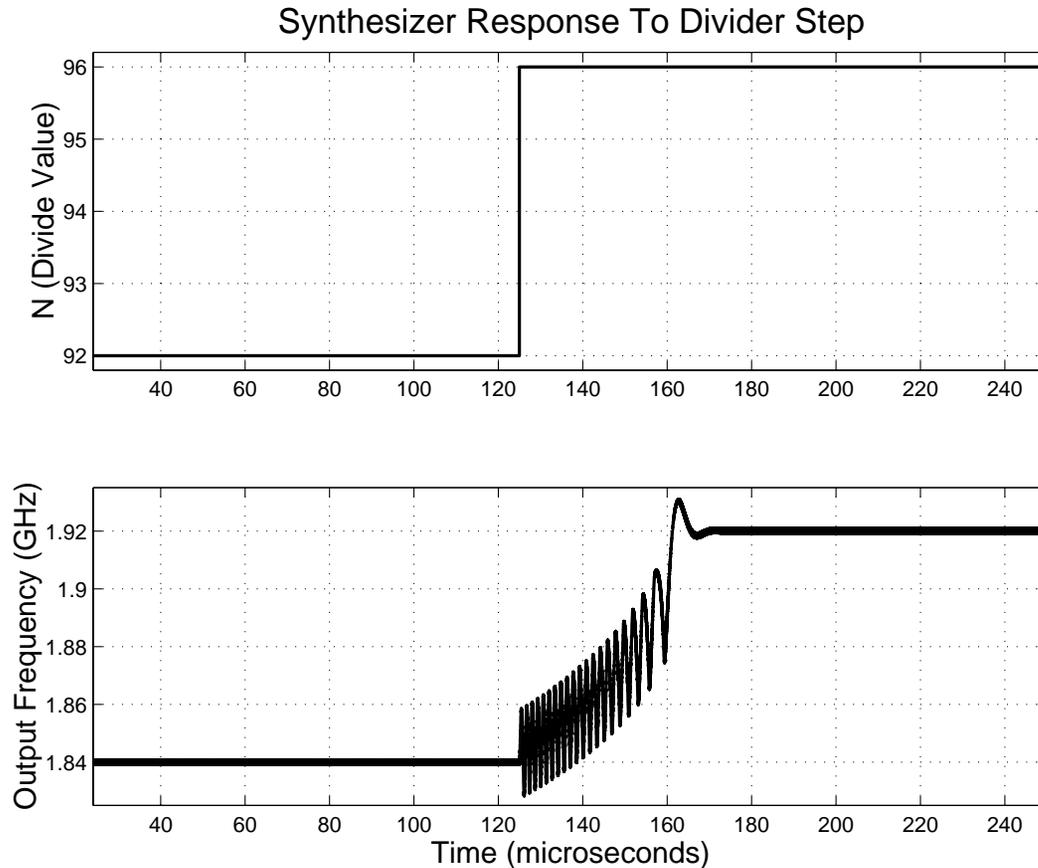
# Impact of Cycle Slipping

- Loop filter averages out phase detector output
- Severe cycle slipping causes phase detector to alternate between regions very quickly
  - Average value of XOR characteristic can be close to zero
  - PLL frequency oscillates according to cycle slipping
  - In severe cases, PLL will not re-lock
    - PLL has finite frequency lock-in range!



## Back to PLL Response Shown Previously

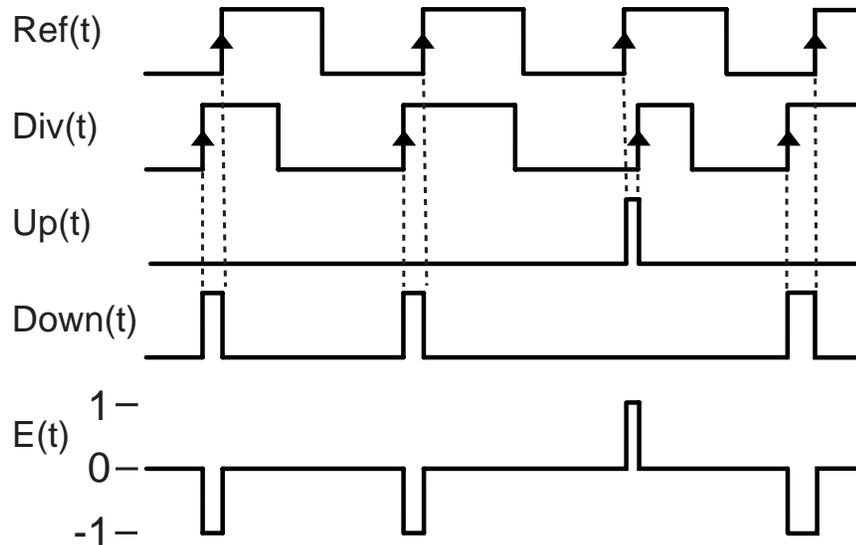
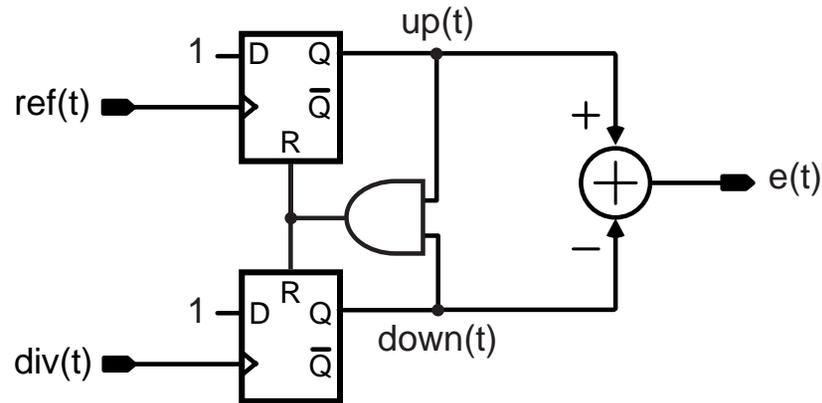
- PLL output frequency indeed oscillates
  - Eventually locks when frequency difference is small enough



- How do we extend the frequency lock-in range?

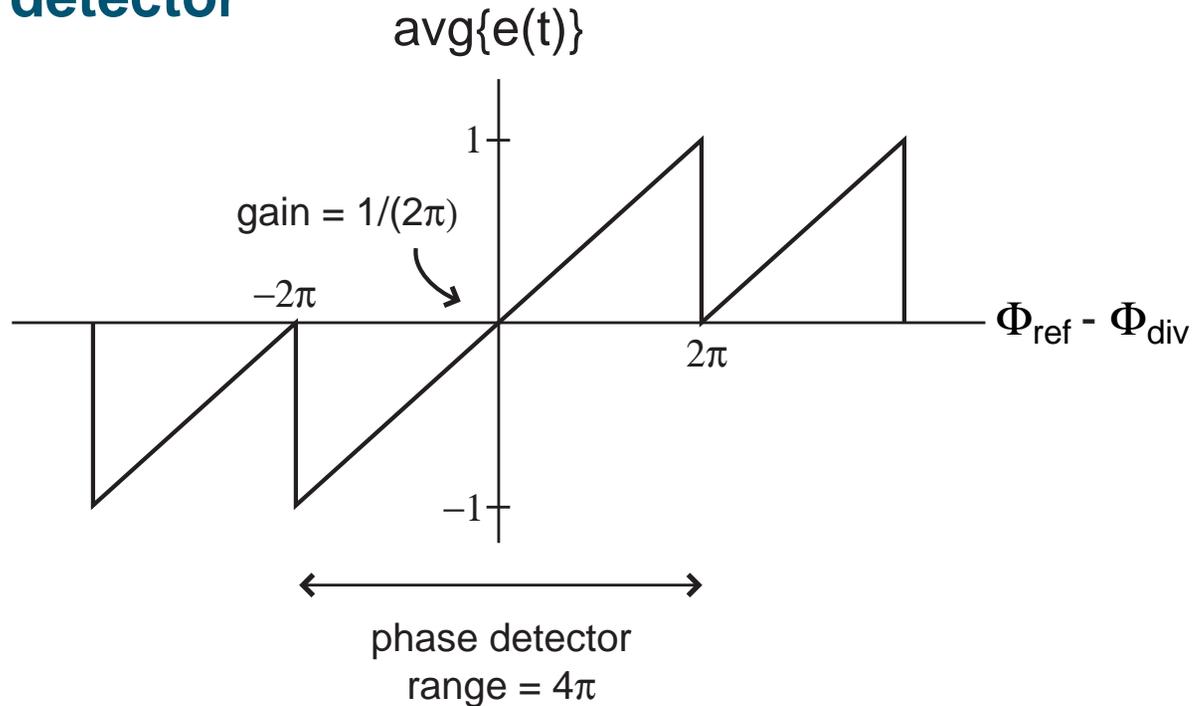
# Phase Frequency Detectors (PFD)

## ■ Example: Tristate PFD



## Tristate PFD Characteristic

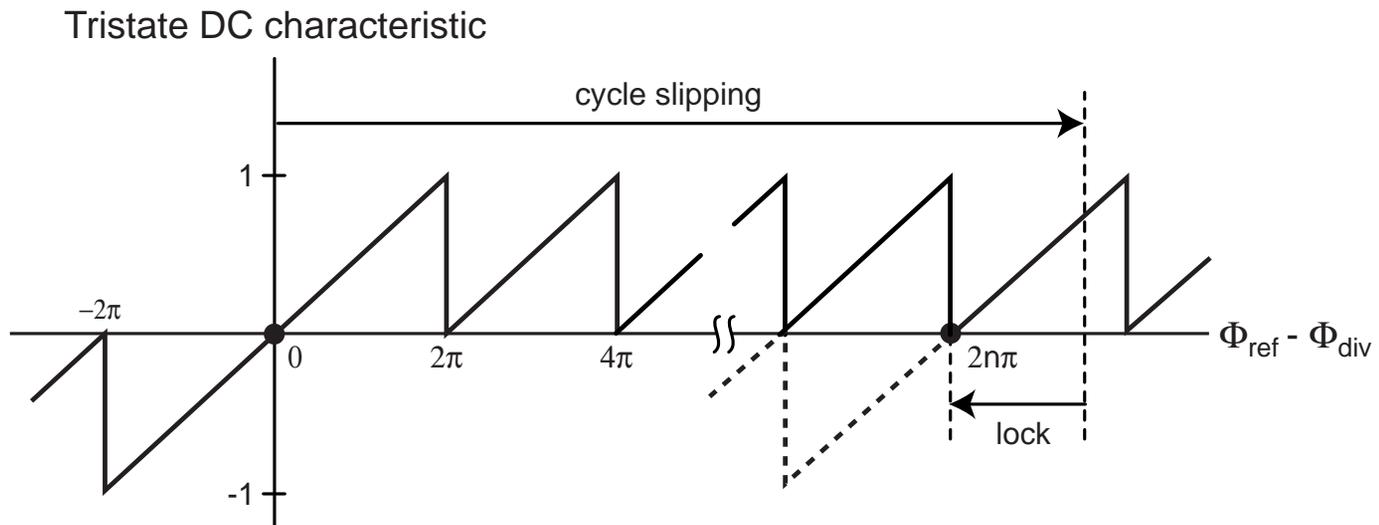
- Calculate using similar approach as used for XOR phase detector



- Note that phase error characteristic is asymmetric about zero phase
  - Key attribute for enabling frequency detection

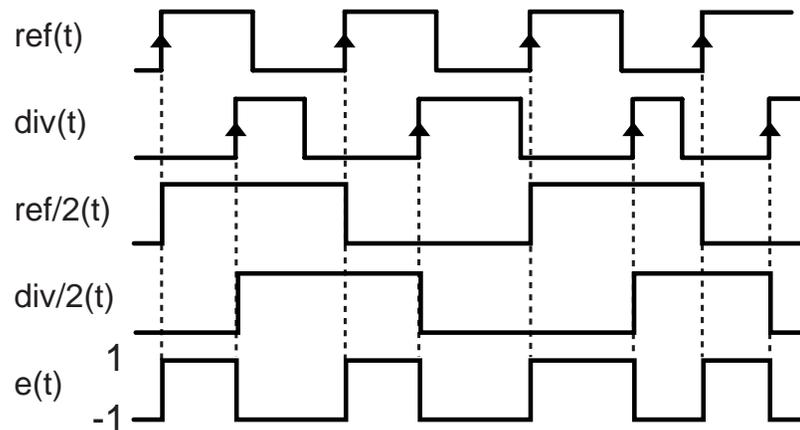
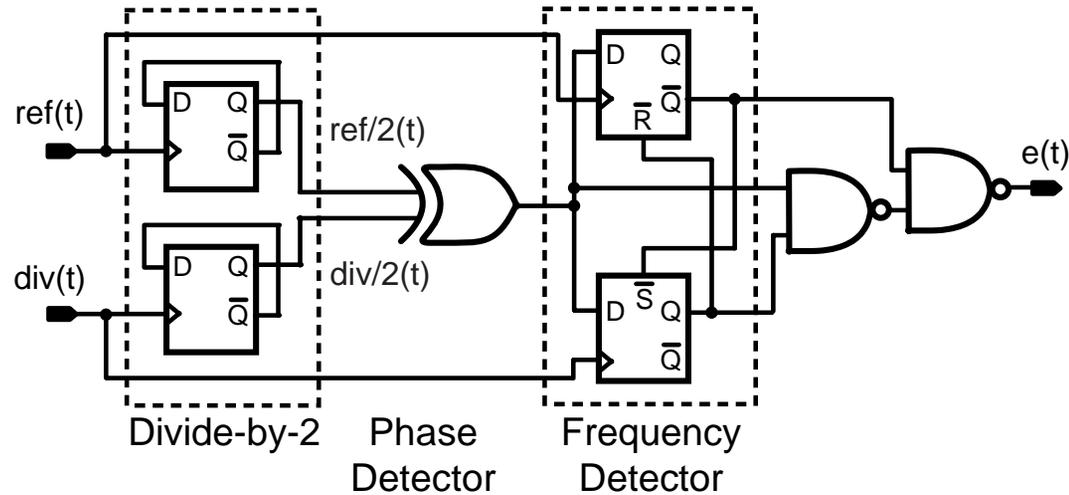
# *PFD Enables PLL to Always Regain Frequency Lock*

- **Asymmetric phase error characteristic allows positive frequency differences to be distinguished from negative frequency differences**
  - Average value is now positive or negative according to sign of frequency offset
  - PLL will always relock



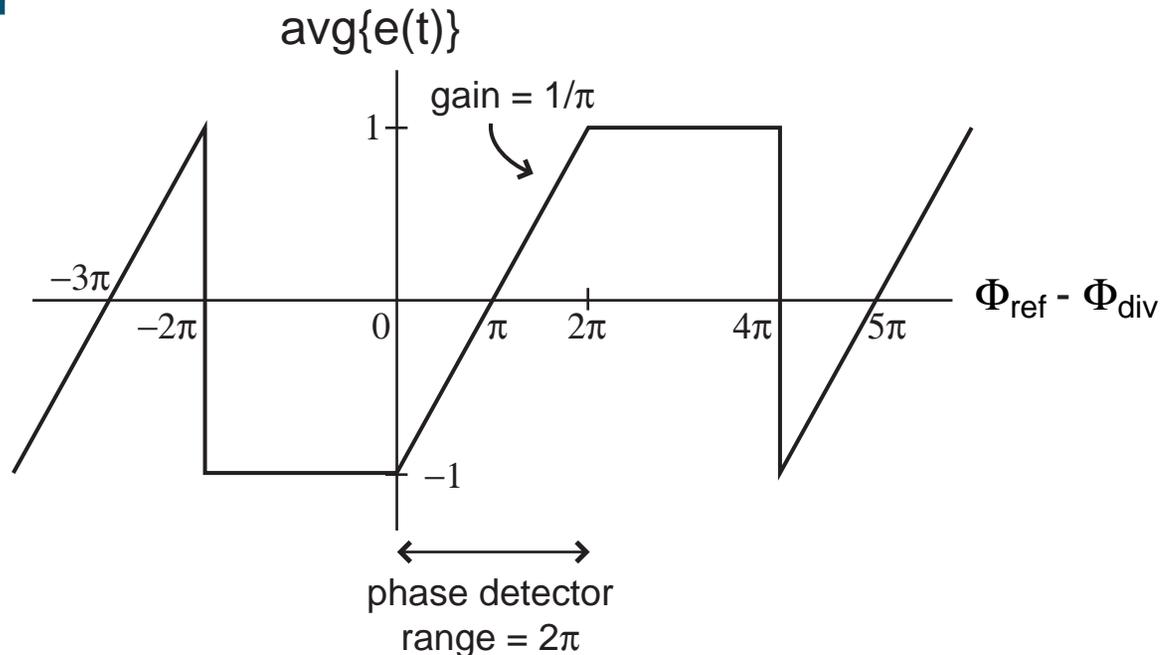
# Another PFD Structure

## ■ XOR-based PFD



## XOR-based PFD Characteristic

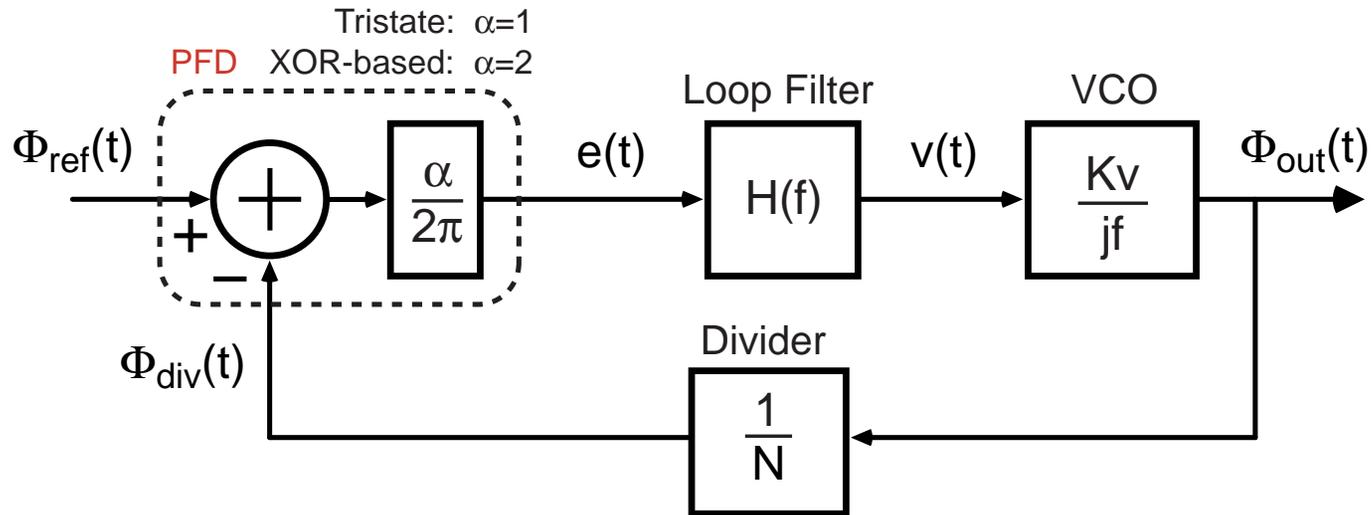
- Calculate using similar approach as used for XOR phase detector



- Phase error characteristic asymmetric about zero phase
  - Average value of phase error is positive or negative during cycle slipping depending on sign of frequency error

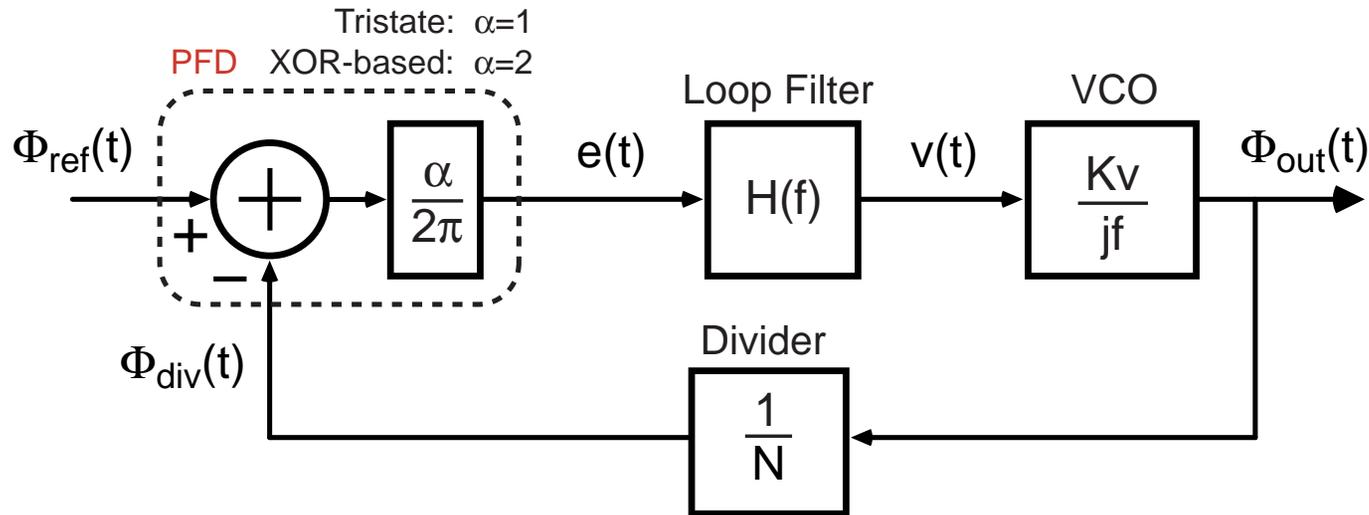
# Linearized PLL Model With PFD Structures

- Assume that when PLL in lock, phase variations are within the linear range of PFD
  - Simulate impact of cycle slipping if desired (do not include its effect in model)
- Same frequency-domain PLL model as before, but PFD gain depends on topology used



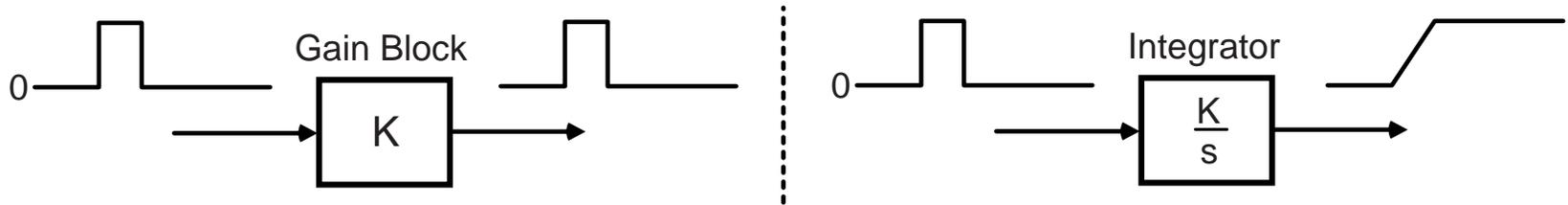
# Type I versus Type II PLL Implementations

- **Type I: one integrator in PLL open loop transfer function**
  - VCO adds on integrator
  - Loop filter,  $H(f)$ , has no integrators
- **Type II: two integrators in PLL open loop transfer function**
  - Loop filter,  $H(f)$ , has one integrator

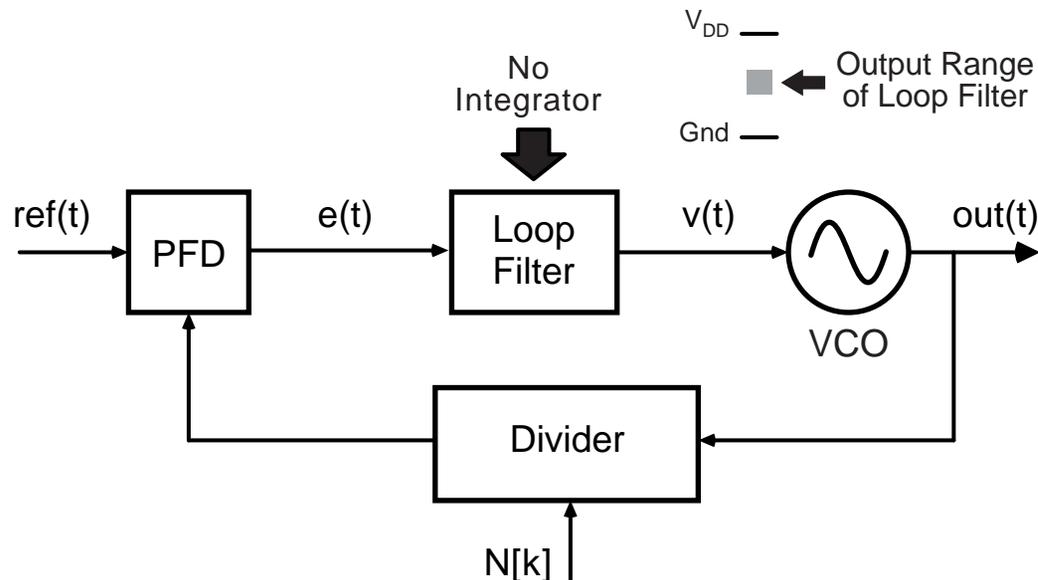


# VCO Input Range Issue for Type I PLL Implementations

- DC output range of gain block versus integrator



- Issue: DC gain of loop filter often small and PFD output range is limited
  - Loop filter output fails to cover full input range of VCO



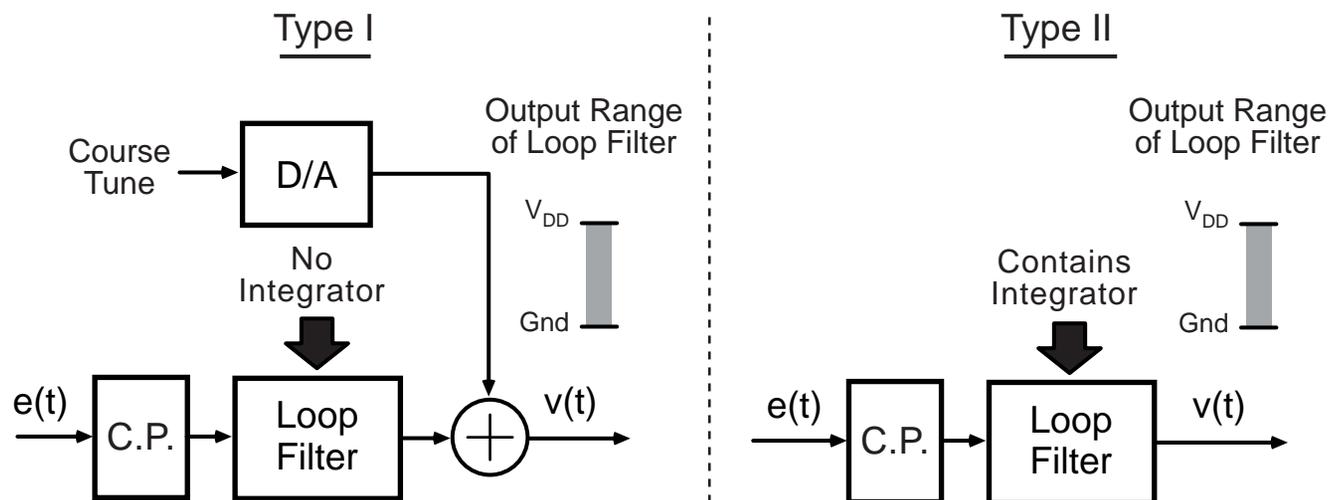
# Options for Achieving Full Range Span of VCO

## ■ Type I

- Add a D/A converter to provide coarse tuning
  - Adds power and complexity
  - Steady-state phase error inconsistently set

## ■ Type II

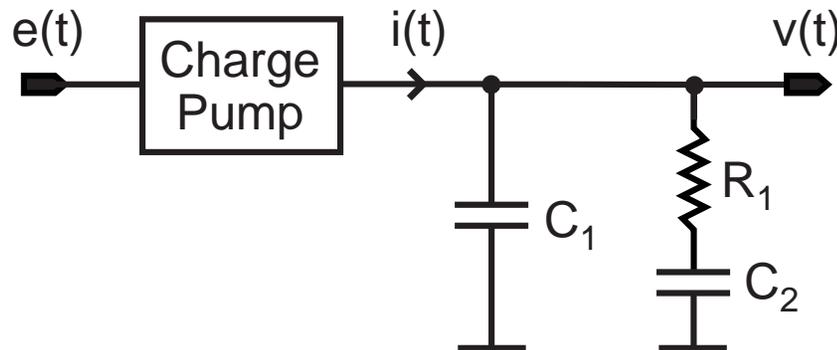
- Integrator automatically provides DC level shifting
  - Low power and simple implementation
  - Steady-state phase error always set to zero



# A Common Loop Filter for Type II PLL Implementation

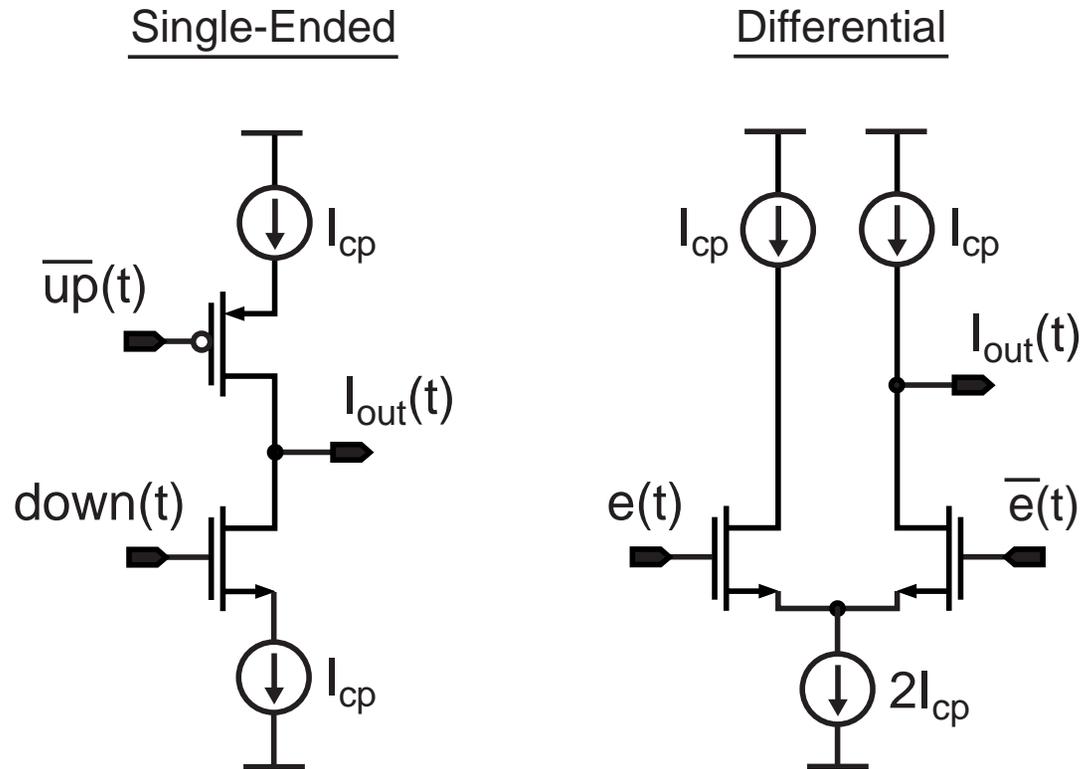
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- Use a charge pump to create the integrator
  - Current onto a capacitor forms integrator
  - Add extra pole/zero using resistor and capacitor
- Gain of loop filter can be adjusted according to the value of the charge pump current
- Example: lead/lag network



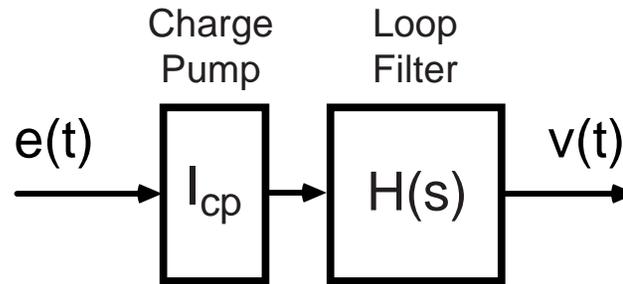
# Charge Pump Implementations

- Switch currents in and out:



# Modeling of Loop Filter/Charge Pump

- Charge pump is gain element
- Loop filter forms transfer function



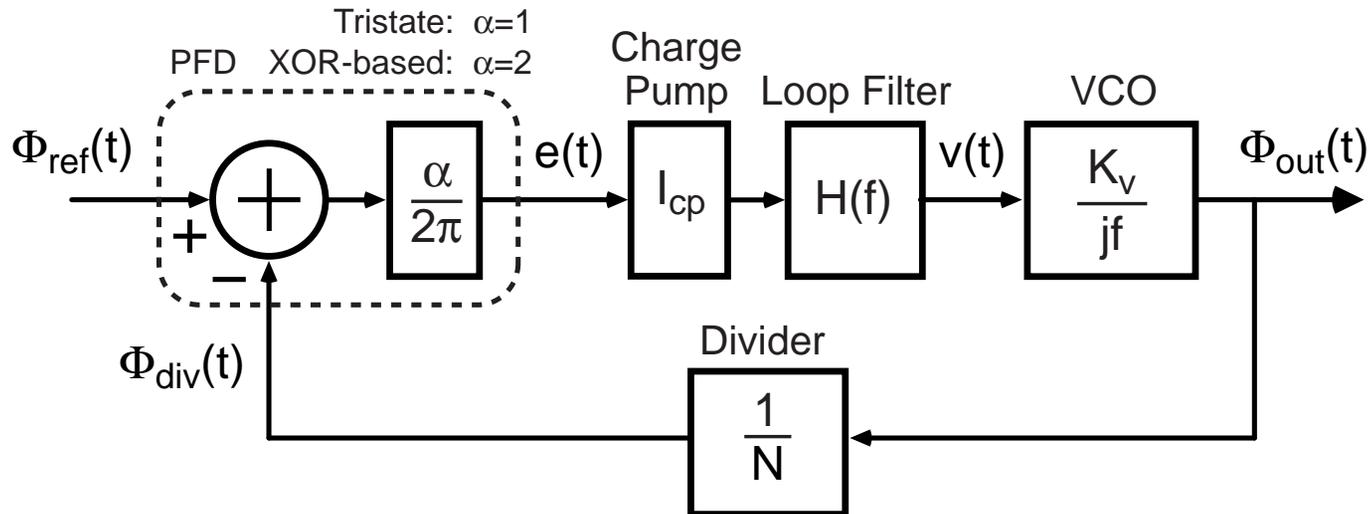
- Example: lead/lag network from previous slide

$$H(f) = \left( \frac{1}{sC_{sum}} \right) \frac{1 + jf/f_z}{1 + jf/f_p}$$

$$C_{sum} = C_1 + C_2, \quad f_z = \frac{1}{2\pi R_1 C_2}, \quad f_p = \frac{C_1 + C_2}{2\pi R_1 C_1 C_2}$$

# PLL Design with Lead/Lag Filter

## Overall PLL block diagram

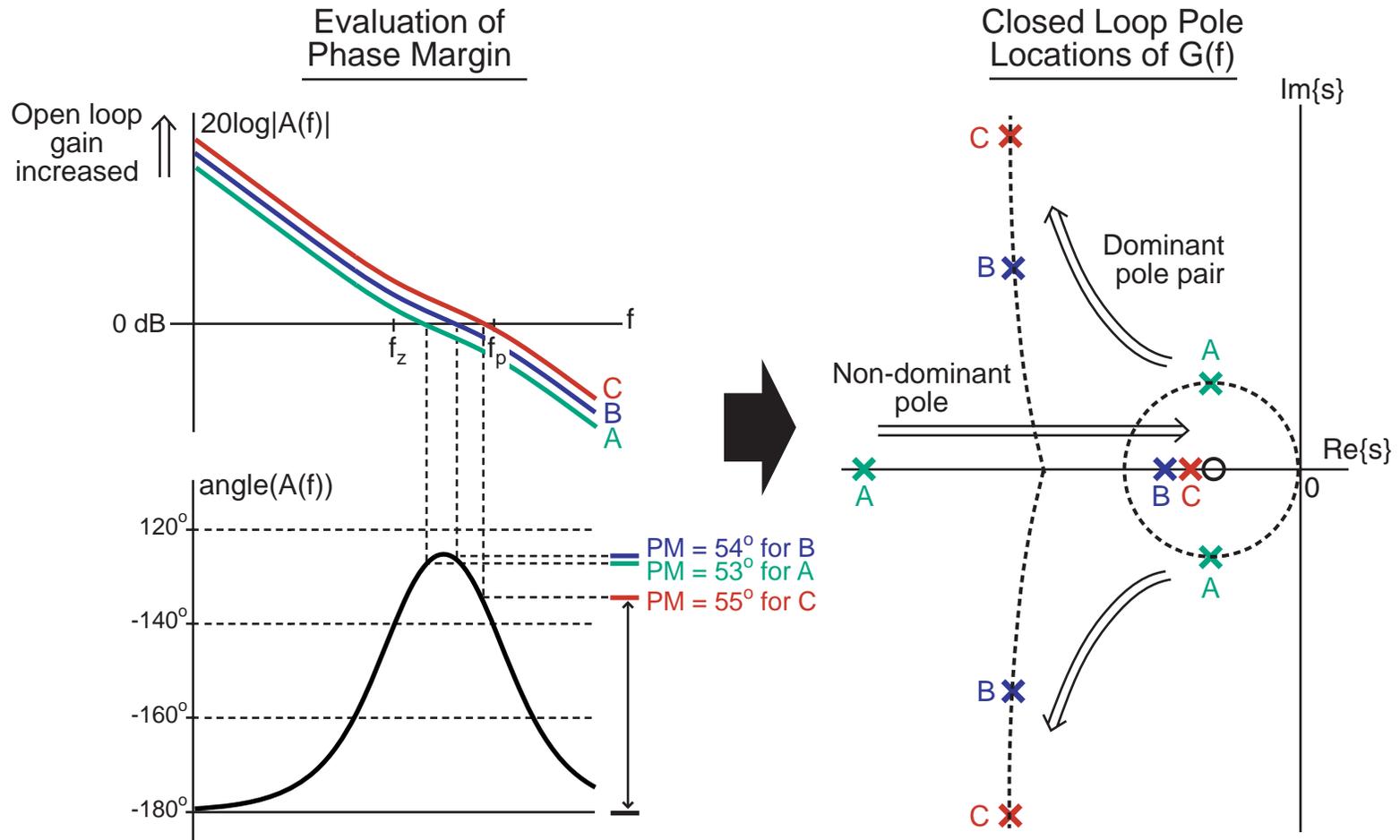


## Loop filter

$$H(f) = \left( \frac{1}{sC_{sum}} \right) \frac{1 + jf/f_z}{1 + jf/f_p}$$

- Set open loop gain to achieve adequate phase margin
  - Set  $f_z$  lower than and  $f_p$  higher than desired PLL bandwidth

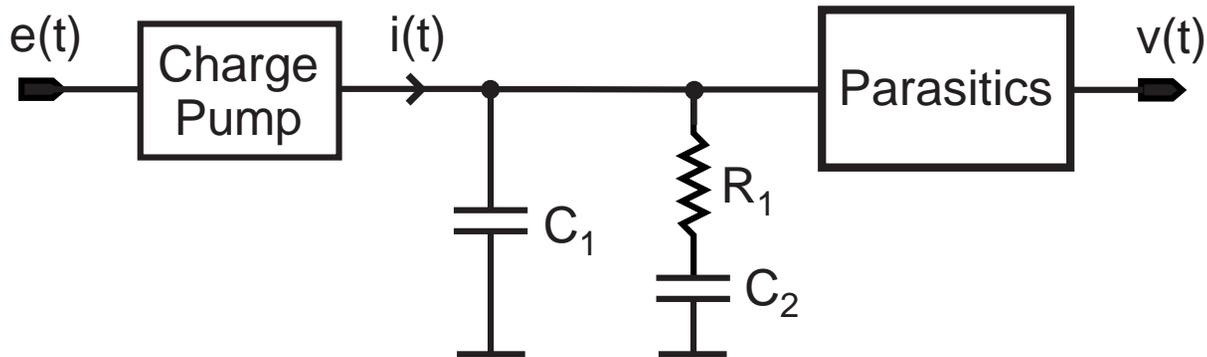
# Closed Loop Poles Versus Open Loop Gain



- Open loop gain cannot be too low or too high if reasonable phase margin is desired

## Impact of Parasitics When Lead/Lag Filter Used

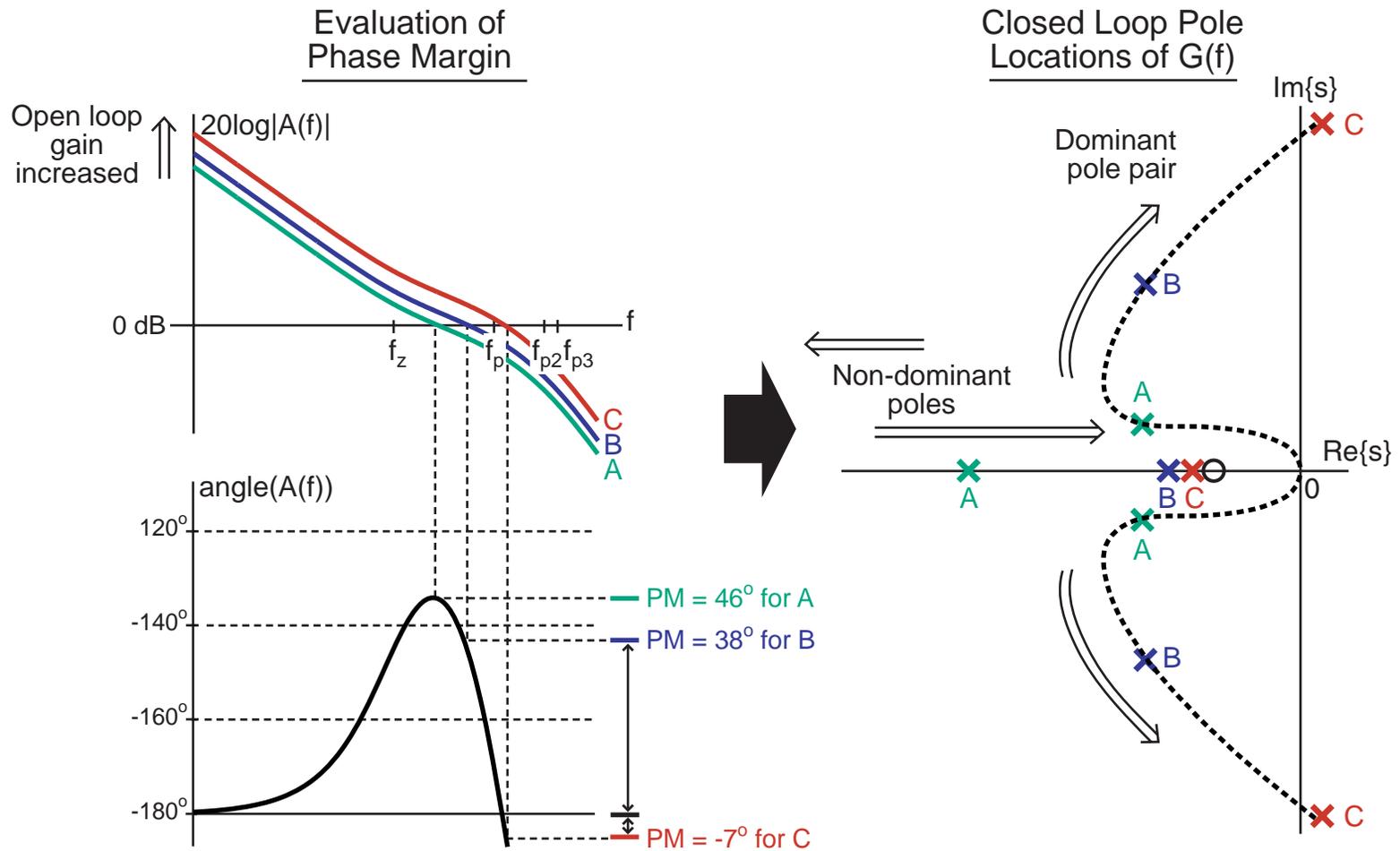
- We can again model impact of parasitics by including them in loop filter transfer function



- Example: include two parasitic poles with the lead/lag transfer function

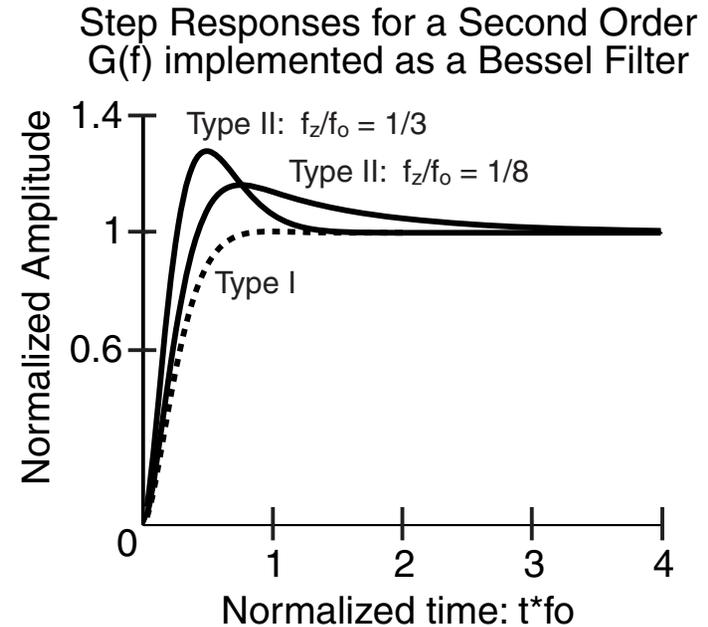
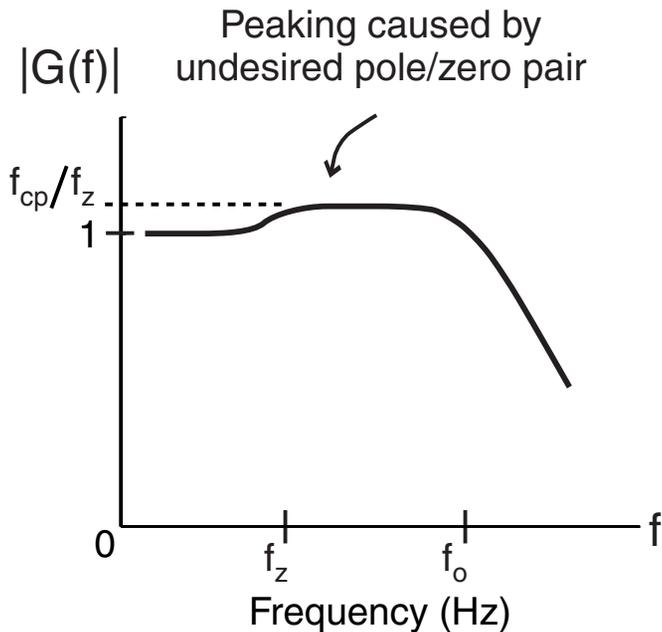
$$H(f) = \left( \frac{1}{sC_{sum}} \right) \frac{1 + jf/f_z}{1 + jf/f_p} \left( \frac{1}{1 + jf/f_{p2}} \right) \left( \frac{1}{1 + jf/f_{p3}} \right)$$

# Closed Loop Poles Versus Open Loop Gain



- Closed loop response becomes unstable if open loop gain is too high

# Negative Issues For Type II PLL Implementations



- **Parasitic pole/zero pair causes**
  - **Peaking in the closed loop frequency response**
    - A big issue for CDR systems, but not too bad for wireless
  - **Extended settling time due to parasitic “tail” response**
    - Bad for wireless systems demanding fast settling time

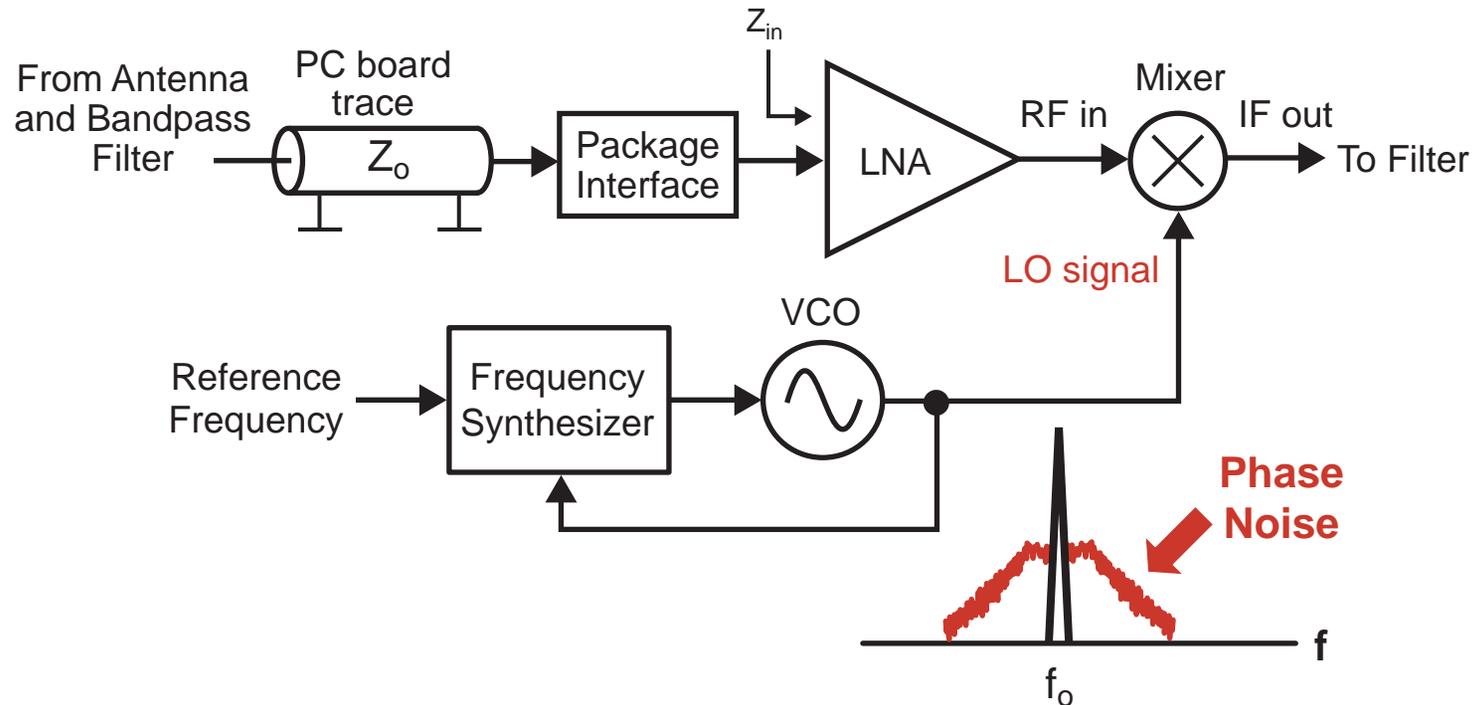
# ***Summary of Integer-N Dynamic Modeling***

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- **Linearized models can be derived for each PLL block**
  - **Resulting transfer function model of PLL is accurate for small perturbations in PLL**
  - **Linear PLL model breaks down for large perturbations on PLL, such as a large step change in frequency**
    - **Cycle slipping is key nonlinear effect**
- **Key issues for designing PLL are**
  - **Achieve stable operation with desired bandwidth**
  - **Allow full range of VCO with a simple implementation**
    - **Type II PLL is very popular to achieve this**

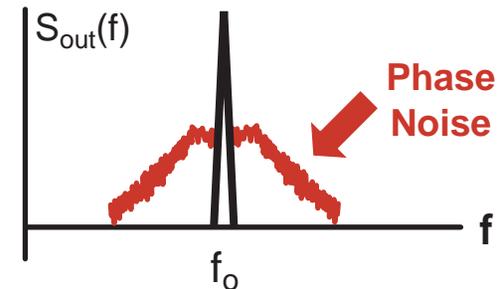
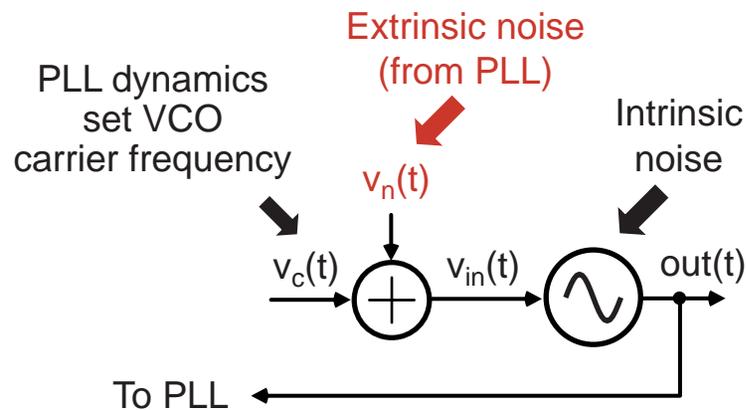
# ***Noise Analysis of Integer-N Synthesizers***

# Frequency Synthesizer Noise in Wireless Systems



- **Synthesizer noise has a negative impact on system**
  - Receiver – lower sensitivity, poorer blocking performance
  - Transmitter – increased spectral emissions (output spectrum must meet a mask requirement)
- **Noise is characterized in frequency domain**

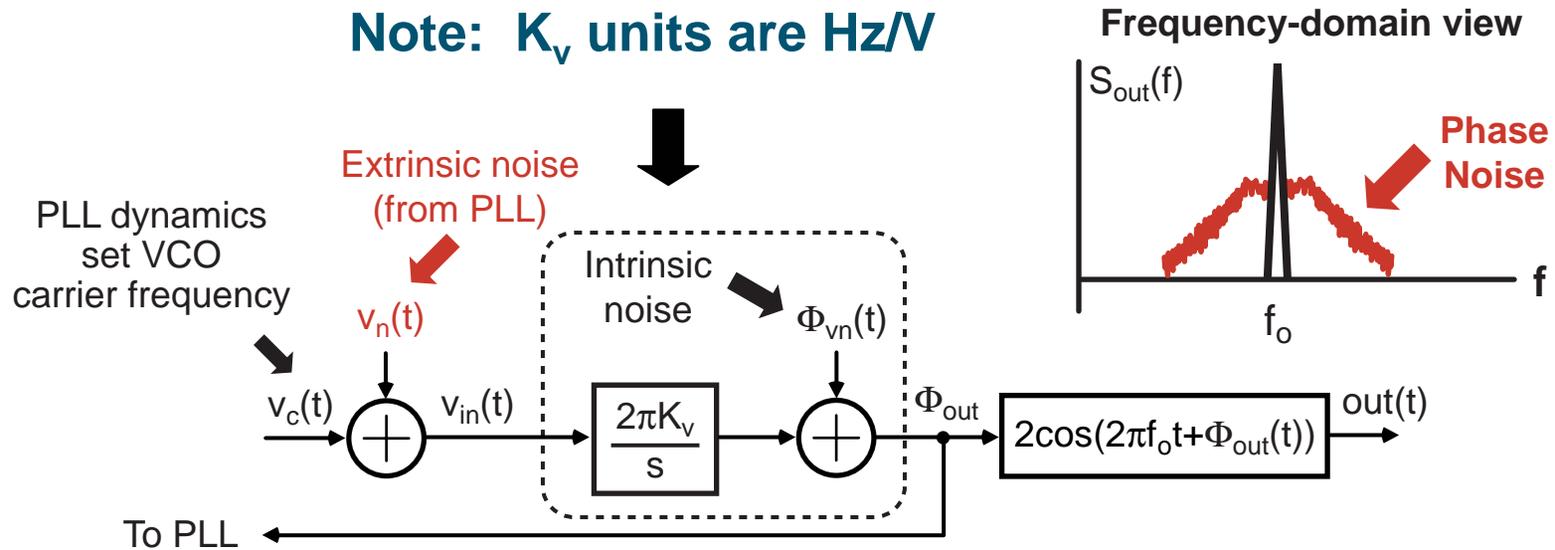
# Noise Modeling for Frequency Synthesizers



- **PLL has an impact on VCO noise in two ways**
  - Adds extrinsic noise from various PLL circuits
  - Highpass filters VCO noise through PLL feedback dynamics
- **Focus on modeling the above based on phase deviations**
  - Simpler than dealing directly with PLL sine wave output

# Phase Deviation Model for Noise Analysis

Note:  $K_v$  units are Hz/V



- Model the impact of noise on instantaneous phase
  - Relationship between PLL output and instantaneous phase

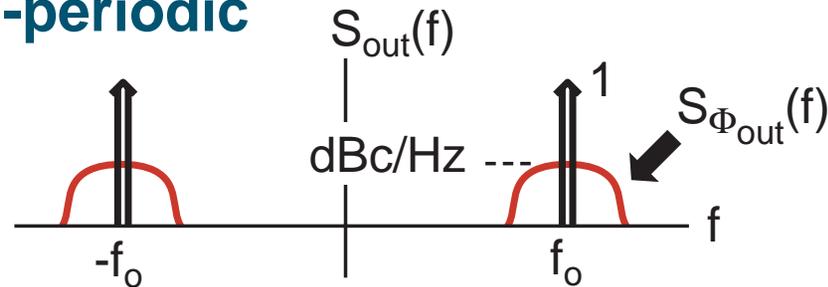
$$out(t) = 2 \cos(2\pi f_0 t + \Phi_{out}(t))$$

- Output spectrum (we will derive this in a later lecture)

$$S_{out}(f) = S_{sin}(f) + S_{sin}(f) * S_{\Phi_{out}}$$

# Phase Noise Versus Spurious Noise

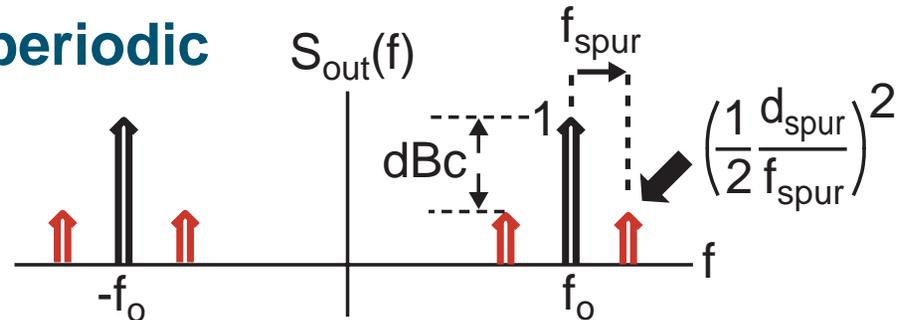
- Phase noise is non-periodic



- Described as a spectral density relative to carrier power

$$L(f) = 10 \log(S_{\Phi_{out}}(f)) \text{ dBc/Hz}$$

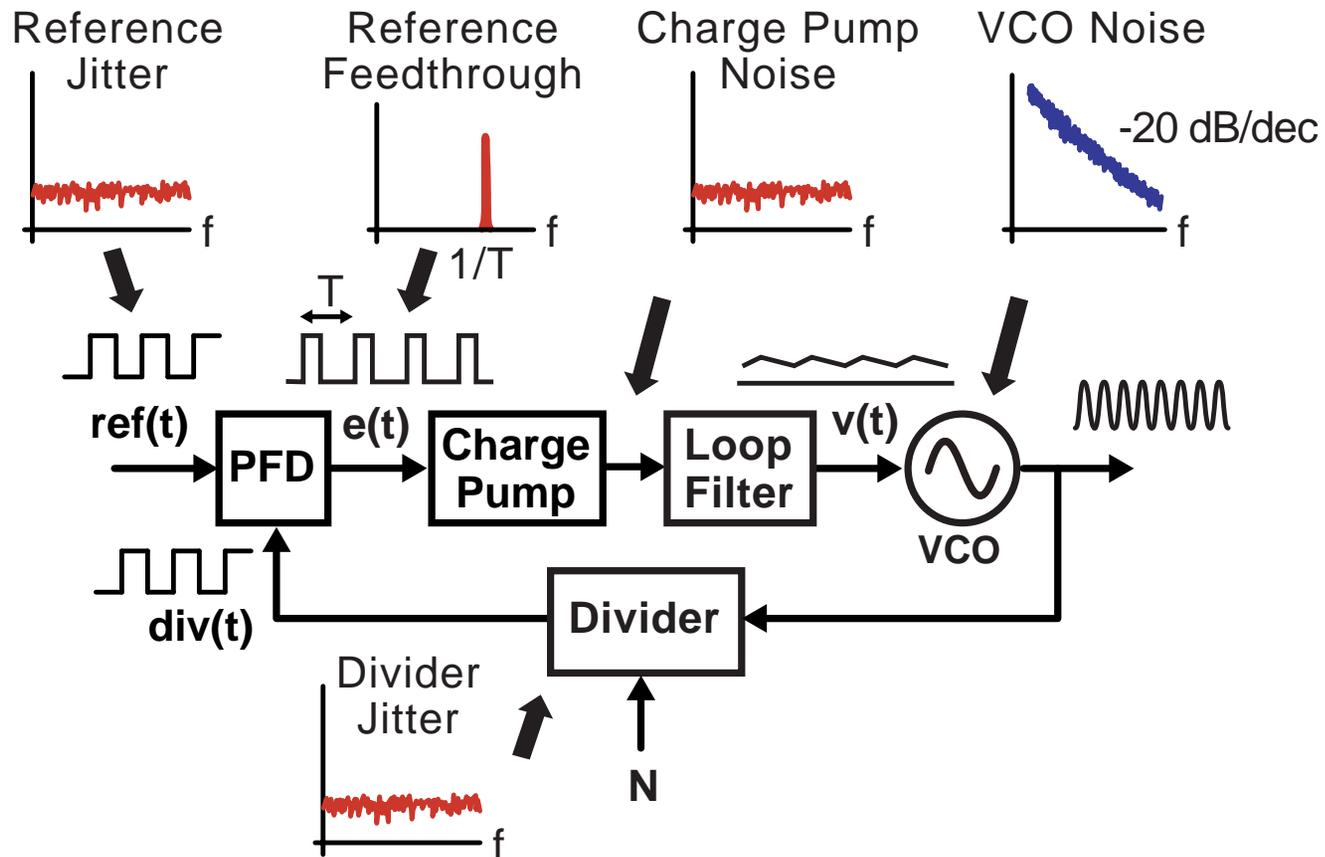
- Spurious noise is periodic



- Described as tone power relative to carrier power

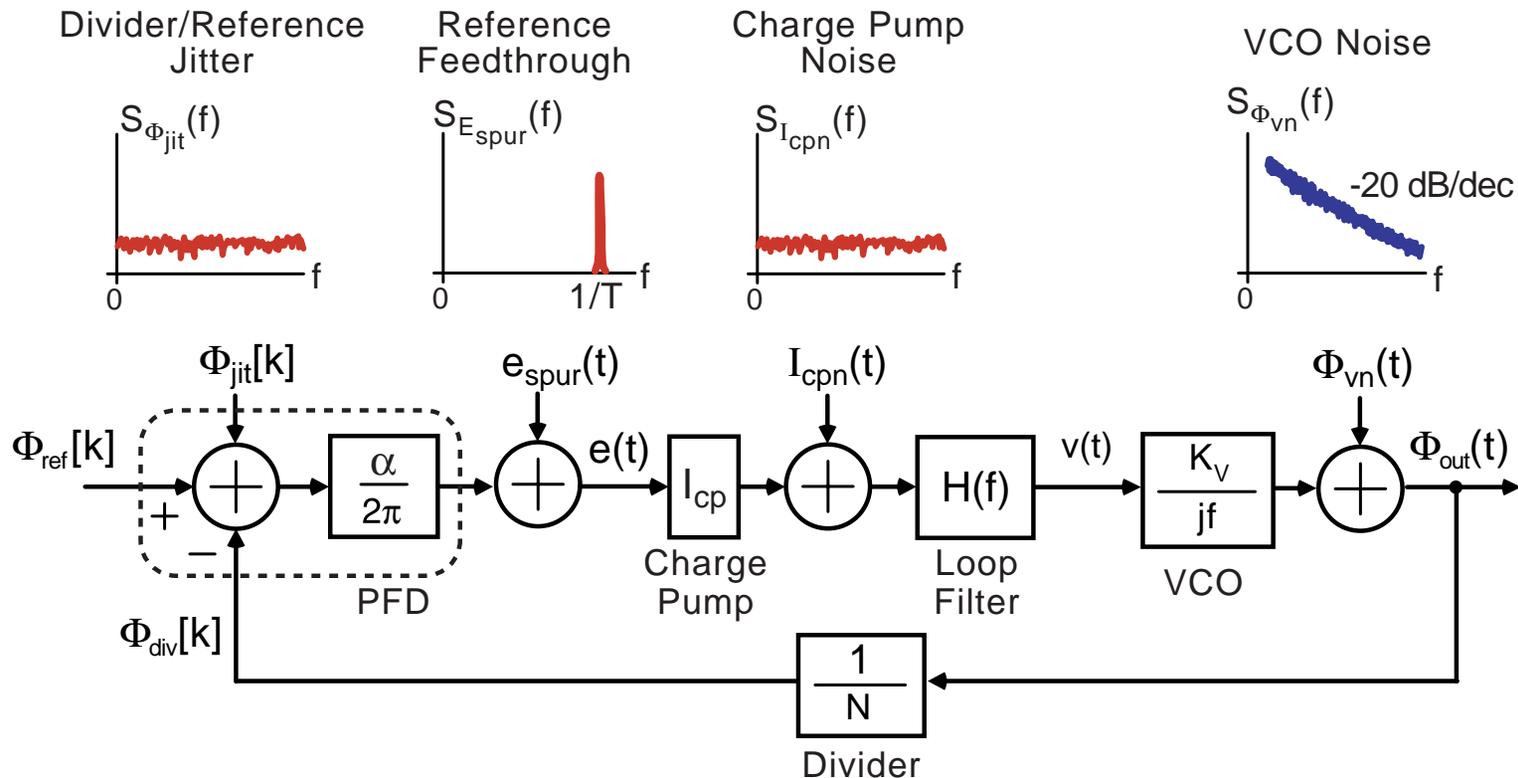
$$20 \log \left( \frac{d_{spur}}{2f_{spur}} \right) \text{ dBc}$$

# Sources of Noise in Frequency Synthesizers



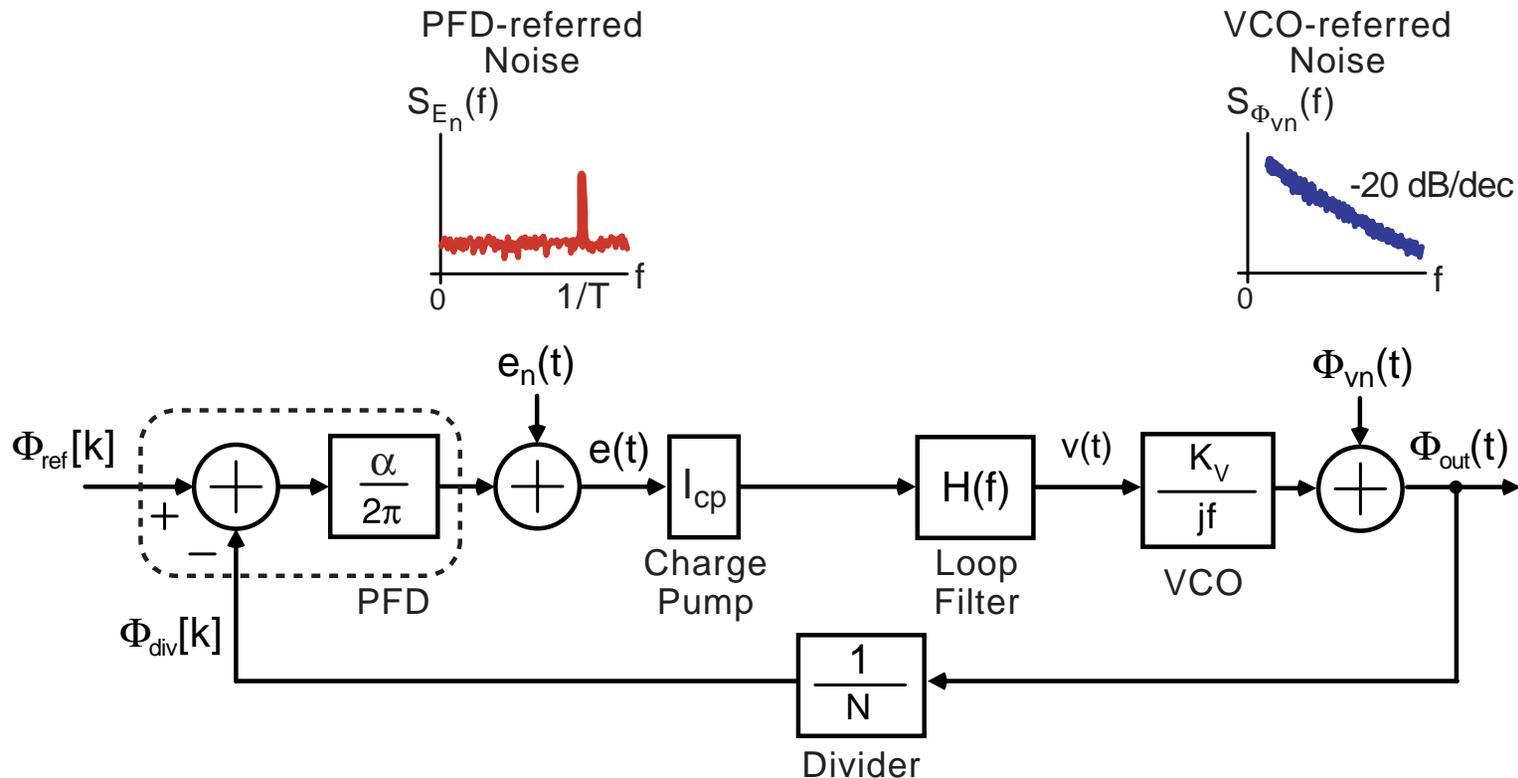
- **Extrinsic noise sources to VCO**
  - Reference/divider jitter and reference feedthrough
  - Charge pump noise

# Modeling the Impact of Noise on Output Phase of PLL



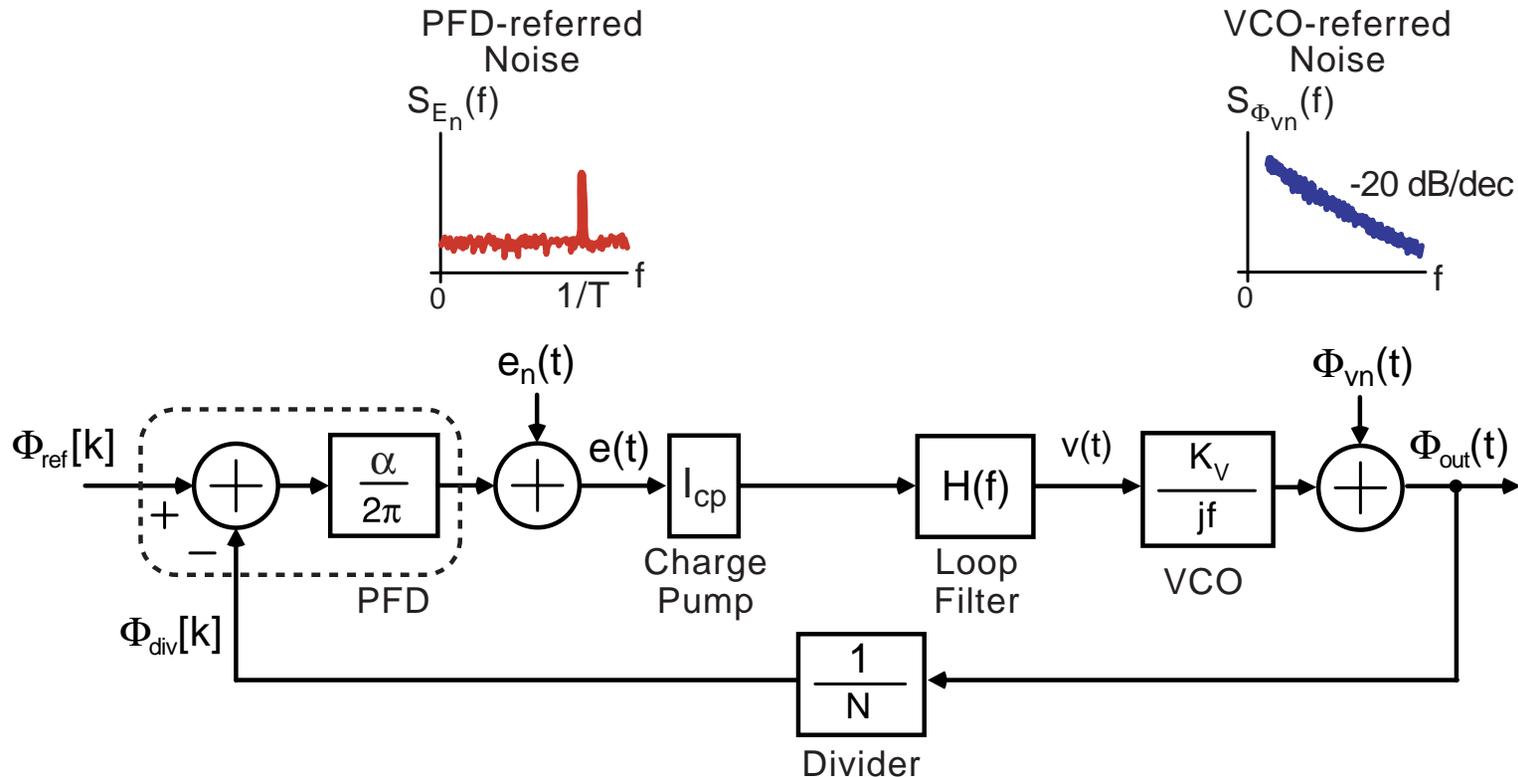
- **Determine impact on output phase by deriving transfer function from each noise source to PLL output phase**
  - **There are a lot of transfer functions to keep track of!**

# Simplified Noise Model



- Refer all PLL noise sources (other than the VCO) to the PFD output
  - PFD-referred noise corresponds to the sum of these noise sources referred to the PFD output

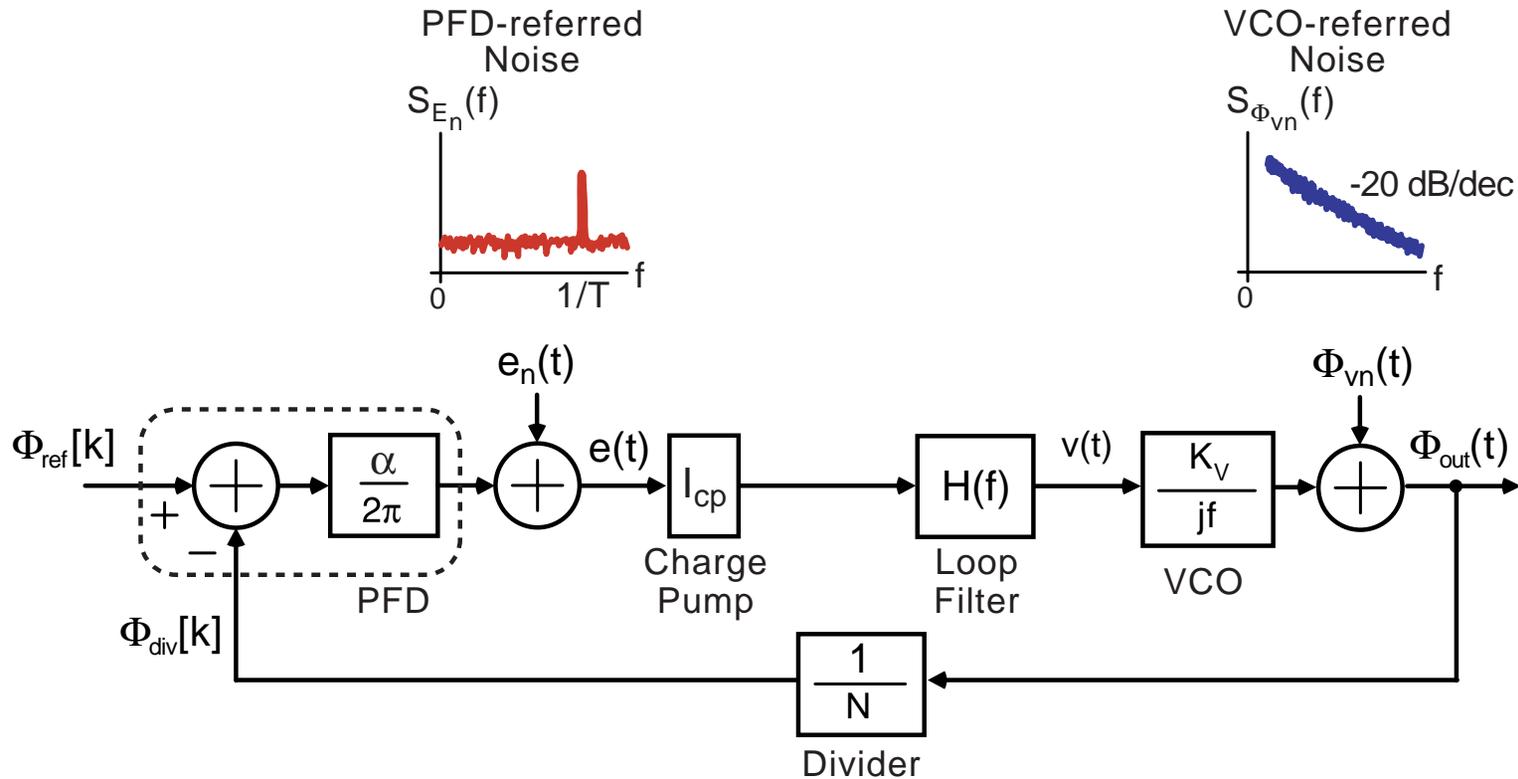
# Impact of PFD-referred Noise on Synthesizer Output



- Transfer function derived using Black's formula

$$\frac{\Phi_{out}}{e_n} = \frac{I_{cp}H(f)K_v/(jf)}{1 + \alpha/(2\pi)I_{cp}H(f)K_v/(jf)(1/N)}$$

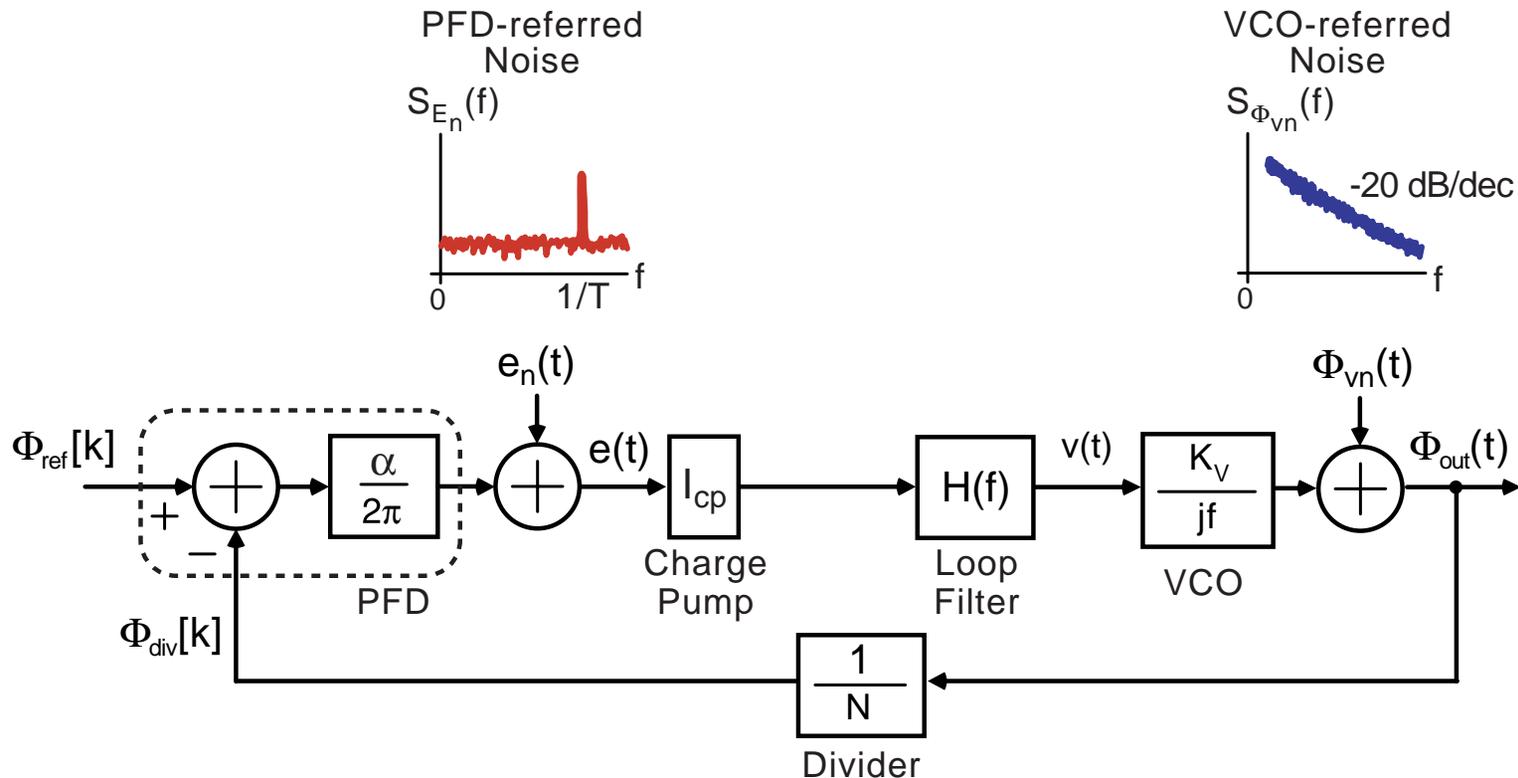
# Impact of VCO-referred Noise on Synthesizer Output



- Transfer function again derived from Black's formula

$$\frac{\Phi_{out}}{\Phi_{vn}} = \frac{1}{1 + \alpha/(2\pi)I_{cp}H(f)K_v/(jf)(1/N)}$$

# A Simpler Parameterization for PLL Transfer Functions



- Define  $G(f)$  as

$$G(f) = \frac{A(f)}{1 + A(f)}$$

Always has a gain of one at DC

- $A(f)$  is the open loop transfer function of the PLL

$$A(f) = \alpha / (2\pi) I_{cp} H(f) K_v / (j f) (1/N)$$

# Parameterize Noise Transfer Functions in Terms of $G(f)$

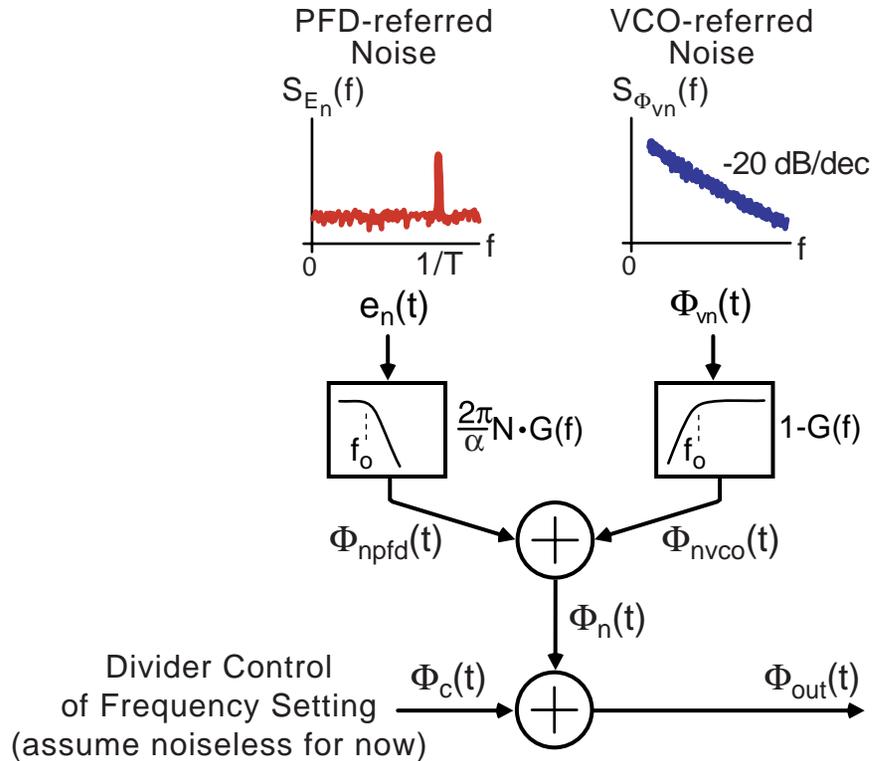
## ■ PFD-referred noise

$$\begin{aligned}\frac{\Phi_{out}}{e_n} &= \frac{I_{cp}H(f)K_v/(jf)}{1 + \alpha/(2\pi)I_{cp}H(f)K_v/(jf)(1/N)} \\ &= \frac{2\pi N}{\alpha} \frac{\alpha/(2\pi)I_{cp}H(f)K_v/(jf)(1/N)}{1 + \alpha/(2\pi)I_{cp}H(f)K_v/(jf)(1/N)} \\ &= \frac{2\pi N}{\alpha} \frac{A(f)}{1 + A(f)} = \boxed{\frac{2\pi N}{\alpha} G(f)}\end{aligned}$$

## ■ VCO-referred noise

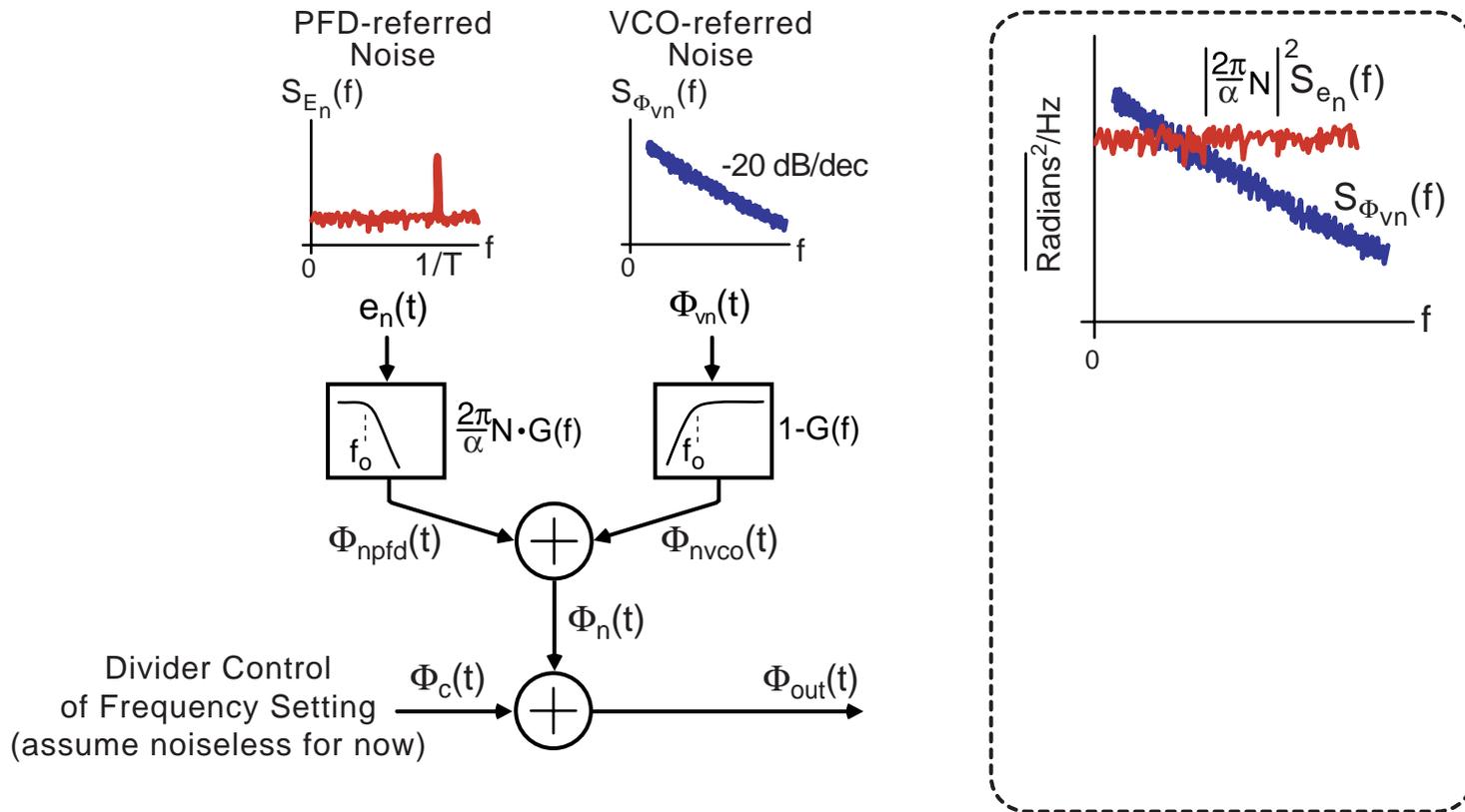
$$\begin{aligned}\frac{\Phi_{out}}{\Phi_{vn}} &= \frac{1}{1 + \alpha/(2\pi)I_{cp}H(f)K_v/(jf)(1/N)} \\ &= \frac{1}{1 + A(f)} = 1 - \frac{A(f)}{1 + A(f)} = \boxed{1 - G(f)}\end{aligned}$$

# Parameterized PLL Noise Model



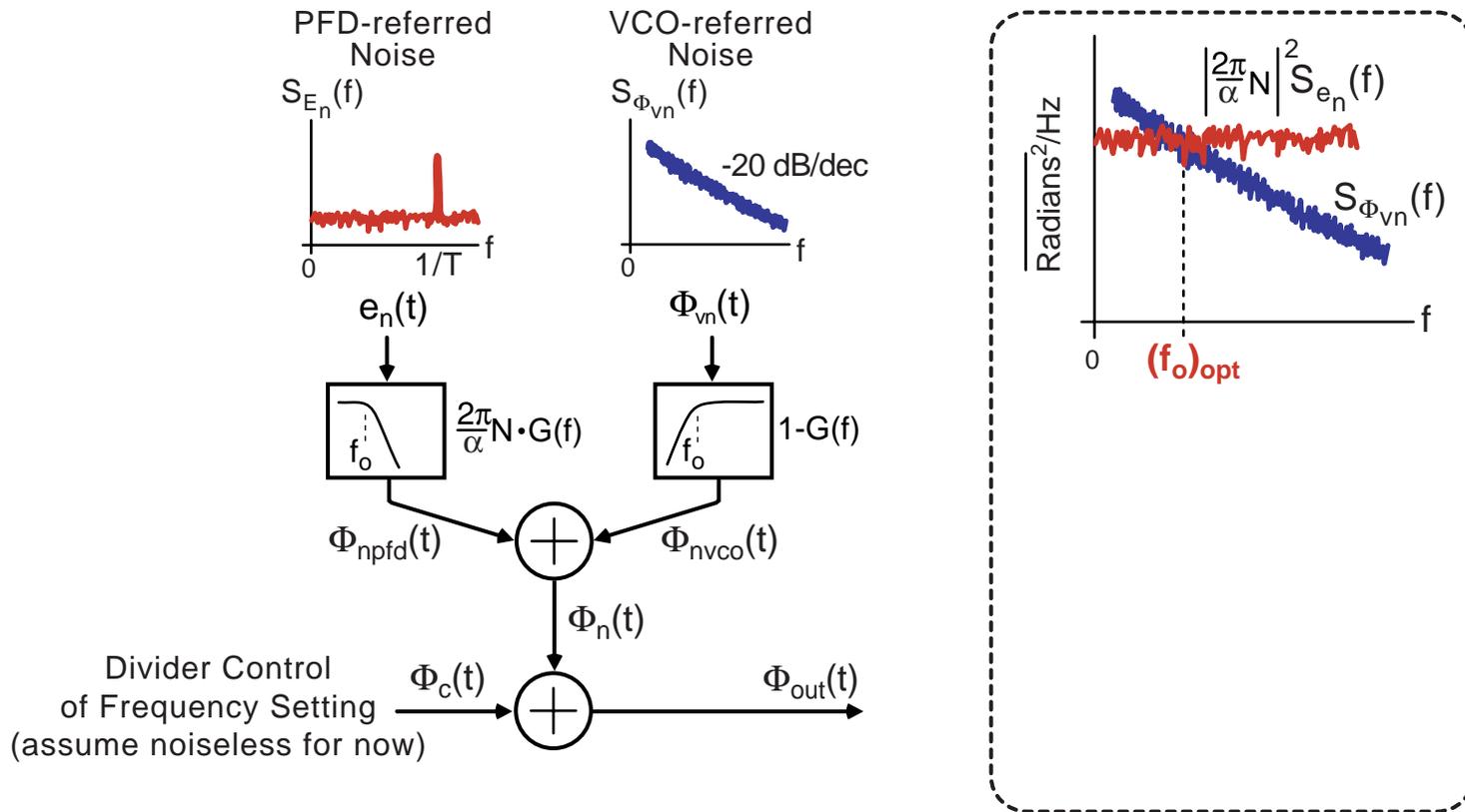
- **PFD-referred noise is lowpass filtered**
- **VCO-referred noise is highpass filtered**
- **Both filters have the same transition frequency values**
  - Defined as  $f_o$

# Impact of PLL Parameters on Noise Scaling



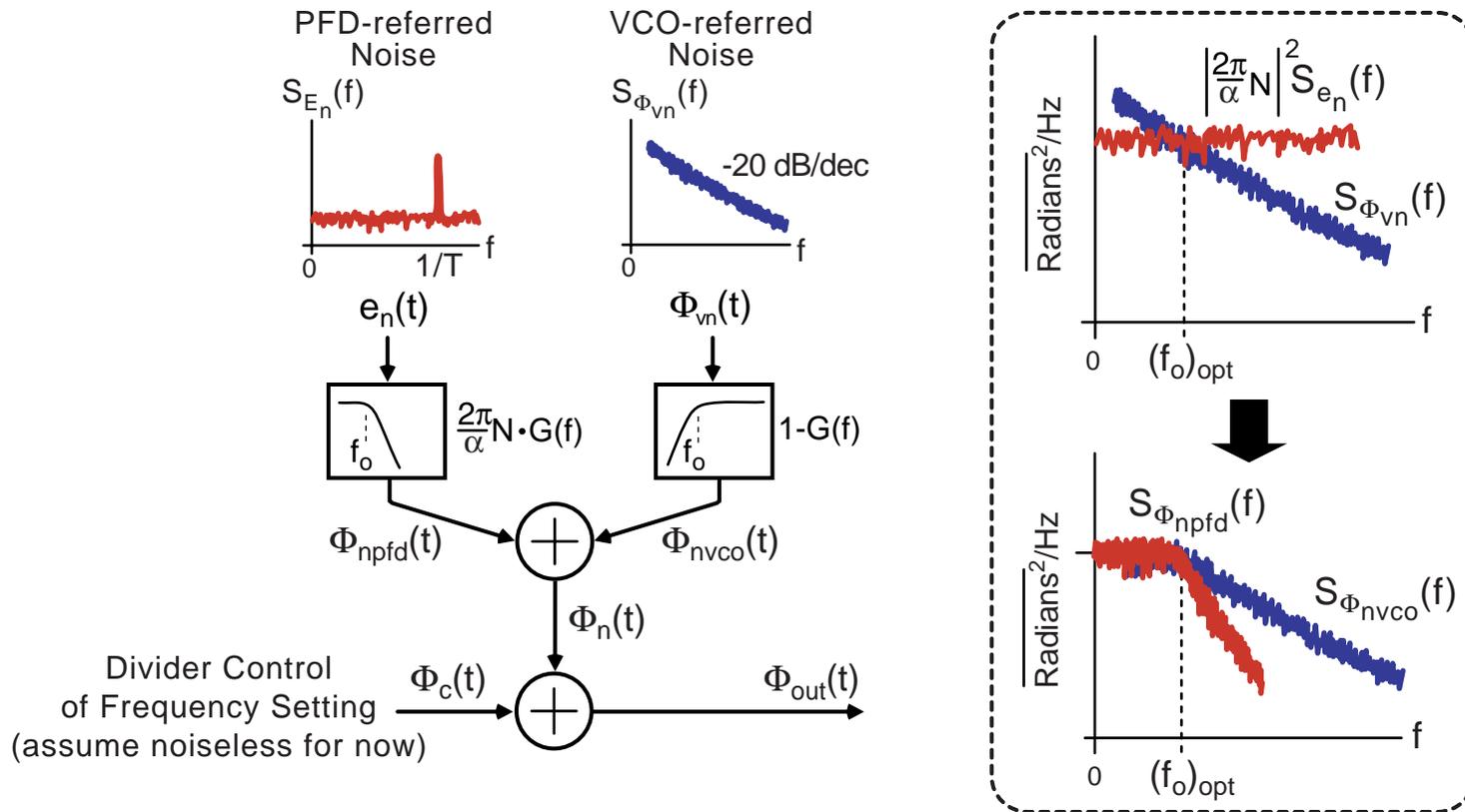
- **PFD-referred noise is scaled by square of divide value and inverse of PFD gain**
  - High divide values lead to large multiplication of this noise
- **VCO-referred noise is not scaled (only filtered)**

# Optimal Bandwidth Setting for Minimum Noise



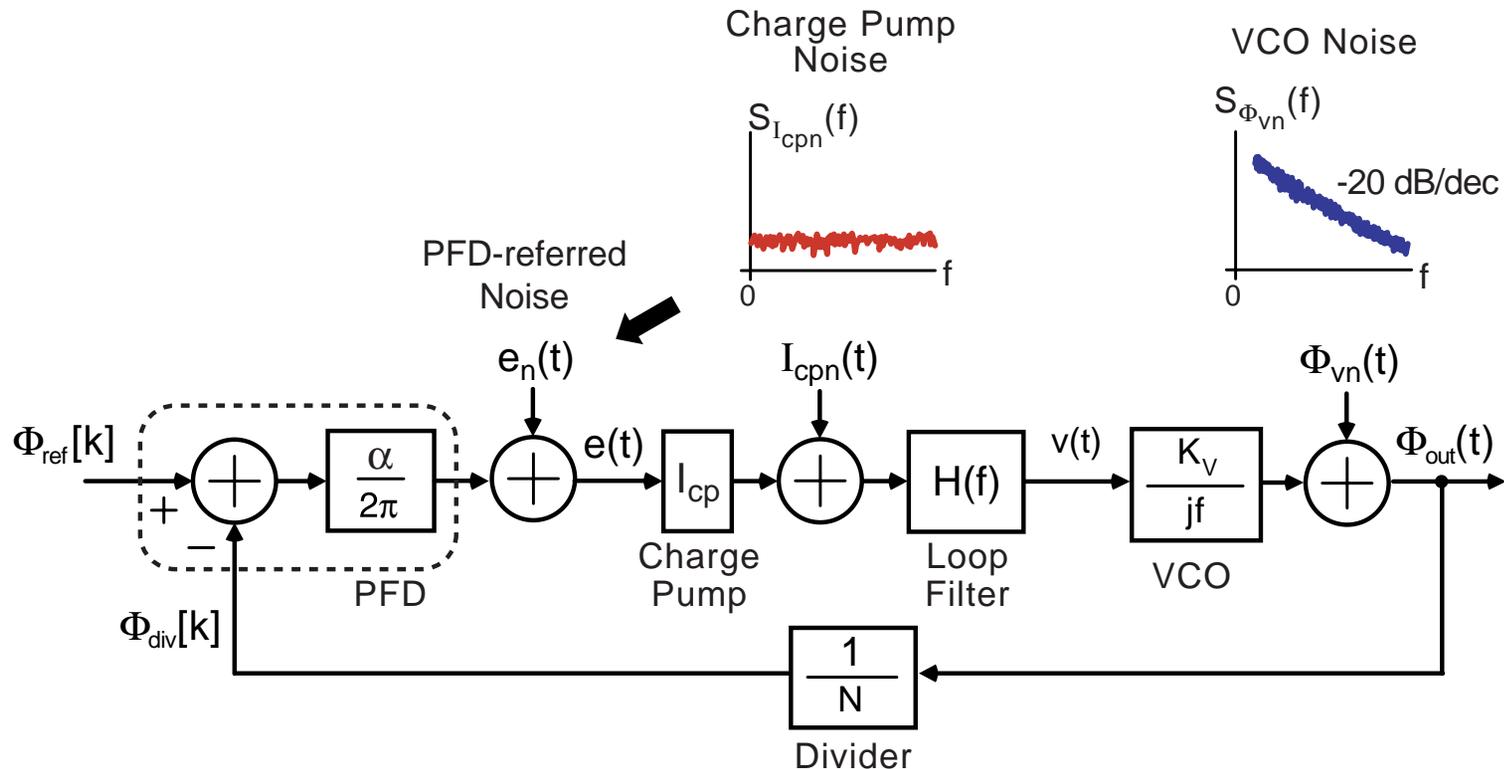
- **Optimal bandwidth is where scaled noise sources meet**
  - Higher bandwidth will pass more PFD-referred noise
  - Lower bandwidth will pass more VCO-referred noise

# Resulting Output Noise with Optimal Bandwidth



- **PFD-referred noise dominates at low frequencies**
  - Corresponds to close-in phase noise of synthesizer
- **VCO-referred noise dominates at high frequencies**
  - Corresponds to far-away phase noise of synthesizer

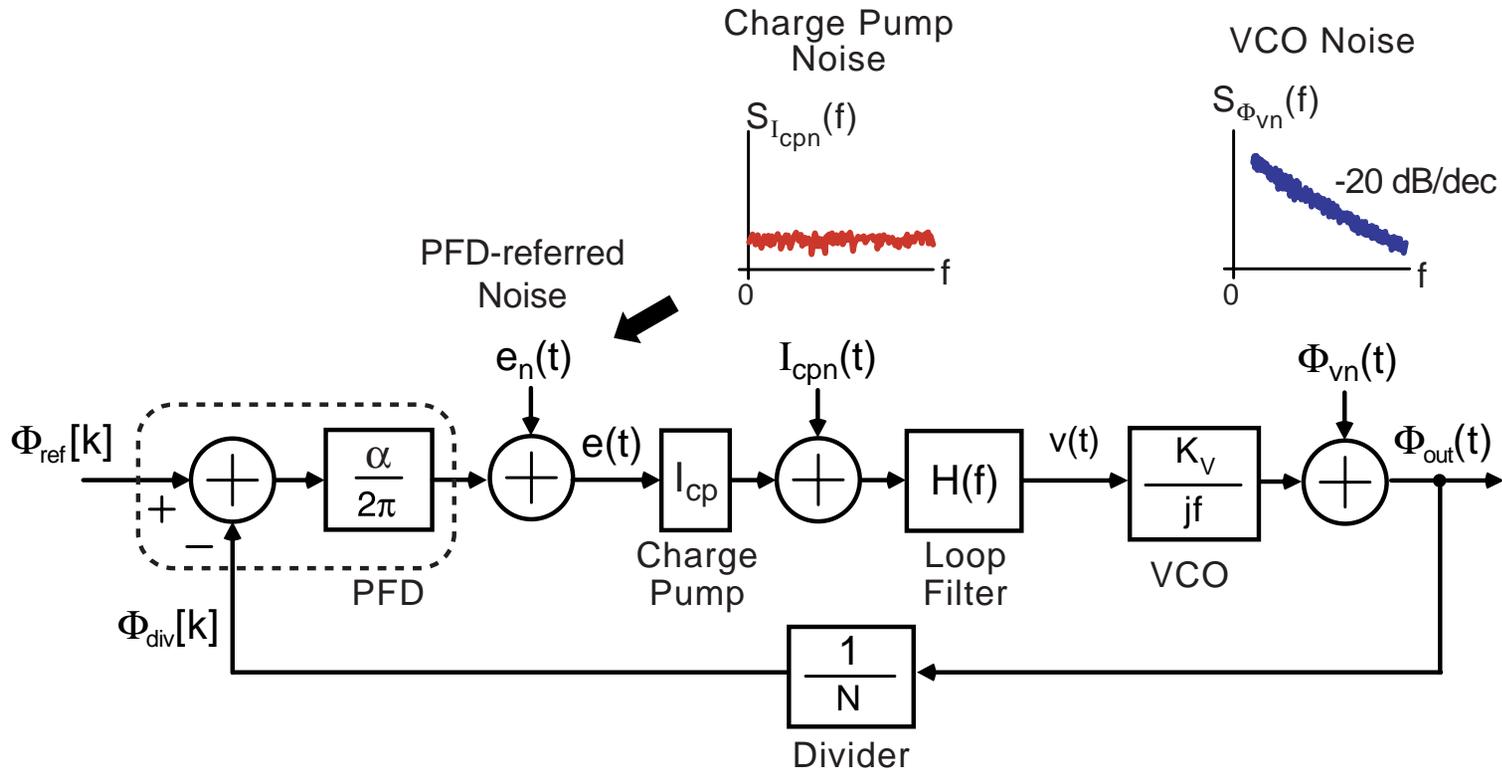
# Analysis of Charge Pump Noise Impact



- We can refer charge pump noise to PFD output by simply scaling it by  $1/I_{cp}$

$$\frac{\Phi_{out}}{I_{cpn}} = \left( \frac{1}{I_{cp}} \right) \frac{\Phi_{out}}{e_n} = \left( \frac{1}{I_{cp}} \right) \frac{2\pi}{\alpha} NG(f)$$

# Calculation of Charge Pump Noise Impact

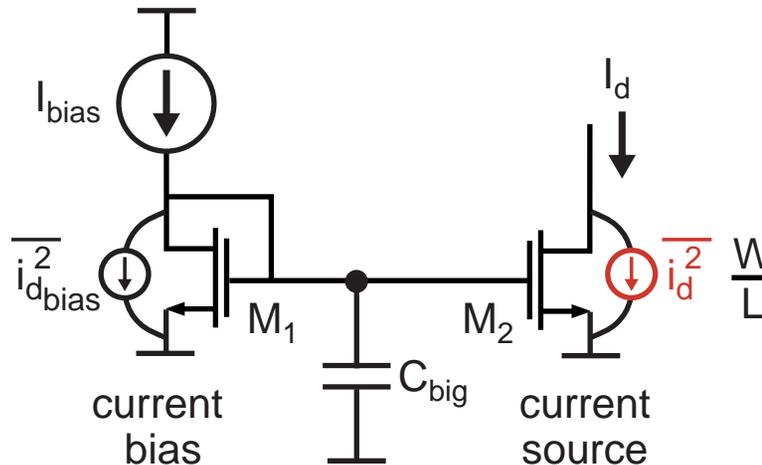


- **Contribution of charge pump noise to overall output noise**

$$S_{\Phi_{out}}(f) = \left(\frac{1}{I_{cp}}\right)^2 \left(\frac{2\pi N}{\alpha}\right)^2 |G(f)|^2 S_{I_{cpn}}(f) + \text{other sources}$$

- **Need to determine impact of  $I_{cp}$  on  $S_{I_{cpn}}(f)$**

# Impact of Transistor Current Value on its Noise



- Charge pump noise will be related to the current it creates as

$$S_{I_{cpn}}(f) \propto \frac{\overline{I_d^2}}{\Delta f} = 4kT\gamma g_{do}$$

- Recall that  $g_{do}$  is the channel resistance at zero  $V_{ds}$ 
  - At a fixed current density, we have

$$g_{do} \propto W \propto I_d \Rightarrow \boxed{\overline{I_d^2} \propto I_d}$$

# Impact of Charge Pump Current Value on Output Noise

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- **Recall**

$$S_{\Phi_{out}}(f) = \left(\frac{1}{I_{cp}}\right)^2 \left(\frac{2\pi N}{\alpha}\right)^2 |G(f)|^2 S_{I_{cpn}}(f) + \text{other sources}$$

- **Given previous slide, we can say**

$$S_{I_{cpn}}(f) \propto I_{cp}$$

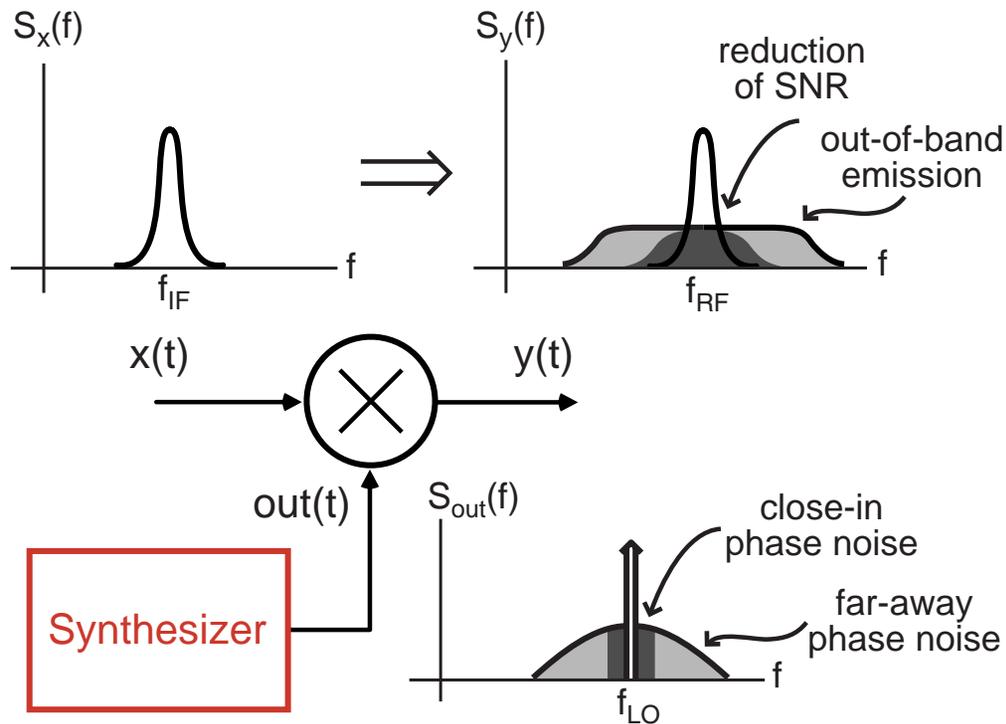
- Assumes a fixed current density for the key transistors in the charge pump as  $I_{cp}$  is varied

- **Therefore**

$$S_{\Phi_{out}}(f) \Big|_{\text{charge pump}} \propto \frac{1}{I_{cp}}$$

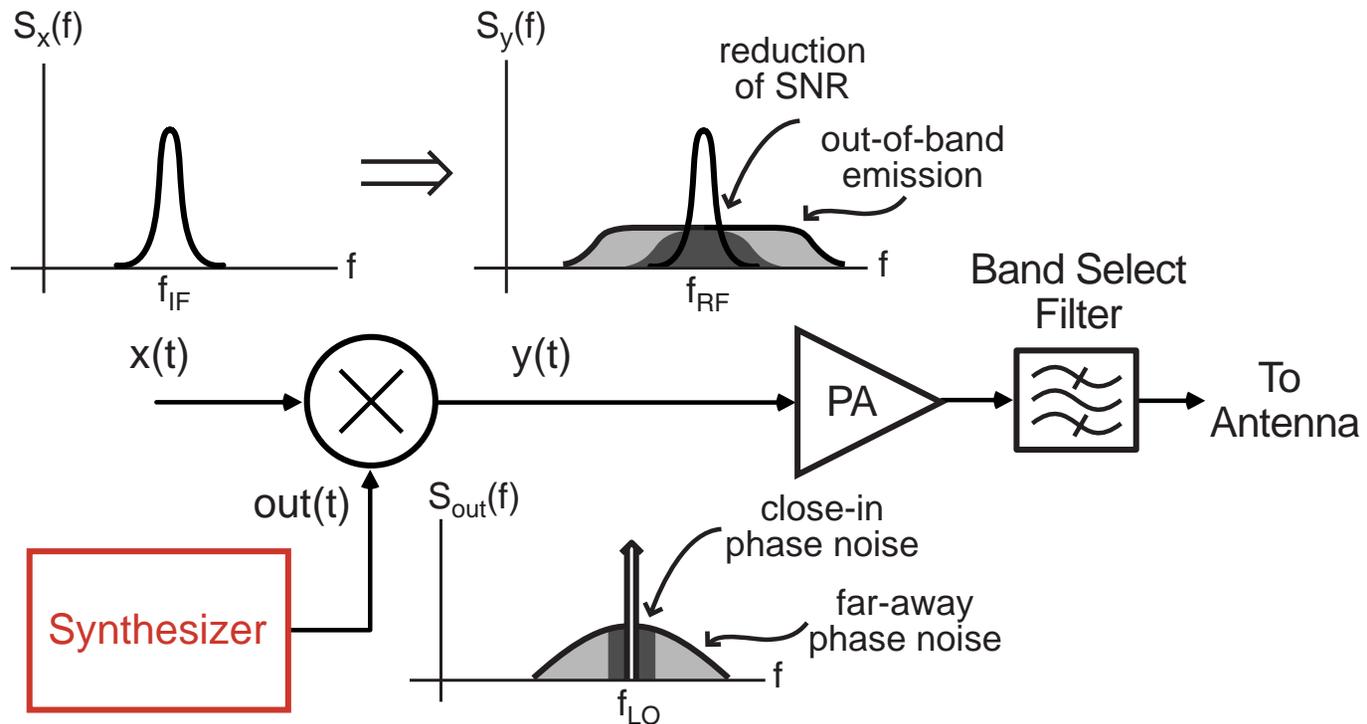
- Want high charge pump current to achieve low noise
- Limitation set by power and area considerations

# Impact of Synthesizer Noise on Transmitters



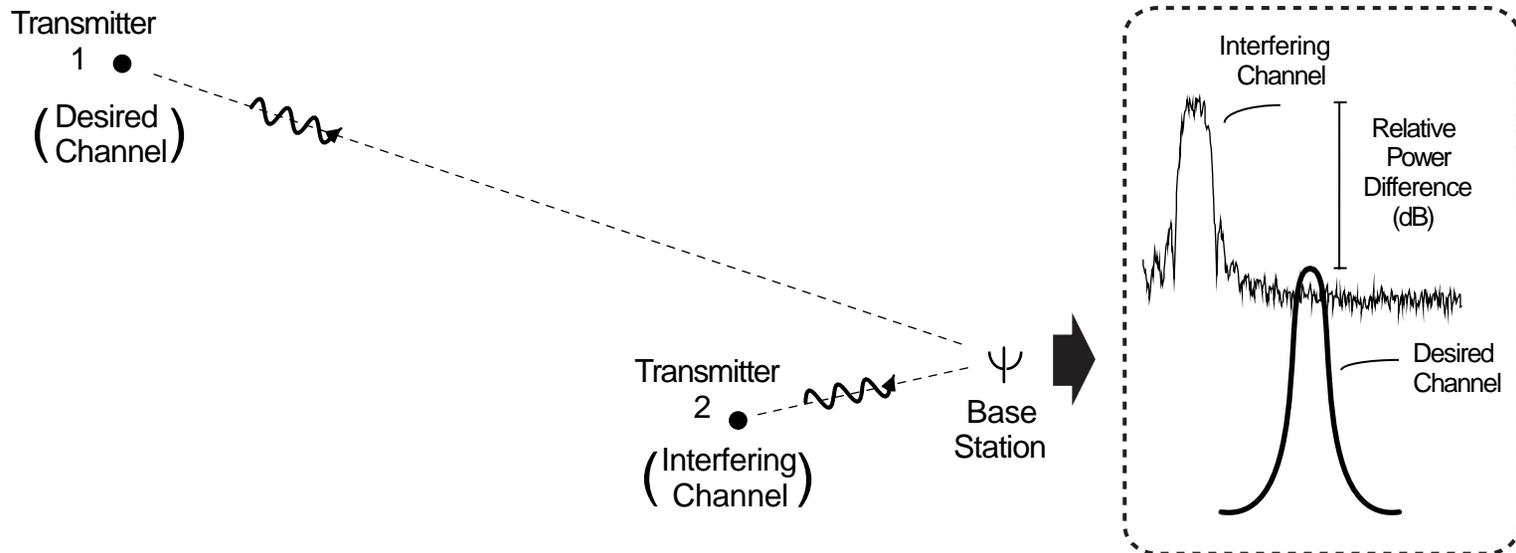
- **Synthesizer noise can be lumped into two categories**
  - **Close-in phase noise:** reduces SNR of modulated signal
  - **Far-away phase noise:** creates spectral emissions outside the desired transmit channel
    - This is the critical issue for transmitters

# Impact of Remaining Portion of Transmitter



- **Power amplifier**
  - Nonlinearity will increase out-of-band emission and create harmonic content
- **Band select filter**
  - Removes harmonic content, but not out-of-band emission

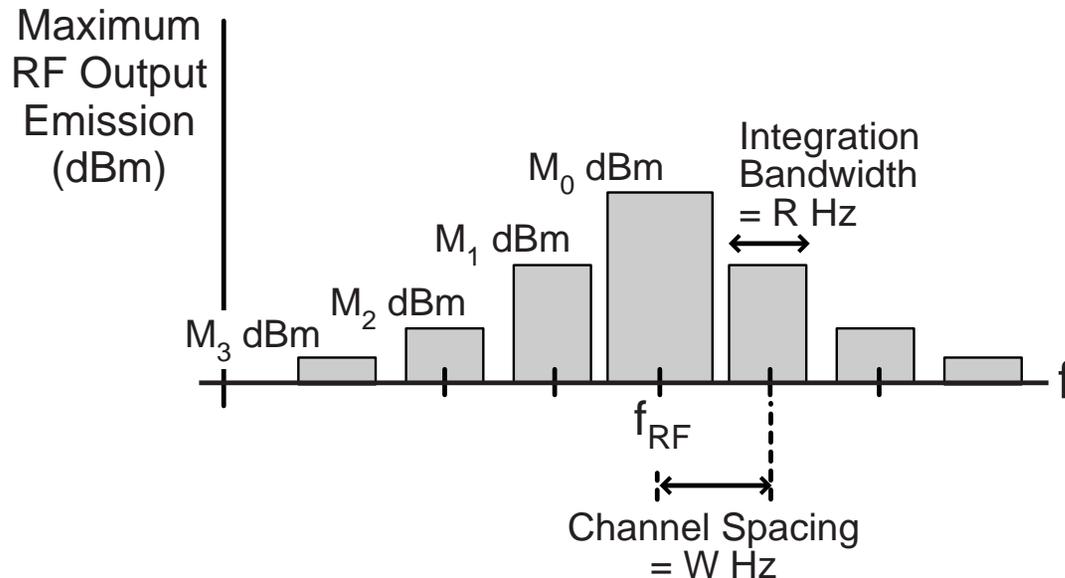
# Why is Out-of-Band Emission A Problem?



## ■ Near-far problem

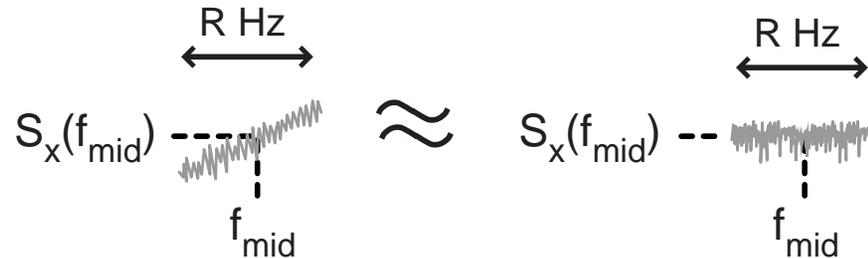
- Interfering transmitter closer to receiver than desired transmitter
- Out-of-emission requirements must be stringent to prevent complete corruption of desired signal

# Specification of Out-of-Band Emissions



- **Maximum radiated power is specified in desired and adjacent channels**
  - **Desired channel power:** maximum is  $M_0$  dBm
  - **Out-of-band emission:** maximum power defined as integration of transmitted spectral density over bandwidth  $R$  centered at midpoint of each channel offset

# Calculation of Transmitted Power in a Given Channel



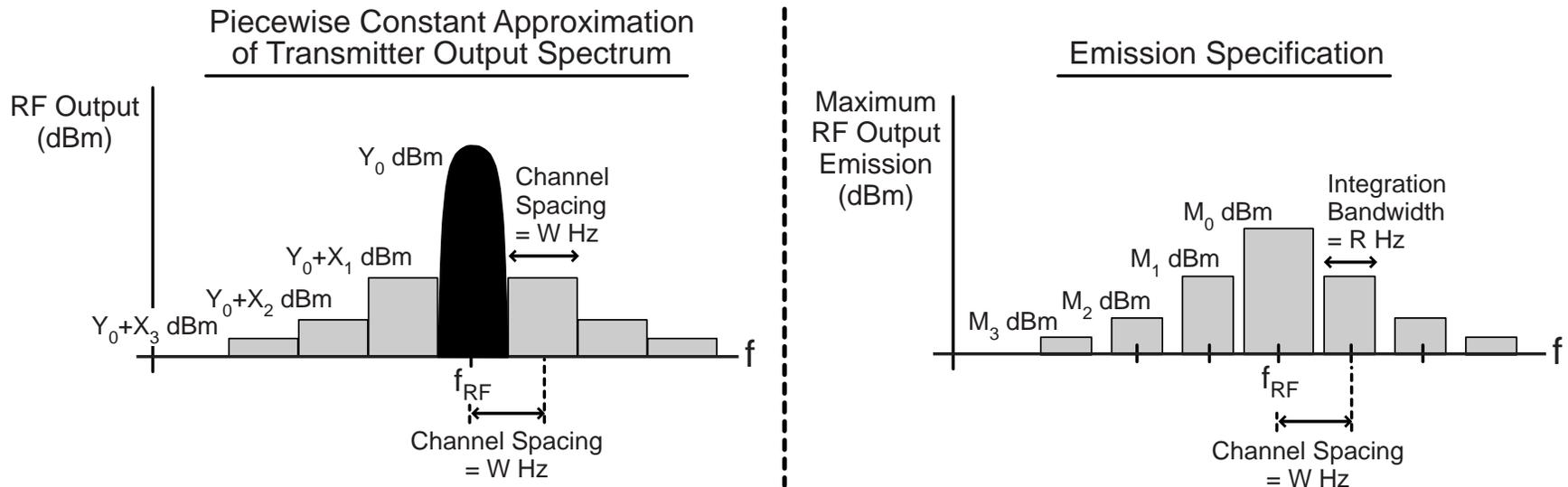
- For simplicity, assume that the spectral density is flat over the channel bandwidth
  - Actual spectral density of signal often varies with frequency over the bandwidth of a given channel
- Resulting power calculation (single-sided  $S_x(f)$ )

$$P_x = \int_{f_{mid}-R/2}^{f_{mid}+R/2} S_x(f) df \approx RS_x(f_{mid})$$

- Express in dB ( Note:  $\text{dB}(x) = 10\log(x)$  )

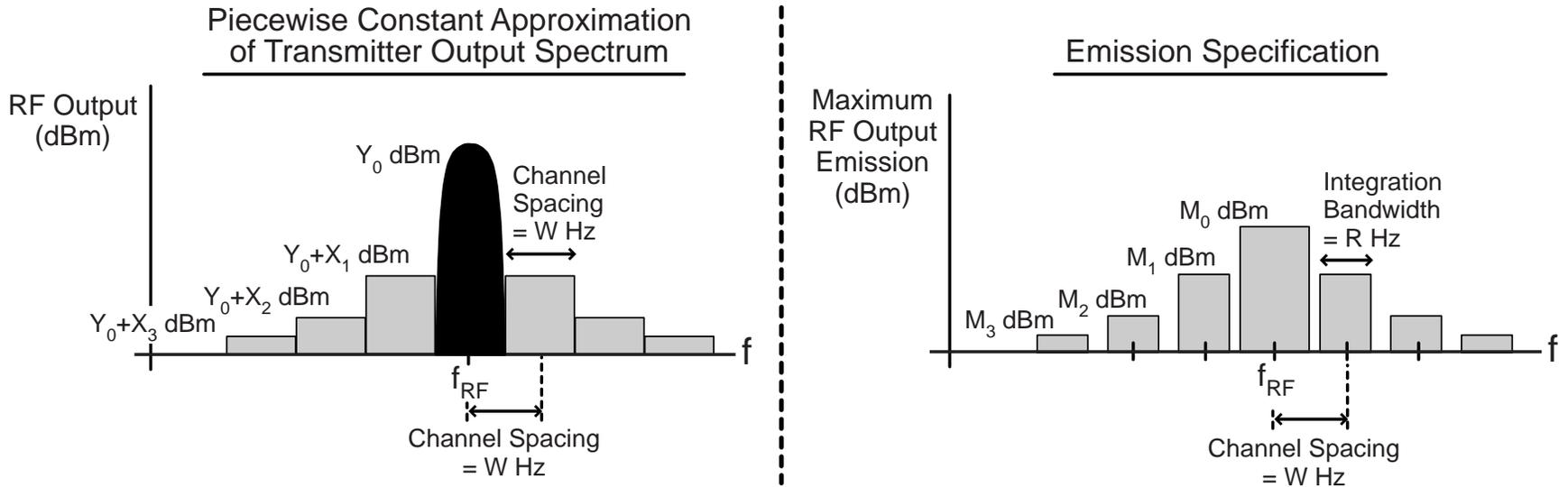
$$\text{dB}(P_x) \approx \text{dB}(RS_x(f_{mid})) = \text{dB}(S_x(f_{mid})) + \text{dB}(R)$$

# Transmitter Output Versus Emission Specification



- Assume a piecewise constant spectral density profile for transmitter
  - Simplifies calculations
- Issue: emission specification is measured over a narrower band than channel spacing
  - Need to account for bandwidth discrepancy when doing calculations

# Correction Factor for Bandwidth Mismatch



## ■ Calculation of maximum emission in offset channel 1

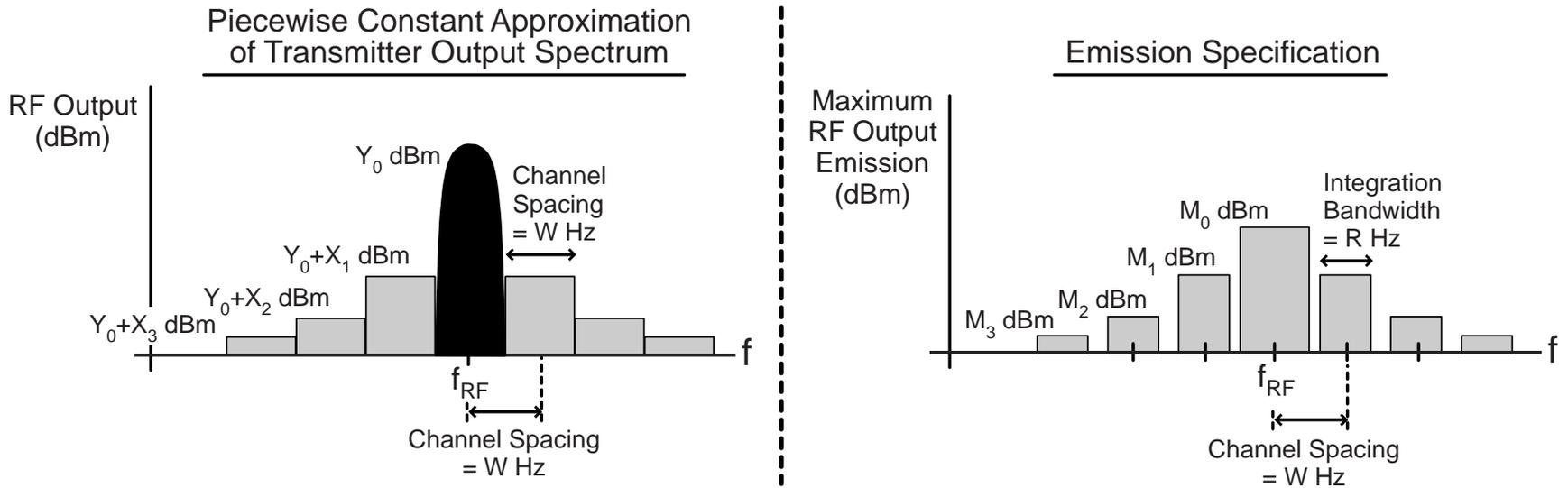
$$\text{dB}(S_{(Y_0+X_1)}R) \leq M_1$$

$$\Rightarrow \text{dB} \left( S_{(Y_0+X_1)} W \frac{R}{W} \right) \leq M_1$$

$$\Rightarrow \text{dB} \left( S_{(Y_0+X_1)} W \right) + \text{dB} \left( \frac{R}{W} \right) \leq M_1$$

$$\Rightarrow Y_0 + X_1 + \text{dB} \left( \frac{R}{W} \right) \leq M_1 \Rightarrow X_1 \leq M_1 - Y_0 + \text{dB} \left( \frac{W}{R} \right)$$

# Condition for Most Stringent Emission Requirement



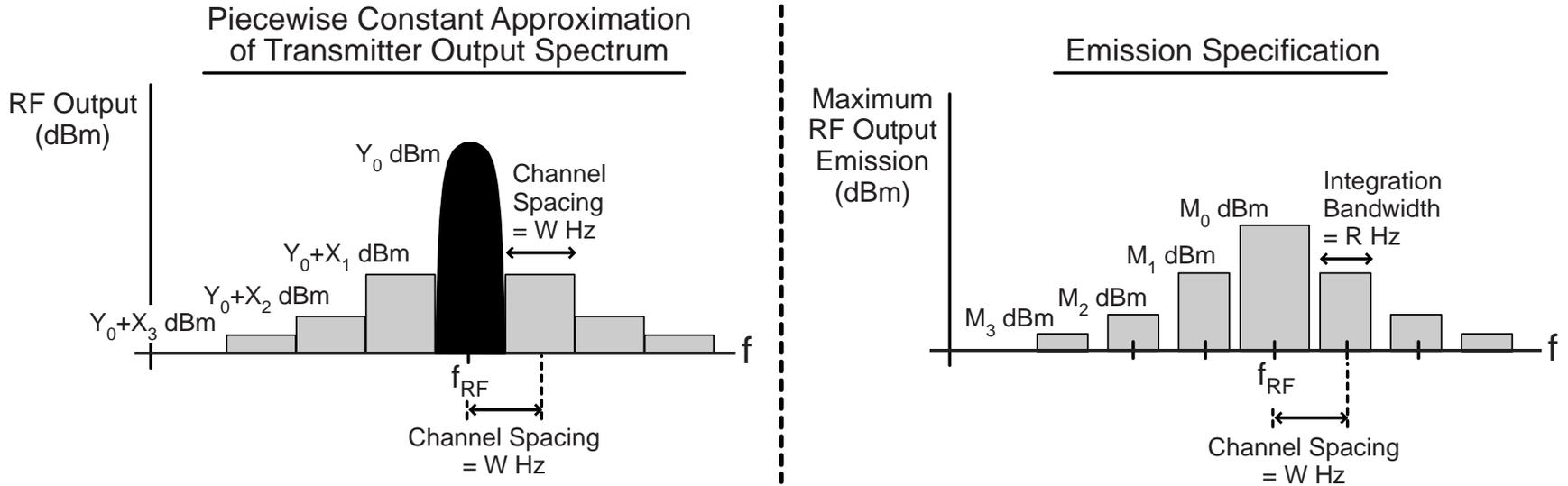
- **Out-of-band emission requirements are function of the power of the signal in the desired channel**
  - **For offset channel 1 (as calculated on previous slide)**

$$X_1 \leq M_1 - Y_0 + \text{dB} \left( \frac{W}{R} \right)$$

- **Most stringent case is when  $Y_0$  maximum**

$$\Rightarrow Y_0 = M_0$$

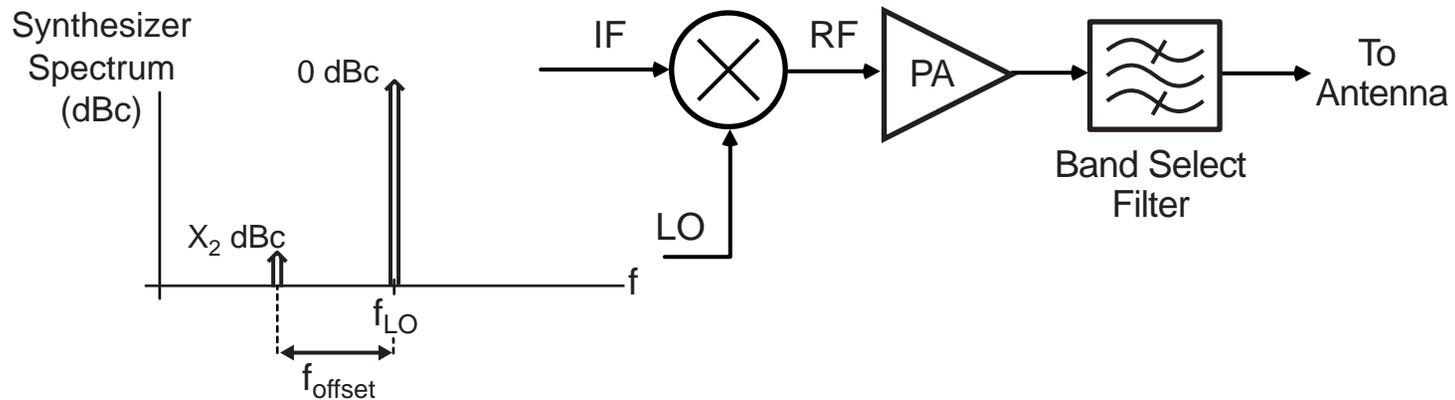
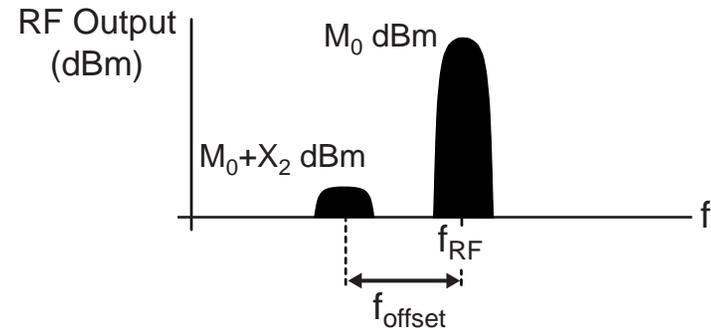
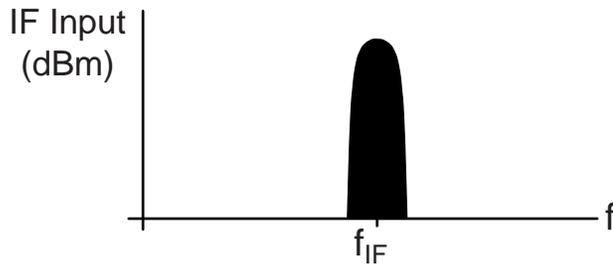
# Table of Most Stringent Emission Requirements



Channel Offset	Mask Power	Emission Requirements (Most Stringent)
0	$M_0$ dBm	$Y_0 = M_0$ (for most stringent case)
1	$M_1$ dBm	$X_1 = M_1 - M_0 + \text{dB}(W/R)$ dB
2	$M_2$ dBm	$X_2 = M_2 - M_0 + \text{dB}(W/R)$ dB
3	$M_3$ dBm	$X_3 = M_3 - M_0 + \text{dB}(W/R)$ dB

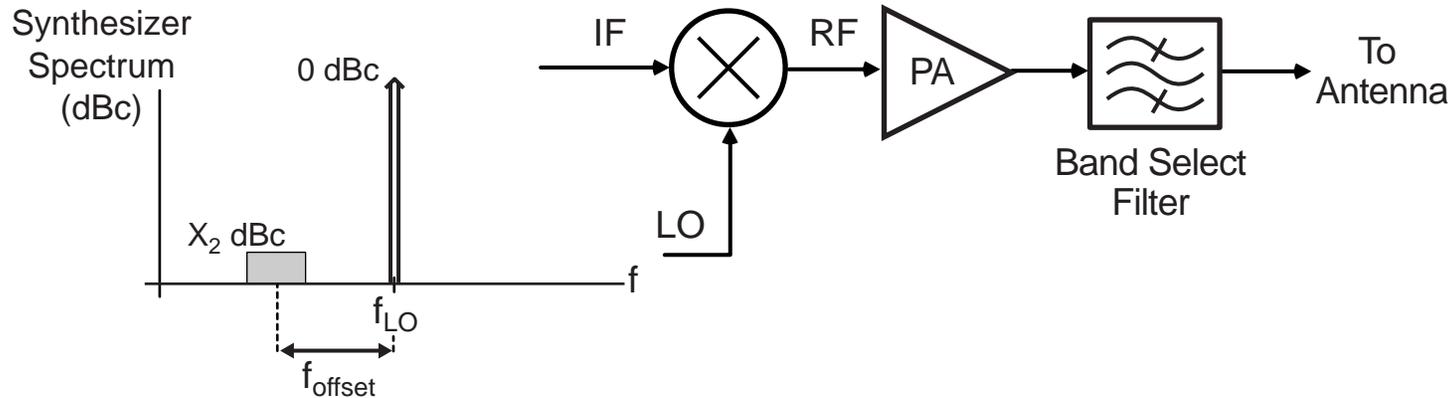
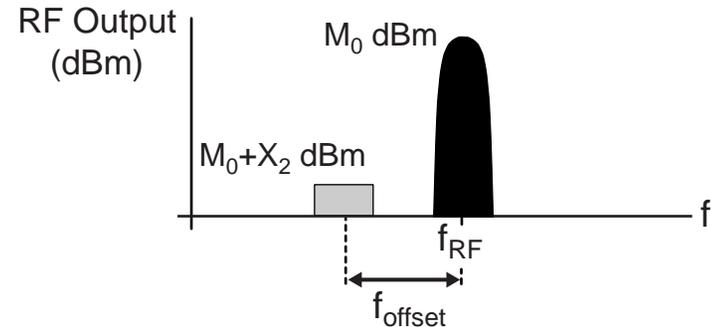
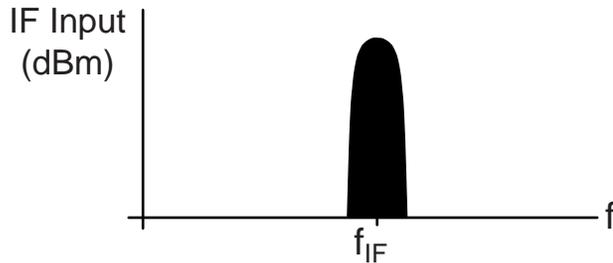
(Note :  $\text{dB}(W/R) = 10 \log(W/R)$ )

# Impact of Synthesizer Noise on Transmitter Output



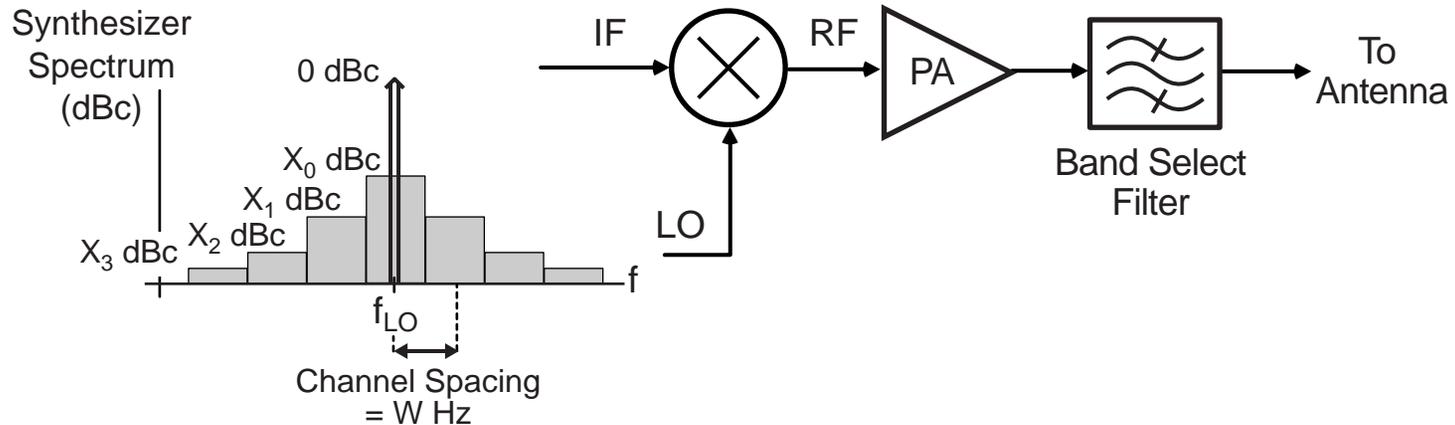
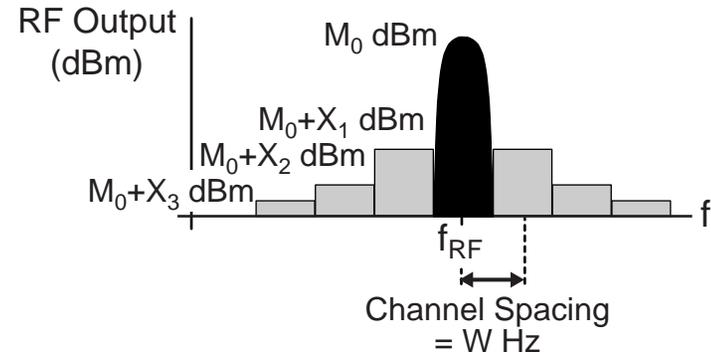
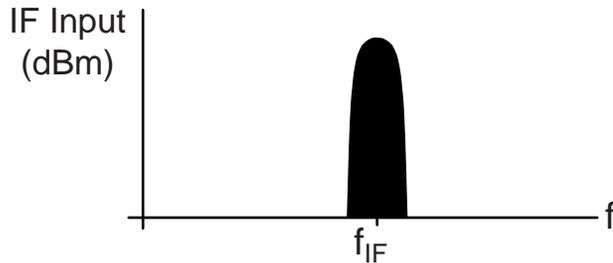
- Consider a spurious tone at a given offset frequency
  - Convolution with IF signal produces a replica of the desired signal at the given offset frequency

# Impact of Synthesizer Phase Noise (Isolated Channel)



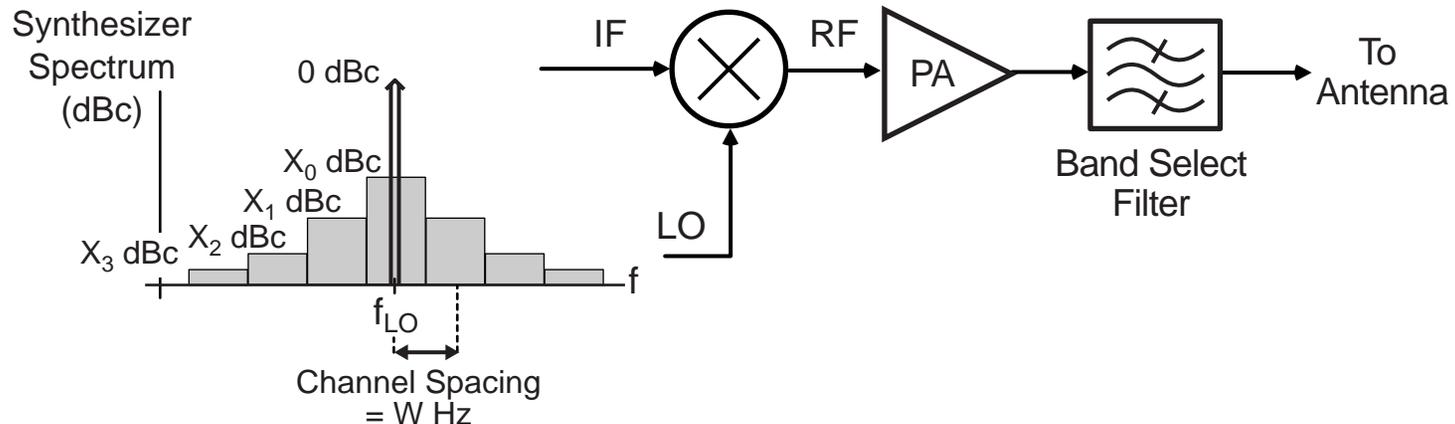
- Consider phase noise at a given offset frequency
  - Convolution with IF signal produces a smeared version of the desired signal at the given offset frequency
    - For simplicity, approximate smeared signal as shown

# Impact of Synthesizer Phase Noise (All Channels)



- Partition synthesizer phase noise into channels
  - Required phase noise power (dBc) in each channel is related directly to spectral mask requirements
    - Exception is  $X_0$  – set by transmit SNR requirements

# Synthesizer Phase Noise Requirements



- Impact of channel bandwidth (offset channel 1)

$$\text{dB}(S_{X_1}W) \leq X_1 \text{ dBc} \Rightarrow \text{dB}(S_{X_1}) \leq X_1 - \text{dB}(W) \text{ dBc/Hz}$$

- Overall requirements (most stringent, i.e.,  $Y_0 = M_0$ )

Channel Offset	Emission Requirements (Most Stringent)	Maximum Synth. Phase Noise (Most Stringent)
0	$Y_0 = M_0$	set by required transmit SNR
1	$X_1 = M_1 - M_0 + \text{dB}(W/R) \text{ dB}$	$X_1 - \text{dB}(W) \text{ dBc/Hz}$
2	$X_2 = M_2 - M_0 + \text{dB}(W/R) \text{ dB}$	$X_2 - \text{dB}(W) \text{ dBc/Hz}$
3	$X_3 = M_3 - M_0 + \text{dB}(W/R) \text{ dB}$	$X_3 - \text{dB}(W) \text{ dBc/Hz}$

## Example – DECT Cordless Telephone Standard

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- Standard for many cordless phones operating at 1.8 GHz
- Transmitter Specifications
  - Channel spacing:  $W = 1.728$  MHz
  - Maximum output power:  $M_0 = 250$  mW (24 dBm)
  - Integration bandwidth:  $R = 1$  MHz
  - Emission mask requirements

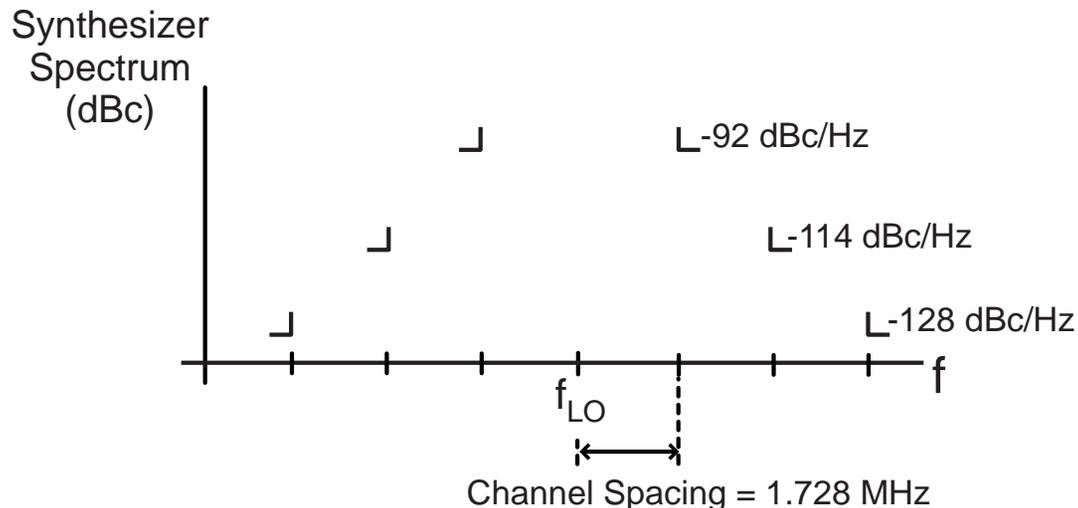
$f_{offset}$ (MHz)	Emission Mask (dBm)
0	$M_0 = 24$ dBm
1.728	$M_1 = -8$ dBm
3.456	$M_2 = -30$ dBm
5.184	$M_3 = -44$ dBm

# Synthesizer Phase Noise Requirements for DECT

- Using previous calculations with DECT values

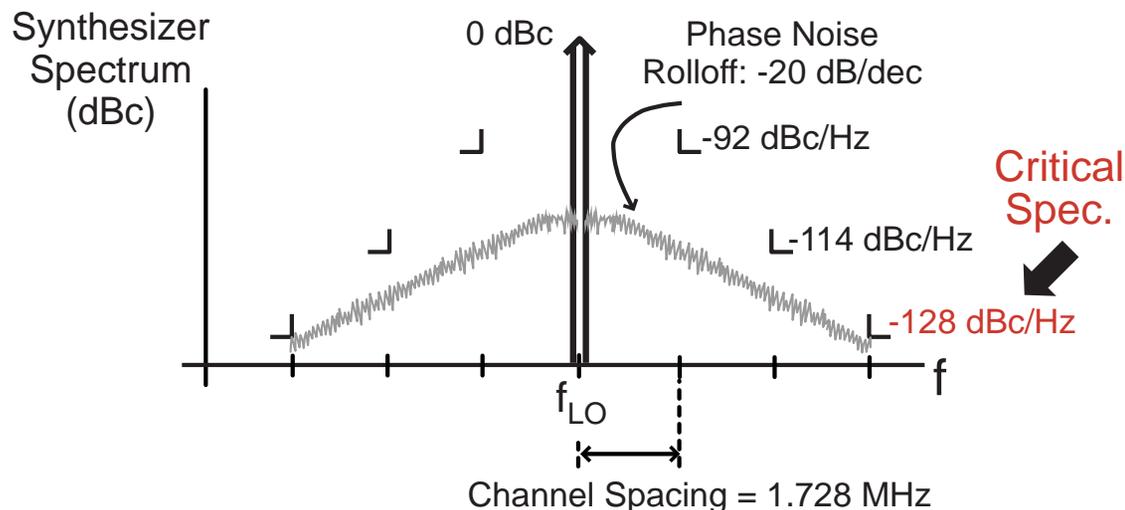
Channel Offset	Mask Power	Maximum Synth. Noise Power in Integration BW	Maximum Synth. Phase Noise at Channel Offset
0	24 dBm	set by required transmit SNR	
1.728 MHz	-8 dBm	$X_1 = -29.6$ dBc	-92 dBc/Hz
3.456 MHz	-30 dBm	$X_2 = -51.6$ dBc	-114 dBc/Hz
5.184 MHz	-44 dBm	$X_3 = -65.6$ dBc	-128 dBc/Hz

- Graphical display of phase noise mask

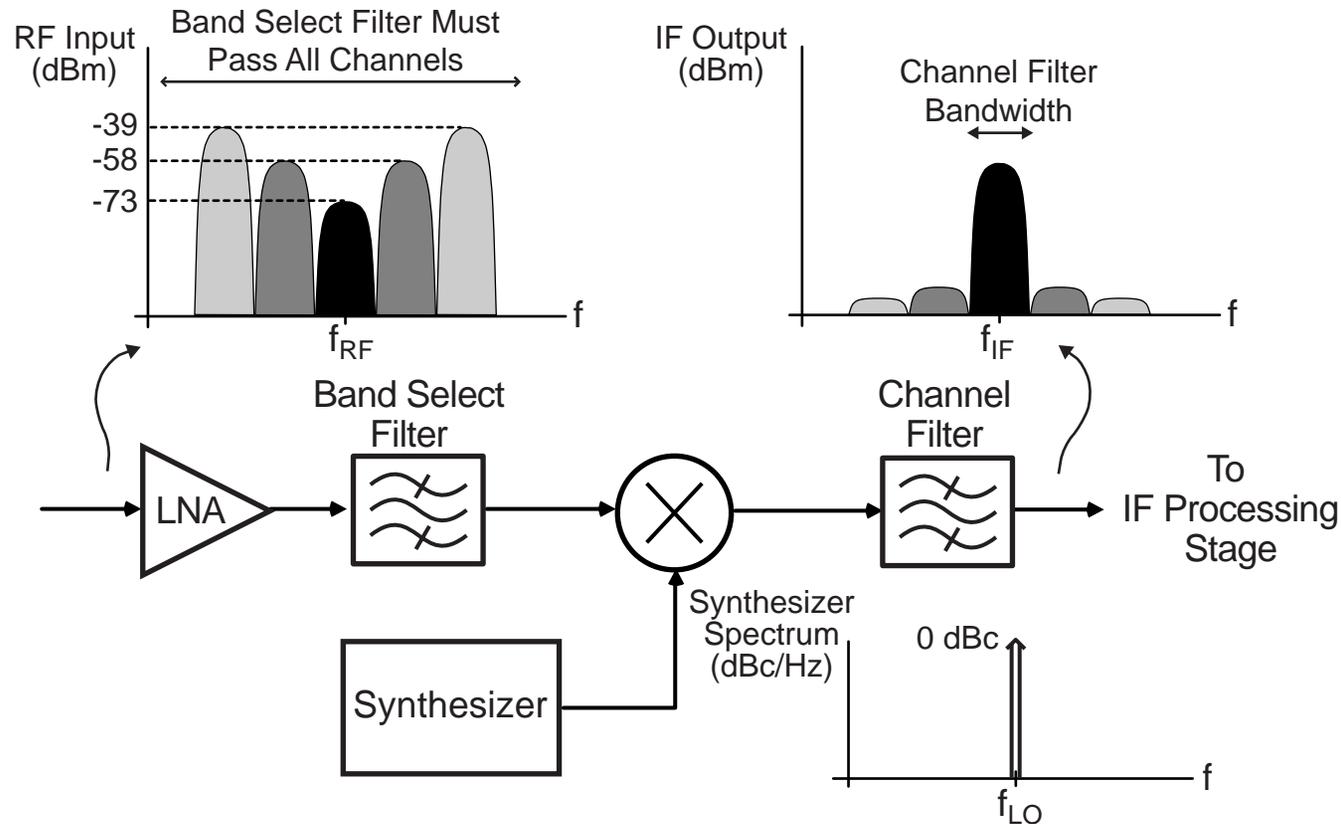


# Critical Specification for Phase Noise

- Critical specification is defined to be the one that is hardest to meet with an assumed phase noise rolloff
  - Assume synthesizer phase noise rolls off at -20 dB/decade
    - Corresponds to VCO phase noise characteristic
- For DECT transmitter synthesizer
  - Critical specification is -128 dBc/Hz at 5.184 MHz offset

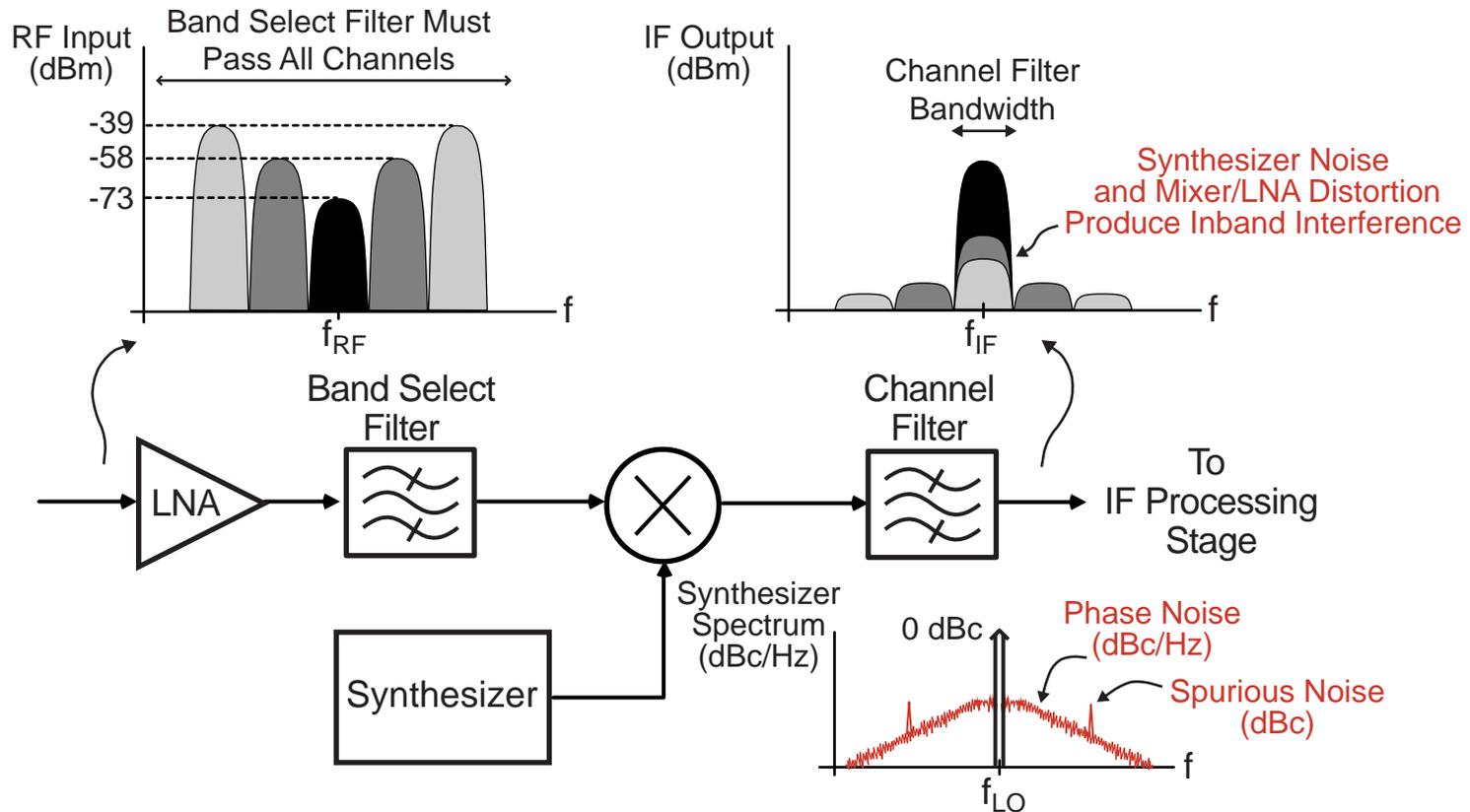


# Receiver Blocking Performance



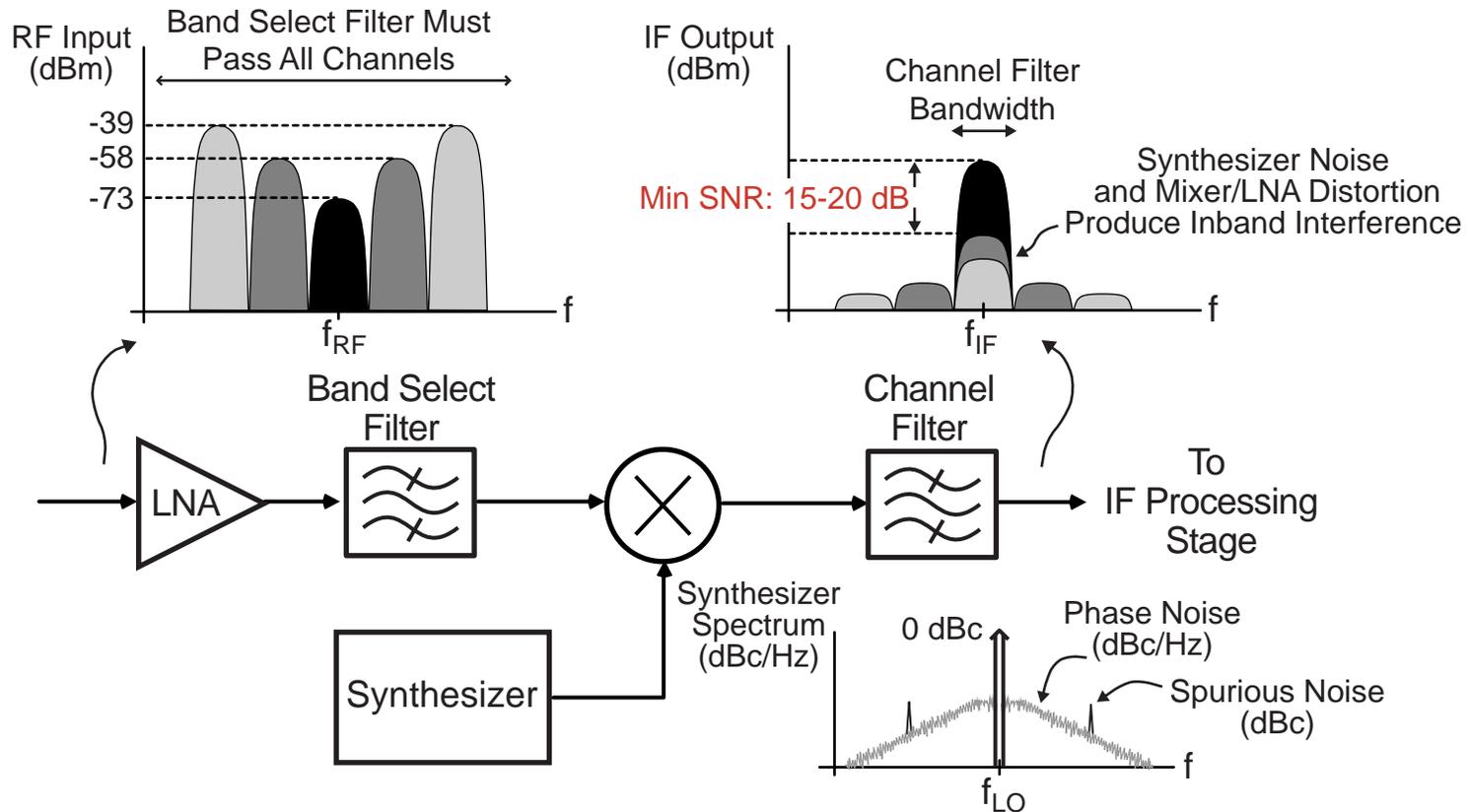
- Radio receivers must operate in the presence of large interferers (called blockers)
- Channel filter plays critical role in removing blockers
  - Passes desired signal channel, rejects interferers

# Impact of Nonidealities on Blocking Performance



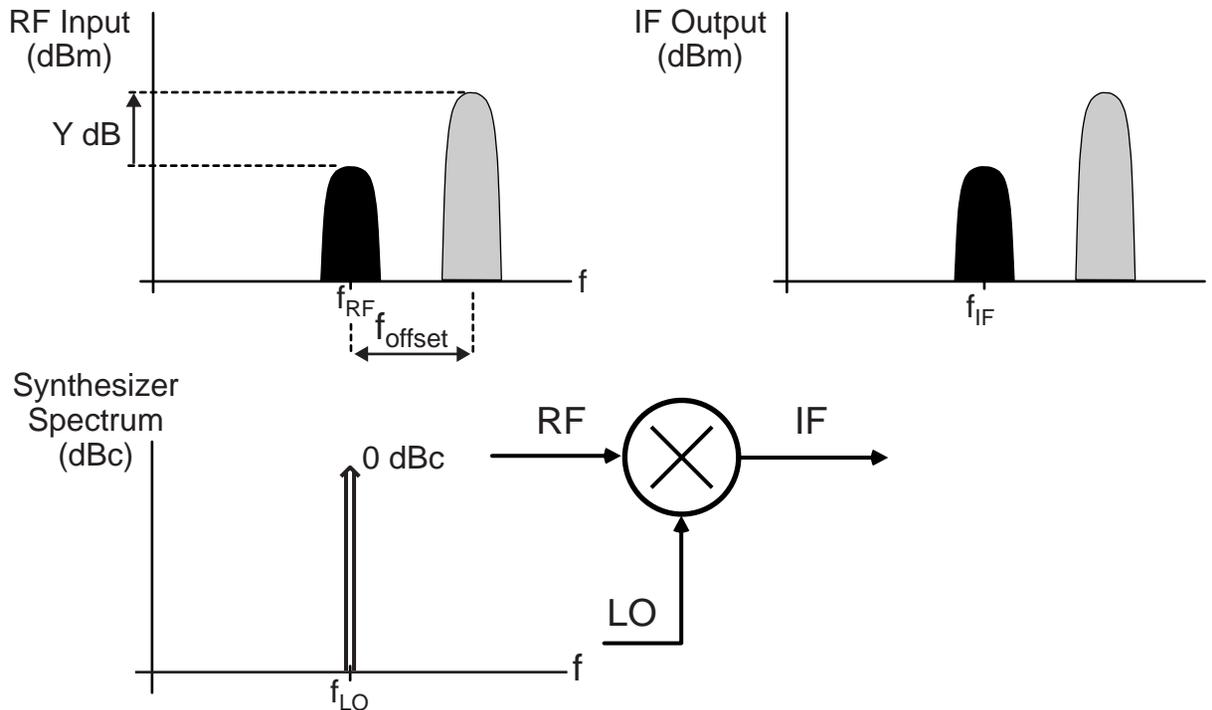
- **Blockers leak into desired band due to**
  - Nonlinearity of LNA and mixer (IIP3)
  - Synthesizer phase and spurious noise
- **In-band interference cannot be removed by channel filter!**

# Quantifying Tolerable In-Band Interference Levels



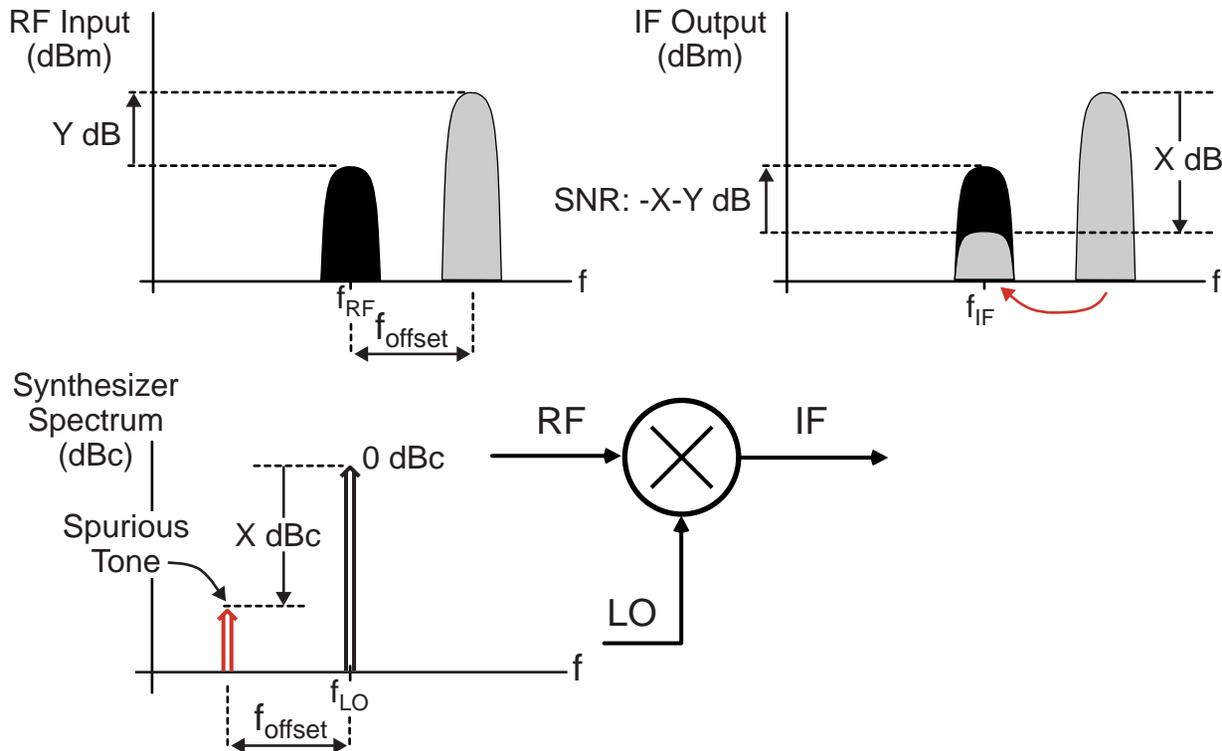
- Digital radios quantify performance with bit error rate (BER)
  - Minimum BER often set at  $1e-3$  for many radio systems
  - There is a corresponding minimum SNR that must be achieved
- Goal: design so that SNR with interferers is above  $SNR_{min}$

# Impact of Synthesizer on Blockers



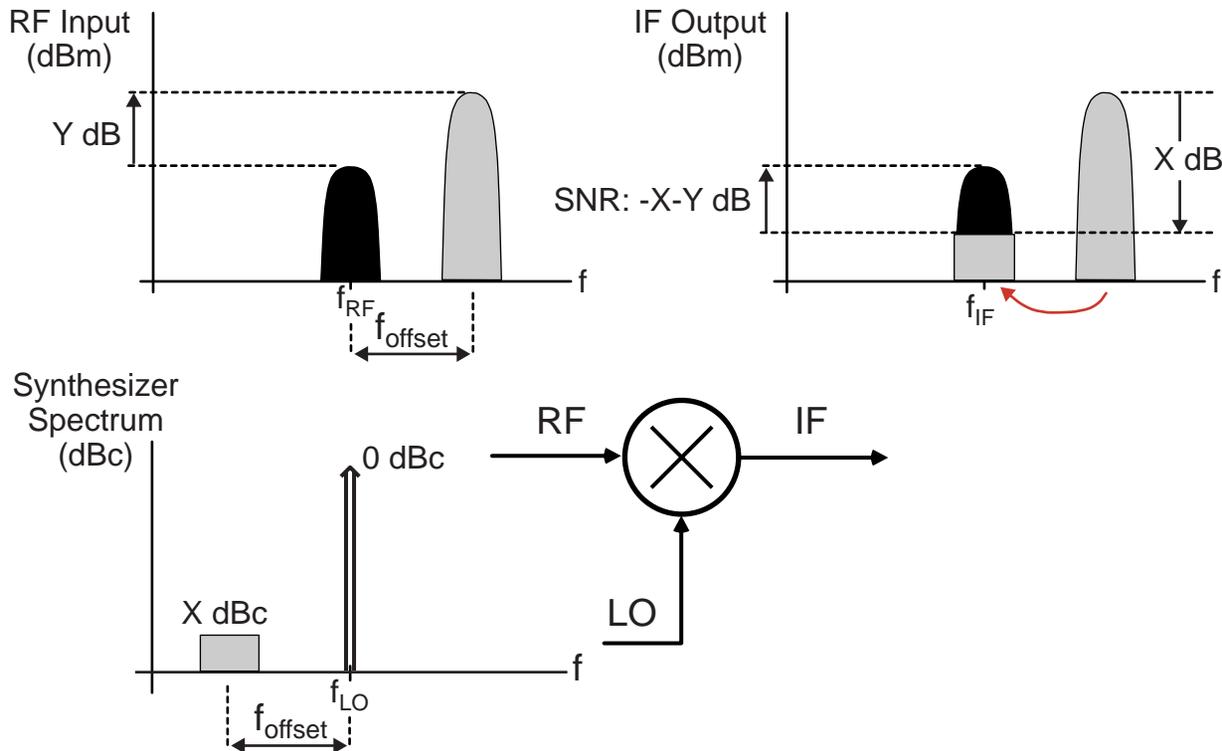
- **Synthesizer passes desired signal and blocker**
  - Assume blocker is  $Y$  dB higher in signal power than desired signal

# Impact of Synthesizer Spurious Noise on Blockers



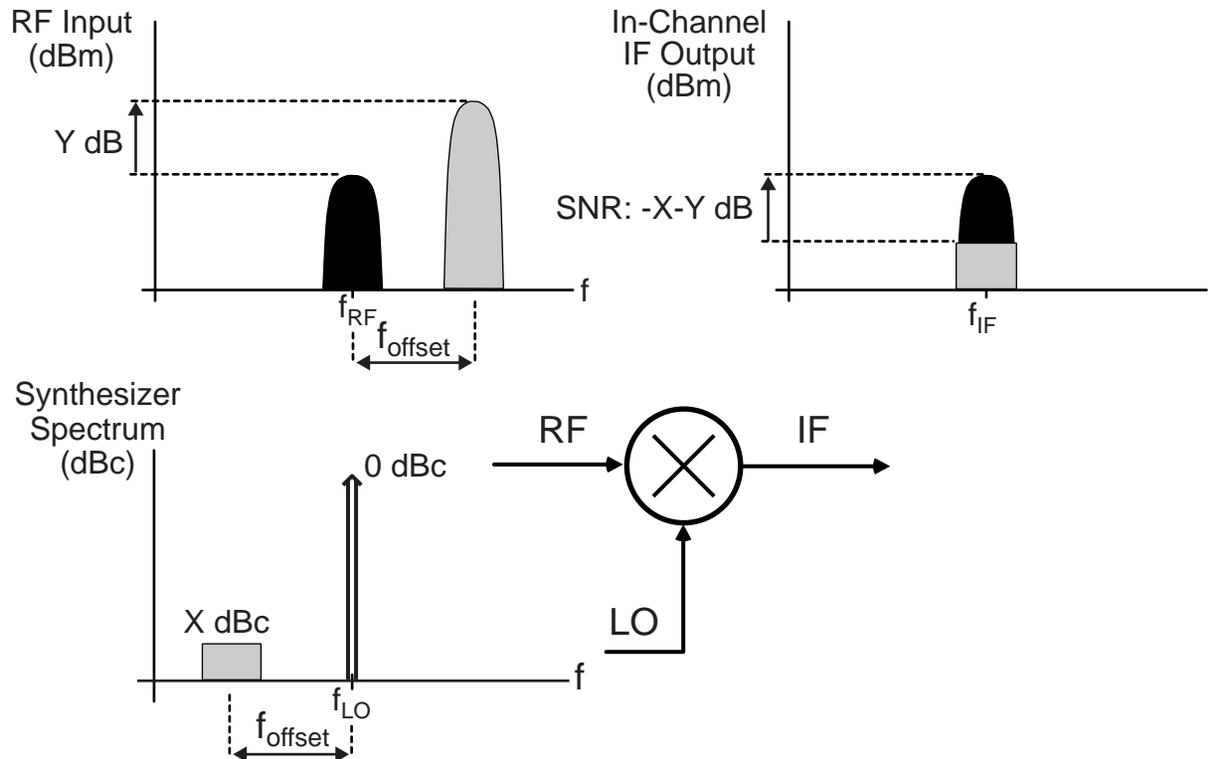
- **Spurious tones cause the blocker ( $Y$  dB) (and desired) signals to “leak” into other frequency bands**
  - In-band interference occurs when spurious tone offset frequency is same as blocker offset frequency
  - Resulting SNR =  $-X-Y$  dB with spurious tone ( $X$  dBc)

# Impact of Synthesizer Phase Noise on Blockers



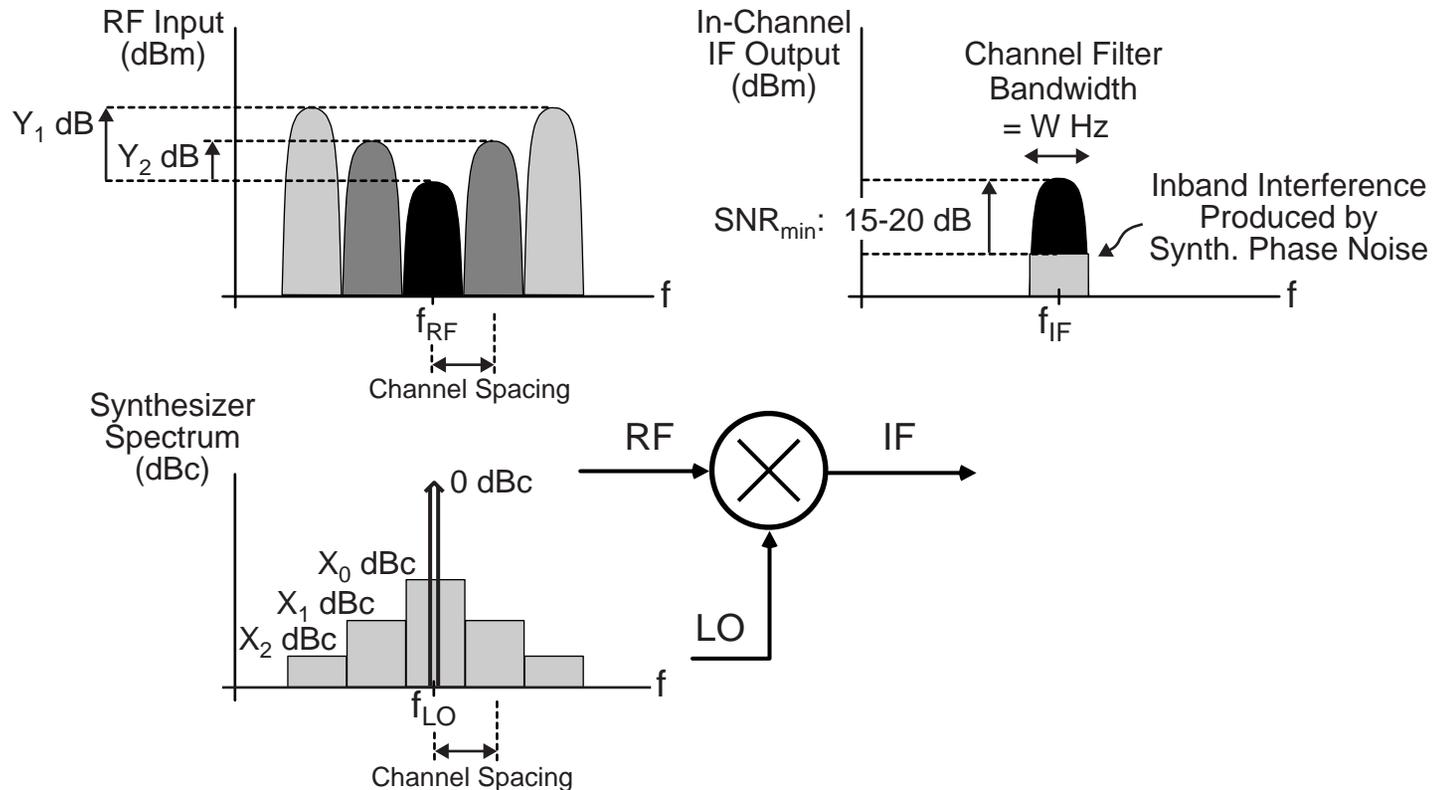
- Same impact as spurious tone, but blocker signal is “smeared” by convolution with phase noise
  - For simplicity, ignore “smearing” and approximate as shown above

# Blocking Performance Analysis (Part 1)



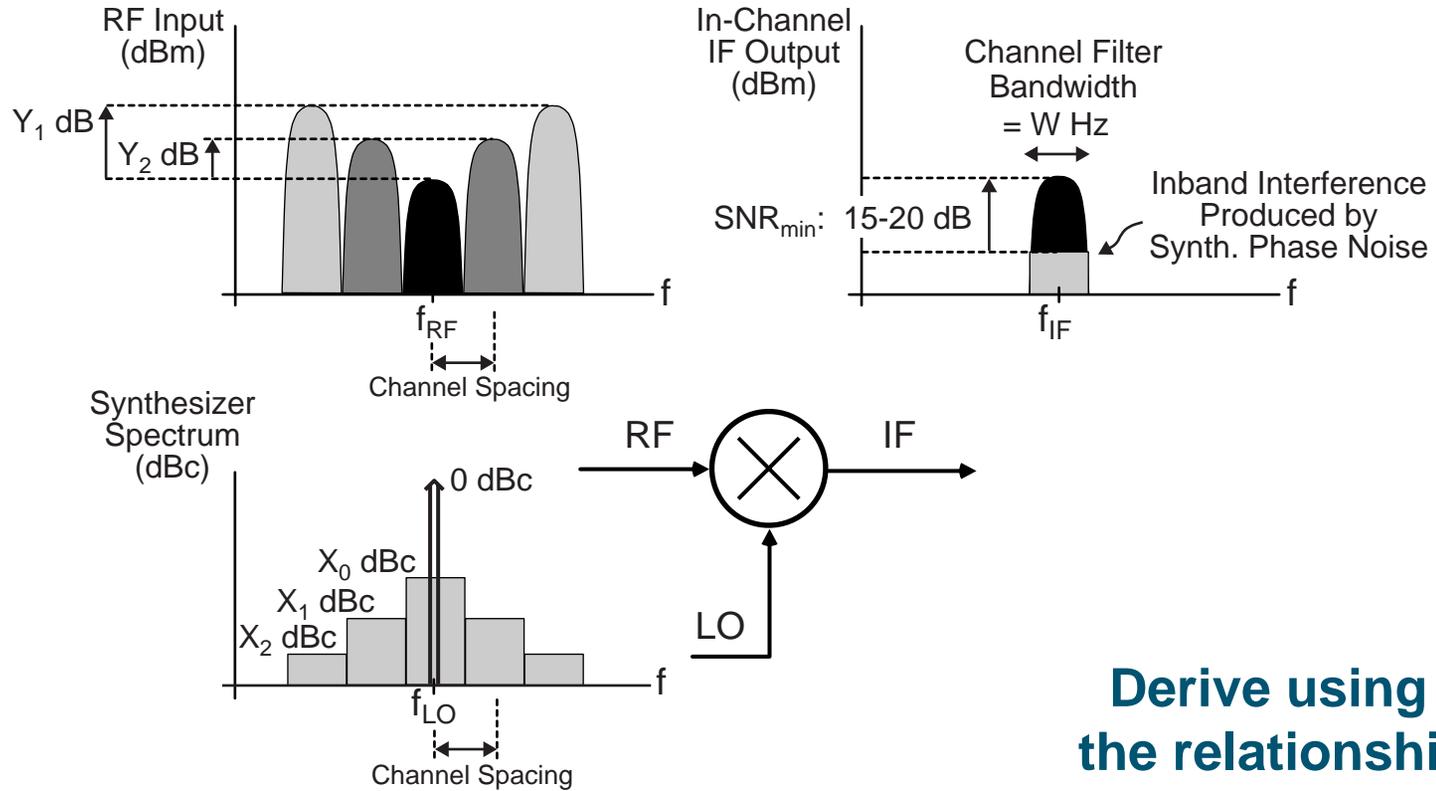
- **Ignore all out-of-band energy at the IF output**
  - Assume that channel filter removes it
  - Motivation: simplifies analysis

# Blocking Performance Analysis (Part 2)



- Consider the impact of blockers surrounding the desired signal with a given phase noise profile
  - SNR<sub>min</sub> must be maintained
  - Evaluate impact on SNR one blocker at a time

# Blocking Performance Analysis (Part 3)

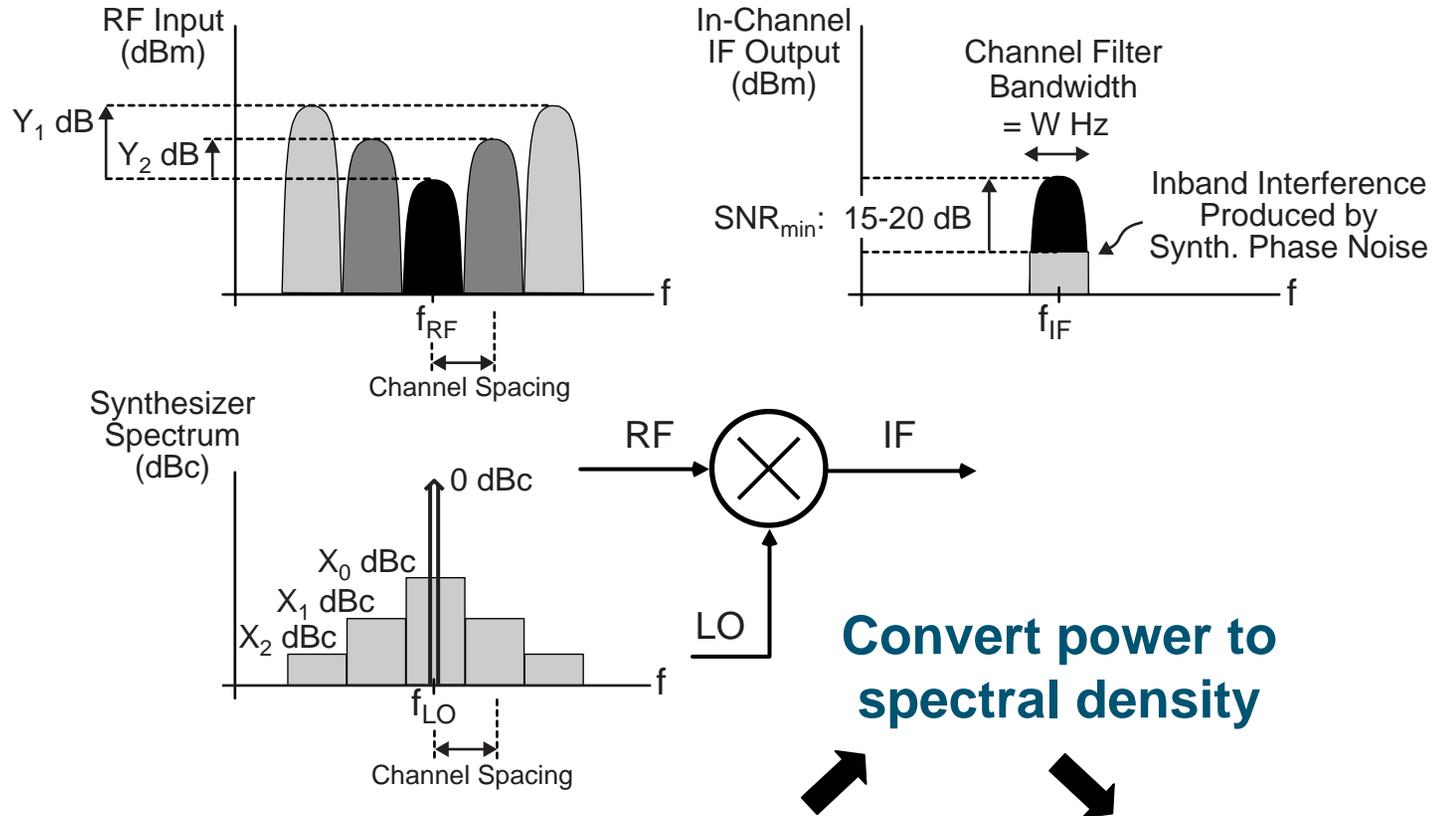


Derive using  
the relationship  
 **$SNR = -X - Y$  dB  $\geq$   $SNR_{min}$**

Channel Offset	Relative Blocking Power	Maximum Synth. Noise Power at Channel Offset
0	0 dB	$X_0 = -SNR_{min}$ dBc
1	$Y_1$ dB	$X_1 = -SNR_{min} - Y_1$ dBc
2	$Y_2$ dB	$X_2 = -SNR_{min} - Y_2$ dBc
3	$Y_3$ dB	$X_3 = -SNR_{min} - Y_3$ dBc



# Blocking Performance Analysis (Part 4)



Channel Offset	Relative Blocking Power	Maximum Synth. Noise Power at Channel Offset	Maximum Synth. Phase Noise at Channel Offset
0	0 dB	$X_0 = -SNR_{min}$ dBc	$X_0 - dB(W)$ dBc/Hz
1	$Y_1$ dB	$X_1 = -SNR_{min} - Y_1$ dBc	$X_1 - dB(W)$ dBc/Hz
2	$Y_2$ dB	$X_2 = -SNR_{min} - Y_2$ dBc	$X_2 - dB(W)$ dBc/Hz
3	$Y_3$ dB	$X_3 = -SNR_{min} - Y_3$ dBc	$X_3 - dB(W)$ dBc/Hz

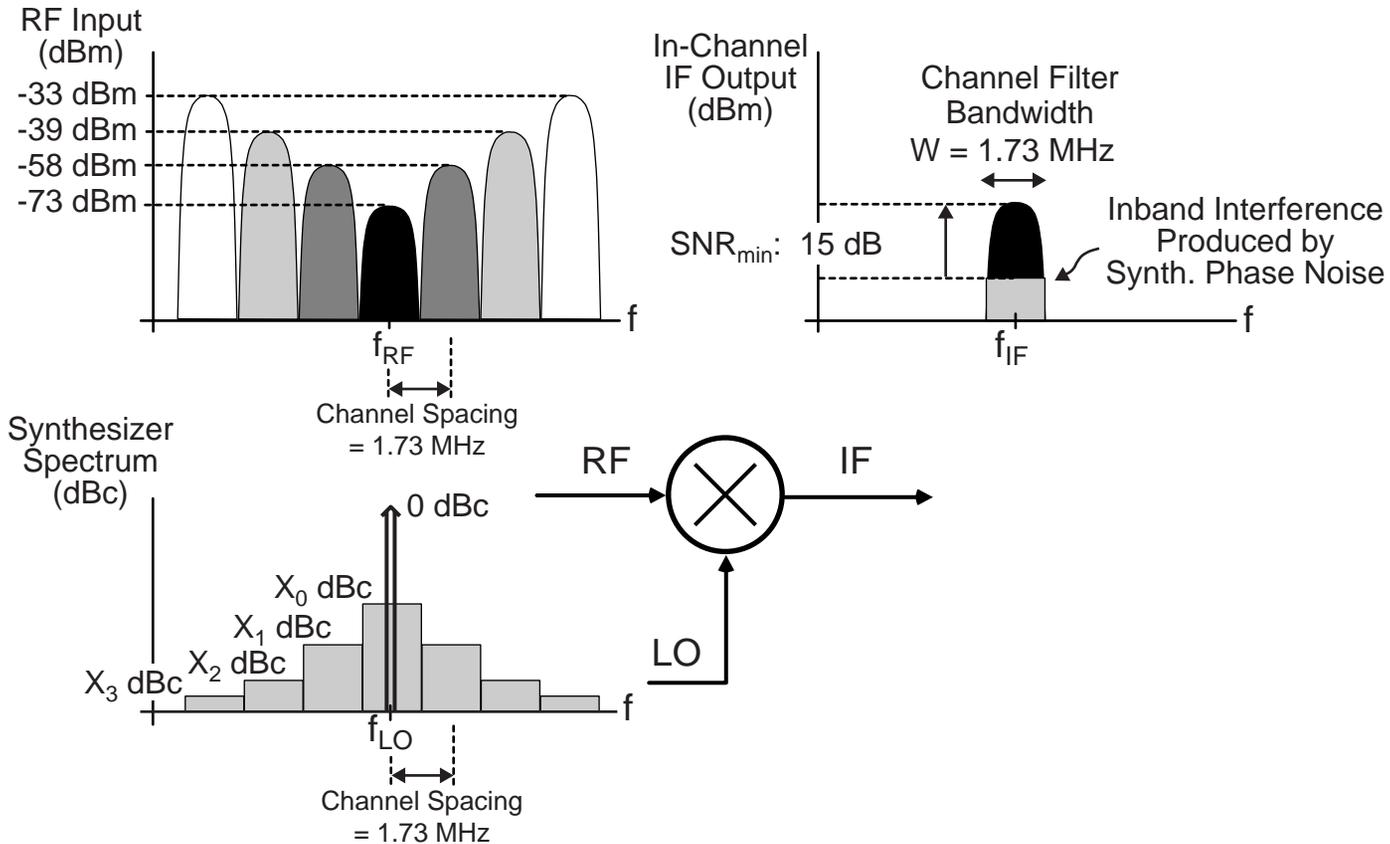
## Example – DECT Cordless Telephone Standard

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- Receiver blocking specifications
  - Channel spacing:  $W = 1.728$  MHz
  - Power of desired signal for blocking test: -73 dBm
  - Minimum bit error rate (BER) with blockers:  $1e-3$ 
    - Sets the value of  $SNR_{min}$ 
      - Perform receiver simulations to determine  $SNR_{min}$
      - Assume  $SNR_{min} = 15$  dB for calculations to follow
  - Strength of interferers for blocking test

$f_{offset}$ (MHz)	Blocker Power (dBm)	Relative Strength
1.728	-58 dBm	$Y_1 = 15$ dB
3.456	-39 dBm	$Y_2 = 34$ dB
5.184	-33 dBm	$Y_3 = 40$ dB

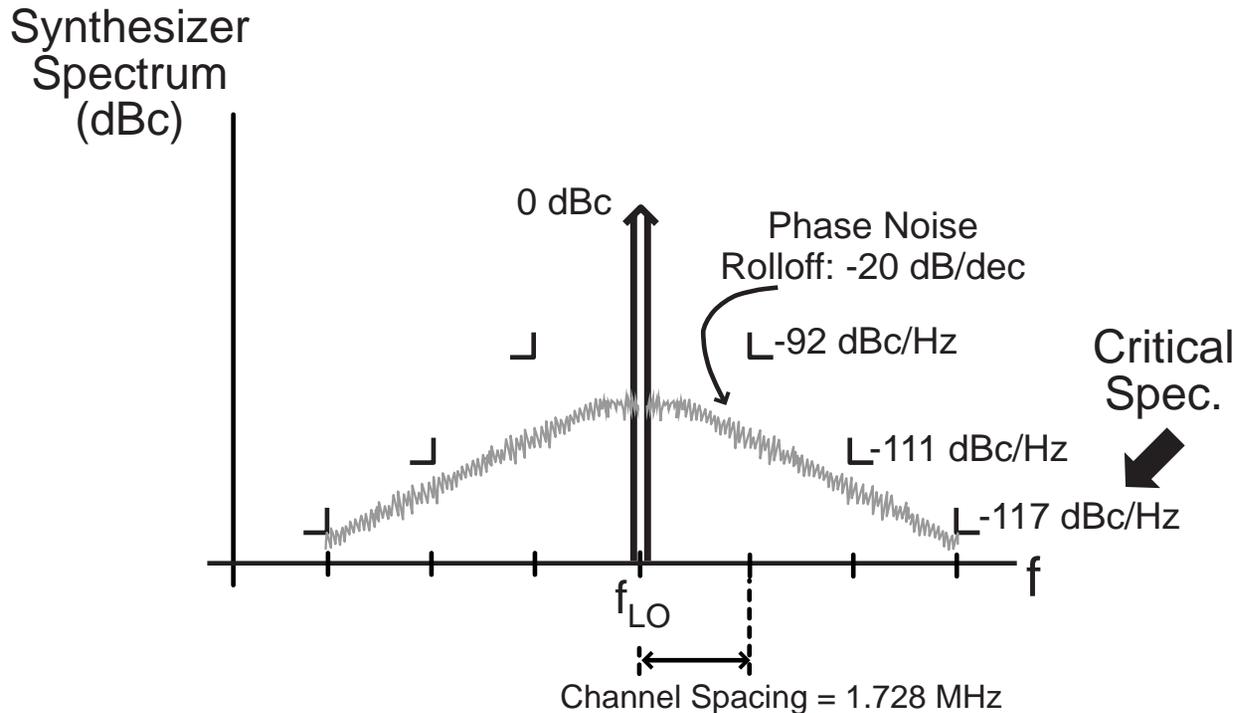
# Synthesizer Phase Noise Requirements for DECT



Channel Offset	Relative Blocking Power	Maximum Synth. Noise Power at Channel Offset	Maximum Synth. Phase Noise at Channel Offset
0	0 dB	$X_0 = -15$ dBc	-77 dBc/Hz
1.728 MHz	$Y_1 = 15$ dB	$X_1 = -30$ dBc	-92 dBc/Hz
3.456 MHz	$Y_2 = 34$ dB	$X_2 = -49$ dBc	-111 dBc/Hz
5.184 MHz	$Y_3 = 40$ dB	$X_3 = -55$ dBc	-117 dBc/Hz

# Graphical Display of Required Phase Noise Performance

- Mark phase noise requirements at each offset frequency



- Calculate critical specification for receive synthesizer
  - Critical specification is -117 dBc/Hz at 5.184 MHz offset
    - Lower performance demanded of receiver synthesizer than transmitter synthesizer in DECT applications!

# Summary of Noise Analysis of Integer-N Synthesizers

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- **Key PLL noise sources are**
  - VCO noise (we will cover in detail tomorrow)
  - PFD-referred noise
    - Charge pump noise, reference noise, etc.
- **Setting of PLL bandwidth has strong impact on noise**
  - High PLL bandwidth suppresses VCO noise
  - Low PLL bandwidth suppresses PFD-referred noise
- **Noise performance required of PLL depends on application**
  - Wireless transmitter: must meet spectral mask
  - Wireless receiver: must suppress blockers and achieve good SNR for received signal